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FIELD EFFECT OF CUPROUS OXIDE

by

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A THESIS

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The undersigned certify that they have read, and recommend to the Faculty of Graduate Studies and Research, for acceptance, a thesis entitled FIELD EFFECT OF CUPROUS OXIDE, submitted by THAVEESAKDI KEOWSIM in partial fulfilment of the requirements for the degree of Master of Science.

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ABSTRACT

This thesis describes the basic principle of the field effect of semiconductors. It also describes experiments performed in order to determine the field effect of single crystals of cuprous oxide, which is known to be a p-type semiconductor. It is possible from measurements of the change in conductance of a bar of cuprous oxide semiconductor with application of an electric field normal to its surface to determine both the electrostatic potential of the surface and the distribution of charge in surface states. Such determinations depend upon the uniqueness of a minimum in surface conductance which is observed in these experiments. It must also be independent of the surface state charge.



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CHAPTER I

INTRODUCTION

Surfaces play an important role in a large range of phenomena. Progress in our understanding of many of the fundamental processes has been slow, however, and our knowledge of the interface is far less extensive than of This is due in large measure to the fact that the physical and chemical processes at the surface are inherently more difficult to analyze. The bulk consists of those regions of the crystal which may be looked upon as an infinite, uniform periodic structure. At the surface, on the other hand, the forces acting on the atoms are no longer symmetrical so that even if the bulk is perfect in every respect the surface atoms are usually displaced from their ideal lattice positions, giving rise to a rather complex two-dimensional structure. At the same time, the unsaturated bonds of the surface atoms make them highly reactive towards the various species outside the crystal. All of these characteristics make the surface a totally different entity from the bulk and require a high degree of sophistication, both experimental and theoretical, for its study.

The term <u>surface</u> or the equivalent term <u>interface</u>, in its broad sense, describes any boundary region between different media. Usually, however, one is primarily



interested in those boundaries in which the change in one or more of the properties characterizing each medium takes place over a region narrow compared to the spatial extent of the system considered. It is these abrupt boundaries that are generally identified with the surface or the interface. The most common interfaces are those separating any two of the solid, liquid, or gaseous phases in contact. Additional interfaces often occur, however, within each phase. In the solid these may be associated with the boundaries between crystallites of different crystallographic orientation, or between sections of different composition. Metal-semiconductor contacts and p-n junctions are important examples of such solid-solid interfaces. the former case the two sections consist of entirely different substances, while in the latter the host crystal is the same and it is only the impurity distribution that varies across the interface.

One of the most important manifestations of the interface is the change in electrostatic potential associated with the transition from one medium to the other. In a semiconductor the potential variation may extend considerably into the underlying bulk, even if all other properties change abruptly. This accounts for the controlling effect of the interface on many of the electronic processes



in a semiconductor. From the experimental standpoint, such a penetration is an invaluable asset in any quantitative investigation of surface phenomena.

In this paper, the interfaces between a semiconductor and a vacuum, gas, or liquid will be referred as free surfaces or simply as surfaces, while the term interface itself will be reserved for solid-solid systems.

1.1 Historical Notes

The first reported phenomena directly related to the field of semiconductor surfaces date back to the end of the last century, when rectification effects were discovered in 1874 by Braun in the system of a metal in contact with a sulphide such as galena, and at about the same time by Schuster² with copper-copper oxide contacts. Shortly afterwards Adams and Day³, working on selenium, discovered the photovoltaic effect. The work at this stage was largely empirical, involving much art and little understanding of the underlying physical principles.

In the early 1930's it became increasingly apparent that rectification and photovoltaic effects were intimately associated with the interface between a metal and a semiconductor (or between two different semiconductors). It was also realized that these effects could arise from the difference in work functions of the two solids.



In 1939 Schottky⁴, Mott⁵, and Davidov⁶ independently formulated theories of rectification based on such considerations. The theories of Schottky, Mott, and Davidov were very successful in accounting quantitatively for the basic features of rectification, and they undoubtedly constituted a major advance in our understanding of interface phenomena. However, two very important links were missing in the theory, one pertaining to the origin of the space-charge region, the other concerning the role of the minority carriers in the current flow.

This group of puzzling phenomena was clarified in one stroke by the far-reaching hypothesis of Bardeen in 1947 that the potential barrier at the semiconductor surface was produced by surface states rather than by contact potential between the semiconductor and the metal in contact with it. These states were assumed to be localized at the surface and to have energies in the otherwise forbidden energy gap. The possibility that localized states can exist at the surface had previously been pointed out by Tamm and by Shockley on purely theoretical grounds.

Bardeen's idea was that electrons from the semiconductor interior can be trapped in the surface states, leaving behind an equal and opposite charge to maintain overall neutrality. Thus a space-charge region, and associated with it a potential barrier, form near the surface. If the den-



sity of surface states is sufficiently large, the potential barrier remains essentially unaltered when contact is made with a metal (or with another semiconductor). The main work at that period was directed towards the investigation of surface states on the one hand and of the detailed characteristics of germanium point-contact rectifiers on the other. It was in the course of this work that transistor action was discovered by Bardeen and Brattain 10.

The existence of surface states on a free surface was demonstrated by Shockley and Pearson 11, who were also able to estimate their density, by a very direct experiment. This, the field-effect experiment, has since become one of the most important tools in surface studies. In it a space-charge region is produced at the surface by an externally applied electrostatic field in an analogous way to the space charge set up by the proximity of a metal of a different work function. A semiconductor slab was used as one plate of a parallel plate capacitor, the other plate being a metal electrode. By measuring the change in conductance of the slab in a direction parallel to the surface as a function of the voltage applied across the capacitor, it was found that only a small fraction of the total induced charge was mobile, indicating that most of it is trapped in surface states.



In one experiment Brattain and Shockley 12 studied the variation of contact potential between n- and p-type samples as a function of bulk impurity content. In another experiment Brattain 13 measured the change in contact potential upon illumination. These studies combined with careful measurements of point-contact rectification characteristics, brought to light the important role played in surface phenomena by minority carriers, even when their concentration in the bulk is very small. In an n-type semiconductor, for example, the conductivity type may change from n-type in the bulk to p-type at the surface, giving rise to what is known as an inversion-type space-charge layer.

Following the discovery of transistor, the main effort in semiconductor research shifted from surface phenomena to bulk properties. It was recognized that while transistor action was primarily a bulk phenomenon, bulk properties alone could not account for the anomalous behaviour of diodes and transistors and that many of the spurious effects were associated with the surface. At the same time, the availability of crystals of a high degree of purity and lattice perfection, and the better understanding of bulk properties, made semiconductors an ideal medium for surface studies.



1.2 Recent Developments in Surface Research

In the course of the surface studies of the last decade, it has become common to distinguish between two types of surfaces, <u>real</u> and <u>clean</u>. The former term refers to surfaces obtained by ordinary laboratory procedures, the latter to surfaces prepared under carefully controlled conditions so as to ensure minimal foreign matter.

Real surfaces have been studied extensively because they are easily prepared and handled and because they are readily amenable to many types of measurements. Moreover, it is the real surface that is encountered in most practical applications. Clean surfaces are much more difficult to produce. They can be prepared by cleavage, ion bombardment, or by heating at elevated temperatures. Once obtained, a clean surface must be maintained in ultra-high vacuum $(10^{-10}$ to 10^{-9} mmHg) to slow down recontamination. The interest in clean surfaces stems from the fact that they constitute the closest approximation to the <u>true</u> crystal surface, and should thus exhibit the fundamental features of the surface per se.

The surface states observed on real surfaces (germanium and silicon) fall into two groups: the "fast states", which are presumably situated at the interface between the crystal and the oxide, and the "slow states",



located predominantly at the outer surface of the oxide layer and arising entirely from adsorbed gas atoms. terms fast and slow refer to the relative speeds with which the respective states interact with the underlying space-charge region of the bulk crystal. The fast states are normally characterized by time constants of the order of microseconds or less, the slow states by time constants ranging from a fraction of a second to hours, depending on the structure of the oxide layer and the nature of the ambient gas. The fast states are usually present with a density of the order of 10¹¹ cm⁻² and their distribution in energy is essentially discrete. Regarding the slow states, little is known about their energy distribution and other characteristics besides the fact that under normal conditions their density is at least 10^{13} cm⁻². This density is sufficient to control the potential barrier at the surface.

The advances in the fundamental understanding of surface phenomena have contributed considerably to device technology. Most of the surface effects detrimental to device performance can be accounted for in terms of the characteristics of the space-charge layer and the surface states, and their known dependence on surface preparation and ambient gas.



While most of the efforts in device technology are primarily aimed at the elimination of surface effects, there is one notable example where interface phenomena are specifically invoked for device operation. This is the unipolar field-effect transistor. Recently, however, means have been devised to nullify the effect of surface states on certain structures involving silicon, cadmium sulphide and gallium arsenide (Ga As). Such structures now play an important role in semiconductor devices; including the input transistors of high input impedance voltmeters such as used for our experiments.

1.3 Scope of Our Work

The present work gives the basic principle of the field-effect of semiconductors. Measurements of the field-effect in cuprous oxide single crystals are reported. A determination of the distribution of charge in surface states is provided.

The presence of a minimum in the experimental field-effect curve allowed us to compare the experimental data with the calculated curves and to find the dependence of the surface band curvature on the applied voltage.

Therefore for the analysis, we selected those samples for which the dependence of the charge in the conductivity on the applied voltage had a minimum.



The theoretical field-effect curves were calculated. The curves obtained and the values of the parameters used in the calculations are given. The dependence of the band curvature $V_{\rm S}$ on the voltage applied to the surface could be determined by comparing the theoretical and experimental field-effect curves.



CHAPTER II

THEORY 1,14

The physical processes that take place at the surface of a semiconductor are greatly influenced by the properties of the underlying bulk material. One can thus hope to be able to separate surface and bulk effects only by being well acquainted with bulk properties and by possessing a certain measure of control over them. A knowledge of bulk characteristics is also an essential prerequisite to surface studies from the conceptual aspect, and in the present chapter we also introduce some of the basic physics of semiconductors.

2.1 Occupation Statistics for Semiconductors (See Many et al¹)

We shall consider the actual distribution of electrons and holes among the various energy states under conditions of thermal equilibrium. The number of electrons in any small energy interval at a fixed temperature depends on two factors: the Fermi-Dirac distribution function, which represents the probability of the electron having this energy, and the number of available states in the given energy interval.



2.1.1 The Fermi-Dirac Distribution Law (See Many et al 1)

Consider the quasi-free electrons in the allowed energy bands. The most probable energy distribution of an ensemble of this sort, being subject to the Pauli exclusion principle, is governed by Fermi-Dirac statistics. The probability that an energy level E be occupied at thermal equilibrium by an electron is given by the Fermi-Dirac distribution function

$$f_n(E) = \frac{1}{1 + \exp[(E - E_F)/kT]}$$
 (1)

where ${\bf E_F}$, referred to as the <u>Fermi level</u>, is determined by the requirement that the total expectation number of electrons be equal to the actual number of electrons involved. For ${\bf E}={\bf E_F}$, ${\bf f}=1/2$, there being an equal probability that the level be occupied or vacant. The Fermi level is closely related to the thermodynamic or chemical potential and is a constant (at a given temperature) throughout a system in thermal equilibrium, even when the system is composed of different phases (such as occur in inhomogeneous semiconductors or in different materials in contact). The Fermi-Dirac distribution function is plotted in Fig. 1 and is seen to vary from unity at low energies to zero at high energies. The main change in occupation probability occurs in the neighbourhood of ${\bf E_F}$, within an energy range $|{\bf E}-{\bf E_F}|$



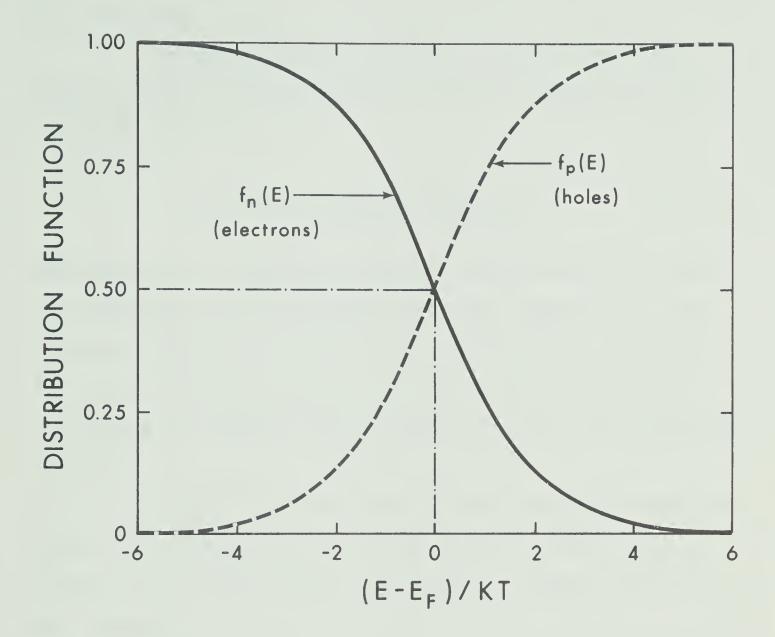


Figure 1. The Fermi-Dirac distribution functions $f_n\left(\text{E}\right) \text{ and } f_p\left(\text{E}\right) \text{ for electrons and holes.}$



of a few units of kT.

The probability $f_p(E)$ that a level E be vacant (that a positive hole occupy the level) is given by $f_p(E) = 1 - f_n(E)$; that is,

$$f_p(E) = \frac{1}{1 + \exp[(E_E - E)/kT]}$$
 (2)

This function is represented by the dashed curve in Figure 1. Recalling that the energy for holes increases in the downward direction, we see that the distribution function for holes is identical with that for electrons provided the energy is measured (with respect to $\mathbf{E}_{\mathbf{F}}$) in the opposite direction.

In order to obtain the volume density of electrons n(E) dE in an energy interval E, E + dE, we must multiply $f_n(E)$ by the volume density of available states N(E) dE in this interval:

$$n(E) dE = f_n(E) N(E) dE.$$
 (3)

The total density of electrons in the conduction band, n_{b} , is given by

$$n_{b} = \int_{E_{C}}^{E_{C}} + A_{C} N_{C}(E) f_{n}(E) dE, \qquad (4)$$

where $E_{\rm c}$ and $E_{\rm c}$ + $A_{\rm c}$ are the lower and upper edges of the conduction band, and $N_{\rm c}$ (E) the density of states per unit



volume and unit energy in the band.

Similarly the total density of holes, \mathbf{p}_{b} , in the valence band is given by

$$p_{b} = \int_{E_{V} - A_{V}}^{E_{V}} N_{V}(E) f_{p}(E) dE, \qquad (5)$$

where E_V - A_V and E_V are the lower and upper edges of the valence band, and N_V (E) the density of states in the band. The subscript b in n_b and p_b stands for "bulk" and signifies that we are dealing with a homogeneous semiconductor.

When the Fermi level is well removed from either of the band edges, the distribution functions (1), (2) reduce to the classical Maxwell-Boltzmann expressions:

$$f_n(E) \stackrel{\sim}{\sim} e = F)/kT = -E/kT$$

$$f_n(E) \stackrel{\sim}{\sim} e = Ae \qquad for (E - E_F) >> kT \qquad (6)$$

$$f_{p}(E) \stackrel{\sim}{\sim} e = E_{F})/kT = E/kT$$

$$= Be \qquad for (E_{F} - E) >> kT \qquad (7)$$

where A and B are normalizing constants. This is only to be expected, since for $|E-E_F|>>kT$ the electron and hole densities are so low that the restrictions imposed by the Pauli exclusion principle are no longer significant. Under these conditions the semiconductor is said to be <u>non-degenerate</u>.



We now turn to the electrons distributed among the various <u>localized</u> states introduced into the forbidden gap by impurity and defect centres. The distribution law for such electrons depends on the characteristics of the centres. In general a centre can capture more than one electron, and in each charge condition there can be several available energy levels (ground and excited states). Moreover, each state may be degenerate (such as when the centre can capture one electron of either spin). The occupation statistics for centres of this sort will be discussed later. Here we shall consider the simple case where, in the charge transfer process between each centre and the energy bands, only <u>one</u> electron takes part and the state of this electron is associated with a <u>single</u> energy level E_t. The probability that such a centre be occupied by an electron is

$$f_n(E_t) = \frac{1}{1 + (g_0/g_1) \exp[(E_t - E_F)/kT]},$$
 (8)

where g_0 and g_1 represent the number of degenerate quantum states of the centre when it is vacant and occupied, respectively. If now we define an effective energy level E_t^f related to the actual level E_t by the equation

$$E_t^f = E_t + kTln(g_0/g_1), \qquad (9)$$

then the distribution function [eq. (8)] reduces to that



for quasi-free electron [eq. (1)] with E_t replaced by E_t^f :

$$f_n(E_t^f) = \frac{1}{1 + \exp[(E_t^f - E_F)/kT]}$$
 (10)

 \mathbf{E}_{t}^{f} is sometimes called the free energy of the centre.

The density of occupied (n_t) and unoccupied (p_t) centres is given by

$$n_{t} = N_{t}f_{n}(E_{t}^{f}); \qquad (11)$$

$$p_t = N_t f_p(E_t^f), \qquad (12)$$

where $f_p(E_t^f)$ is defined similarly to $f_n(E_t^f)$, i.e.

$$f_p(E_t^f) = \frac{1}{1 + \exp[(E_F - E_t^f)/kT]},$$
 (13)

and $N_t = n_t + p_t$ is the total density of centres having an effective energy E_t^f . It should be noted that now the centres are half occupied $(n_t = p_t)$ when the Fermi level coincides with E_t^f , rather than with E_t .

2.1.2 Intrinsic Semiconductors (See Many 1, Sze 14)

In a chemically pure semiconductor having no localized levels, the electron and hole densities must be equal, since every electron excited into the conduction band leaves behind a hole in the valence band. The carrier



densities in this case will be denoted by n;

$$n_i = n_b = p_b. \tag{14}$$

Applying this condition to (4) and (5), we can determine the Fermi level and thus obtain an expression for $n_{\rm i}$. In a semiconductor the energy gap $E_{\rm g}(\Xi \ E_{\rm C} - E_{\rm V})$ is usually large compared to kT so that $n_{\rm i}$ will be sufficiently small to permit the use of Boltzmann statistics [eqs. (6), (7)]. Furthermore, electrons will be found only near the minimum (E_{\rm C}) of the conduction band and holes near the maximum (E_{\rm V}) of the valence band. In these regions the density of state $N_{\rm C}(E)$, $N_{\rm V}(E)$ can be expressed in terms of the components of the effective mass tensor $^{\rm l}$. For the case in which there is a single minimum in the conduction band and a single maximum in the valence band, the densities of states can be written in the form

$$N_{c}(E) = \left(\frac{4\pi}{h^{3}}\right)(2m_{n})^{3/2}(E - E_{c})^{1/2};$$
 (15)

$$N_V(E) = \left(\frac{4\pi}{h^3}\right)(2m_p)^{3/2}(E_V - E)^{1/2}.$$
 (16)

Here m_n and m_p are given by $(m_x m_y m_z)^{1/3}$, where m_x , m_y , m_z represent the diagonal components of the effective-mass tensor for electron at E_c and for holes at E_v . If there



is a number of minima (or maxima), (15) and (16) should be replaced by appropriate sums over the various valleys. The average masses m_n and m_p appearing in (15) and (16) are referred to as the "density-of-states" effective masses.

The intrinsic carrier densities are obtained from (4) and (5) in conjunction with (6), (7), (15), and (16):

$$n_b = n_i = \left(\frac{4\pi}{h^3}\right)(2m_n)^{3/2}\int_{E_c}^{E_c} e^{+A_c} (E - E_c)^{1/2}e^{-(E - E_F)/kT_{dE}};$$
(17)

$$p_{b} = n_{i} = \left(\frac{4\pi}{h^{3}}\right)(2m_{p})^{3/2} \int_{E_{V} - A_{V}}^{E_{V}} (E_{V} - E)^{1/2} e^{(E - E_{F})/kT} dE.$$
(18)

Because of the rapidly decreasing exponentials under the integral signs, the limits of integration $E_C + A_C$ and $E_V - A_V$ can be replaced by $+\infty$ and $-\infty$, respectively. Consequently

$$n_b = n_i = N_c e^{-(E_c - E_F)/kT};$$
 (19)

$$p_b = n_i = N_v e^{-(E_F - E_V)/kT}$$
 (20)

where

$$N_{C} \equiv 2 \left(\frac{2\pi m_{n} kT}{h^{2}} \right)^{3/2}; \qquad (21)$$



$$N_{V} = 2 \left(\frac{2\pi m_{p} kT}{h^{2}} \right)^{3/2}.$$
 (22)

Hence, for the purpose of calculating the carrier densities, the conduction and valence bands can be regarded as two single levels at energies $E_{\rm c}$ and $E_{\rm v}$ having effective densities of states $N_{\rm c}$ and $N_{\rm v}$, respectively. From (19) and (20) we have that

$$n_i^2 = N_c N_v e^{-(E_c - E_v)/kT} = N_c N_v e^{-E_g/kT}$$
 (23)

The intrinsic Fermi level, $\mathbf{E_F}^{(i)}$, is given by

$$E_{\rm F}^{(i)} = (1/2)(E_{\rm C} + E_{\rm V}) - (1/2) \, kT \ln(N_{\rm C}/N_{\rm V}).$$
 (24)

If the density-of-states effective masses for electrons and holes are equal, then $N_{\rm C}=N_{\rm V}$ and $E_{\rm F}^{(i)}$ lies exactly midway between the conduction- and valence-band edges. In most semiconductors the deviation from this position is small, since the difference in mass enters only logarithmically into the expression for $E_{\rm F}^{(i)}$.

2.1.3 <u>Semiconductors with Localized Levels</u> (See Many¹, Sze¹⁴)

We turn now to consider the effect of impurity or defect centres on the carrier densities. Evidently, as long as non-degenerate conditions prevail, the electron



and hole densities will still be given by (19) - (22), so that

$$n_b = N_c e^{-(E_C - E_F)/kT}$$
 for $(E_C - E_F) >> kT$, (25)

$$p_b = N_v e^{-(E_F - E_V)/kT} \text{ for } (E_F - E_V) >> kT.$$
 (26)

The Fermi level is no longer given by (24) but now depends on the density and energy distribution of the localized levels in the forbidden gap. On the other hand, the product $n_b p_b$ depends, as before, on temperature only:

$$n_b p_b = N_c N_v e^{-E} g^{/kT} = n_i^2.$$
 (27)

Non-degenerate conditions, for which eqs. (25) - (27) have been derived, will be assumed to hold throughout the subsequent discussions.

In some semiconductors the carrier densities are usually controlled by the introduction of shallow impurity levels. Consider then, a semiconductor having a concentration N_D of shallow donors at energy E_D just below E_C and a concentration N_A of shallow acceptor at energy E_A just above E_V . The density of electrons n_D bound to donors and of holes p_A bound to acceptors can be expressed in terms of the respective effective energies E_D^f and E_A^f [see eqs. (9) - (13)] in the form



$$n_{D} = \frac{N_{D}}{1 + \exp[(E_{D}^{f} - E_{F})/kT]};$$
 (28)

$$p_{A} = \frac{N_{A}}{1 + \exp[(E_{F} - E_{A}^{f})/kT]}$$
 (29)

The Fermi level is determined by the condition of overall electrical neutrality. The density of the negative charge is $-q(n_b + N_A - p_A)$ while that of the positive charge is $q(p_b + N_D - n_D)$. Thus

$$n_b + n_D + N_A = p_b + p_A + N_D.$$
 (30)

Using (25), (26), (28) and (29), we obtain from (30) a quadratic equation in $\exp(E_{\rm F}/{\rm kT})$ which, in the general case, must be solved numerically.

Consider an intrinsic semiconductor and introduce into it a few shallow donors whose ionization energy $E_{\rm C}$ - $E_{\rm D}$ is small compared to the forbidden gap. As long as $N_{\rm D}$ is not too large compared to $n_{\rm i}$, $E_{\rm F}$ will not depart appreciably from its intrinsic position [eq. (24)] and will remain well below $E_{\rm D}$. Use of (25) and (28) then yields

$$n_D/n_b = (N_D/N_C) e^{(E_C - E_D^f)/kT}$$
(31)

and thus $n_D^{<<}n_b^{}$. It therefore follows from the neutrality



condition [eq. (30)] that $n_b - p_b = N_D$, the donors being in effect completely ionized. Combining this condition with the relation $n_b p_b = n_i^2$ [eq. (27)], we obtain

$$n_{b} = (1/2)N_{D} \left[\left(1 + \frac{4n_{i}^{2}}{N_{D}^{2}} \right)^{1/2} + 1 \right];$$
 (32)

$$p_{b} = (1/2)N_{D} \left[\left(1 + \frac{4n_{i}^{2}}{N_{D}^{2}} \right)^{1/2} - 1 \right].$$
 (33)

Obviously n_b is greater than p_b , and we have what is called an n-type semiconductor. For $N_D^{>>n}_i$ the electrons originating from the donors far exceed those excited across the gap, and $n_b \sim N_D$. Under these conditions the electron density is essentially a constant, independent of temperature, and we have an extrinsic n-type semiconductor. And the position of Fermi level is now given by (see eq. (25)]

$$(E_C - E_F)/kT = ln(N_C/N_D).$$
 (34)

The assumption of non-degeneracy made above is valid for $N_{\rm D} \ \ \stackrel{<}{\scriptstyle \sim} \ \ 0.1 \ N_{\rm C}.$

Referring to (31), $E_c - E_D^f$ may no longer be small compared to kT (in the range of very low temperatures) and full ionization will not take place. Equations (32) and



(33) are then no longer valid and we must use the Fermi-Dirac distribution function to describe the density of the electron bound to donors. For sufficiently low temperatures

$$n_{b} = \sqrt{N_{c}N_{D}} e^{(E_{c} - E_{D}^{f})/2kT} \text{ for } E_{c} - E_{D}^{>>kT}$$
 (35)

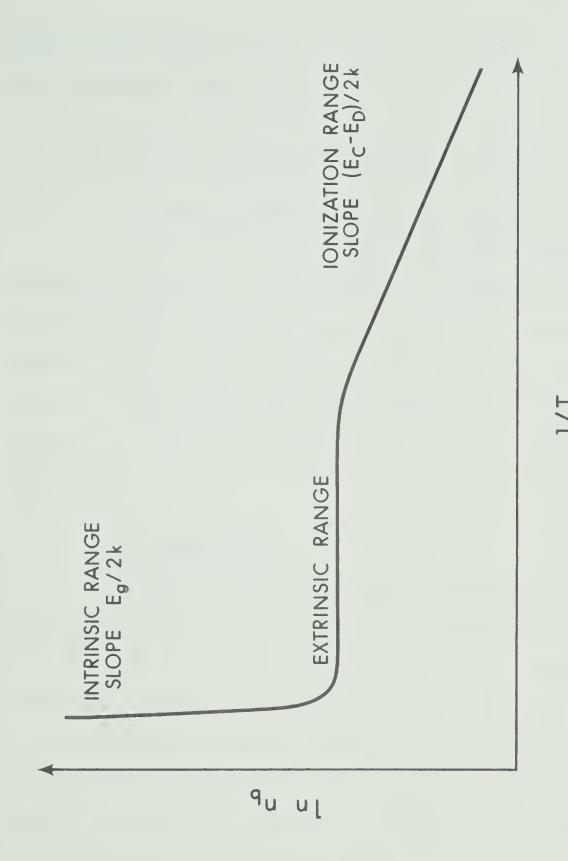
and

$$E_{\rm F} = (1/2)(E_{\rm C} + E_{\rm D}^{\rm f}) - (1/2)kT\ln(N_{\rm C}/N_{\rm D}).$$
 (36)

These equations are identical with (23) and (24) for an intrinsic semiconductor provided that ${\rm E}_{_{\rm V}}$ and ${\rm N}_{_{\rm D}}$ are replaced by ${\rm E}_{\rm D}^{\rm f}$ and ${\rm N}_{\rm D}.$

We can now see how the free-carrier density in a given semiconductor varies with temperature. This is illustrated in Figure 2 for an n-type semiconductor $(N_D>>N_A)$. Here $\ln n_b$ is plotted again 1/T, and three ranges are apparent. A very low temperature (35) holds, n_b increasing exponentially with T. The slope in this range yields the ionization energy $E_C - E_D$. As the temperature is raised extrinsic conditions are approached, and thereafter n_b is a constant (equal to $N_D - N_A$) over a considerable temperature range. At still higher temperatures, carrier excitation across the forbidden gap becomes important and (32), (33) are applicable. At sufficiently high temperature such that $n_i>>N_D - N_A$, intrinsic conditions set in and n_b





Temperature variation of the electron density Figure 2.

in an n-type semiconductor.



again varies exponentially with T [eq. (23)]. The slope now yields the energy gap E_{α} .

2.2 The Surface Space-Charge Region (See Many et al¹)

2.2.1 The Origin of the Space-Charge Region

The space-charge region near the surface of a conducting solid may be produced by an external applied electric field outside the solid, or by the proximity of another solid with a different work function. Alternatively, it may result from the presence of a localized charged layer at the surface proper, due usually to surface states.

2.2.1.1 External Field

Consider a parallel-plate capacitor having one electrode a metal and the other a semiconductor. The application of a voltage across the capacitor results in the establishment of an electric field E between the plates. A displacement of mobile charge-carriers near the surface of each plate takes place, thus giving rise to two space charge regions. The density $Q_{\rm S}$ of the induced charge on each plate is given by Gauss law:

$$Q_{S} = \varepsilon_{O} E. \tag{37}$$

Since the free carrier density in a semiconductor is much



smaller than that in a metal, the space-charge region will extend much farther into the bulk of the former. This situation is illustrated schematically in Figure 3. In order to obtain an idea of the magnitude of the total potential drop $V_{\rm S}$ between the surface and the underlying bulk, we shall approximate the potential in the space-charge region by a linear extension (dashed line). From the figure we see that

$$\frac{V_{S}}{V_{O} - V_{S}} = \frac{Z_{S}/\varepsilon_{S}}{Z_{O}}$$
 (38)

where $V_{\rm o}$ is the applied voltage, $Z_{\rm o}$ is the separation of the capacitor plates and $Z_{\rm s}$ the approximate distance (within the semiconductor) over which the potential drops to zero. An estimate of $Q_{\rm s}$ is readily obtained by Gauss' law

$$Q_{s} = \frac{-\varepsilon_{o}(V_{o} - V_{s})}{Z_{o}} \approx qn_{b}Z_{s}.$$
 (39)

Combining (38) and (39) we have

$$Z_{s} \approx \sqrt{\frac{\varepsilon_{o}\varepsilon_{s}|V_{s}|}{n_{b}q}}; \frac{V_{s}}{V_{o}-V_{s}} \approx \frac{\varepsilon_{o}(V_{o}-V_{s})}{\varepsilon_{s}Z_{o}^{2}n_{b}q}.$$
 (40)

The approximations used in deriving eq. (40) appear rather crude, nevertheless the results yield the correct order of

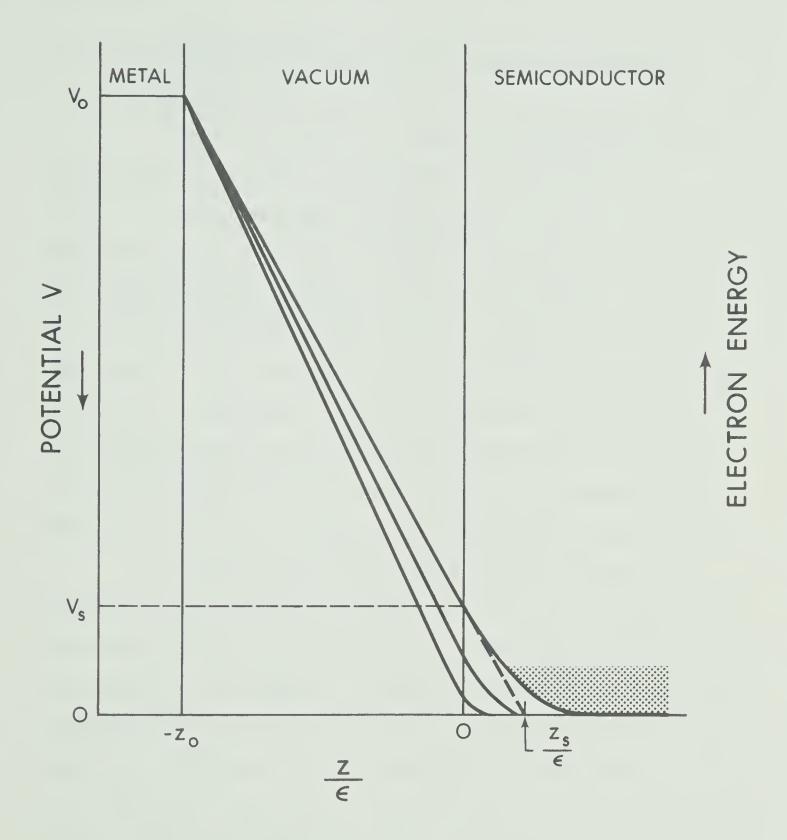


Figure 3. Potential distribution in the space-charge region.

[Space-charge region in an n-type semiconductor devoid of surface states as produced by an applied voltage between a metal and the semiconductor. The potential and electron energy are shown as functions of the normalized distance

Z/ε. The three curves are for different values of the bulk electron density n_b, the uppermost curve corresponding to the smallest n_b. The dots illustrate the electron energy distribution in the semiconductor.]







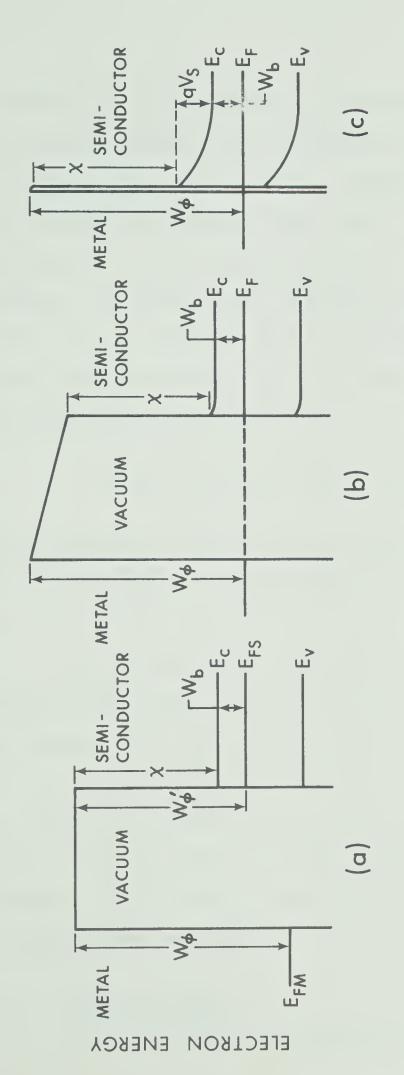
magnitude..

2.2.1.2 Contact Potential and the Metal-Semiconductor Contact

The work required to remove an electron at the Fermi level to a point in free space just outside the solid is defined as the work function W_{φ} of the solid. In semiconductors it is found useful to define a second quantity, the electron affinity X, as being the work required to remove an electron from the bottom edge of the conduction band at the surface to a point in free space just outside the semiconductor. The work function and affinity are illustrated in Figure 4a, which represents an energy-level diagram for an electron in a system composed of a metal and an n-type semiconductor separated by free space.

We now make an electrical contact between the solids in such a way as to allow the flow of electrons from one medium to the other but without disturbing the surfaces presented in the figure. In the case illustrated, the work function of the semiconductor W_{φ} ' is lower than that of the metal W_{φ} . Electrons in the semiconductor thus tend to flow into the metal and a space charge builds up at the two surfaces. This flow continues until the Fermi levels are adjusted to the same height, corresponding to thermal equilibrium conditions, as shown in Figure 4b. Because





The two an Energy-level diagram for an electron in a metal and n-type semiconductor devoid of surface states. Figure 4.

media are

- (a) isolated from one another,
- (b) in thermal equilibrium, and
- (c) in close proximity.



the separation of the metal and the semiconductor is large, the contact potential (the difference in work functions) falls mostly across the vacuum. Accordingly, the energy bands of the semiconductor bend only slightly upwards, corresponding to a small space charge. As the separation decreases, the bending of the bands increases until, the surfaces are at atomic distance (as Figure 4c), practically the whole contact potential falls across the space-charge region and $V_{\rm S}$ is given by

$$-qV_{s} = W_{\phi} - W_{\phi}' = W_{\phi} - X - W_{b}.$$
 (41)

Here $W_{\rm b}$ represents the energy difference between the Fermi level ${\rm E_F}$ and conduction-band edge ${\rm E_C}$ in the semiconductor bulk.

It follows from (41) that $V_{\rm S}$ depends on the work function of the metal and on the affinity. Contrary to these theoretical expectations, experimental evidence has shown that $V_{\rm S}$ is usually practically independent of the metal and of the conductivity of the semiconductor. To explain this discrepancy, Bardeen proposed the existence of surface states—energy levels in the forbidden gap at the semiconductor surface.

2.2.1.3 Surface States

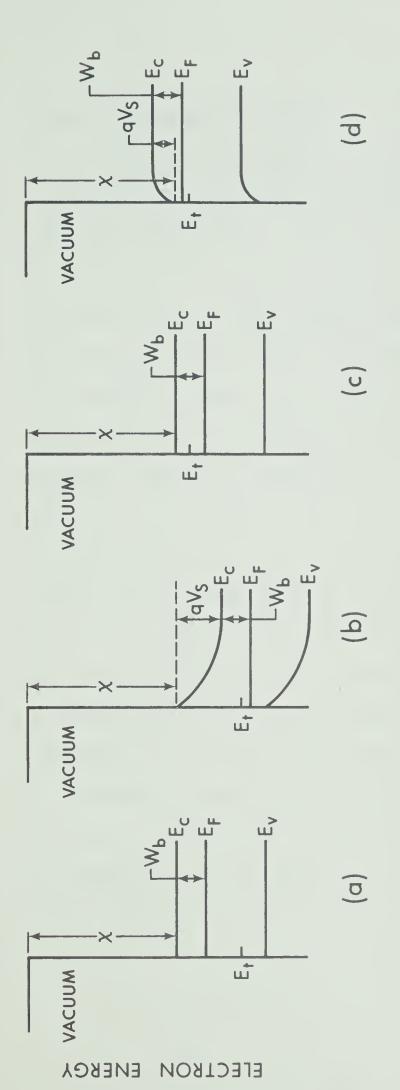
In the absence of surface states, the energy



bands of a semiconductor continue straight up to the surface, provided there is no external field. When acceptorlike surface states are introduced below the Fermi level, they will not be in equilibrium with the energy bands as long as they remain unoccupied. This situation is illustrated in Figure 5a, where the surface states have been introduced at an energy level E_{+} . Since the states are empty and below the Fermi level, some of the electrons in the conduction band fall into them. In this process, the surface becomes negatively charged while a positive spacecharge layer forms below it. Consequently, the energy bands at the surface bend upwards with respect to the Fermi level. The process of charge transfer continues until equilibrium is reached (Figure 5b). In the particular case shown, the surface states at thermal equilibrium are somewhat above the Fermi level and so are only partially filled. The larger the surface-state density, the higher the bending of the bands at the surface. The situation for donorlike surface states placed above the Fermi level is completely analogous (Figure 5c, 5d). The introduction of acceptor-like states above the Fermi level or of donorlike states below the Fermi level has of course no influence on the shape of the energy bands.

Now consider the modification that the presence of surface states introduces into the treatment of the





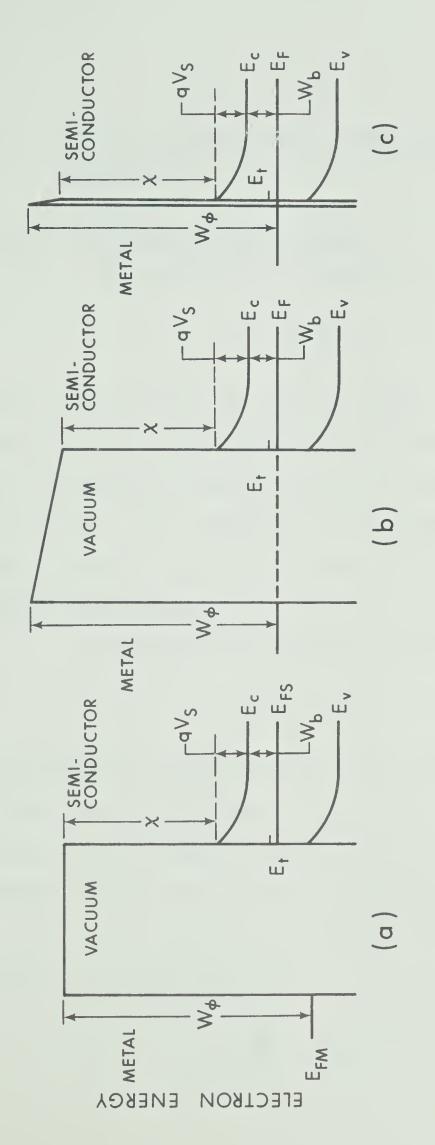
Energy-level diagram for an n-type semiconductor in the presence (d)] and donor-like [(c) and surface states at an energy level E_t. acceptor-like [(a) and (b)] . اک Figure

introduction of the surface states; (b) and (d), after thermal (a) and (c) represent conditions immediately following the equilibrium has been reached.



metal-semiconductor contact. If such states are appropriately located with respect to the Fermi level, the energy bands will be bent even before any electrical contact is made with the metal. Figure 6a illustrates this situation for the case of a large density of charged acceptor-like surface states. When thermal equilibrium is established and the two Fermi levels coincide, the energy bands of the semiconductor bend only slightly higher (Figure 6b). This slight additional bending is sufficient to cause the required number of electrons to leave the surface states and enter the metal. Thus, the field caused by the contact potential is almost entirely terminated by the surface states rather than by the space charge, and nearly the whole contact potential falls across the vacuum. This situation continues as the metal-semiconductor separation is decreased to a few interatomic distances (Figure 6c), provided the surface-state density is sufficiently large. The barrier height V_{s} then remains practically independent of the work functions of the solids, and the system behaves as though the semiconductor surface were a thin metallic film screening the bulk from external fields.





The effect of (acceptor-like) surface states on the 9 Figure

metal-semiconductor contact.

- (a) Prior to electrical contact.
- (b) After thermal equilibrium has been reached.
- (c) At close proximity.



2.2.2 The Space-Charge Pensity and the Potential Barrier (See Many 1)

2.2.2.1 Concepts and Definitions

The potential ϕ is defined by the equation

$$q\phi \equiv E_F - E_{i'}$$
 (42)

where E_i is parallel to the band edges and in the bulk coincides with the intrinsic Fermi level (Figure 7). Its exact position is given by (24), and is usually close to the mid-gap. The value of ϕ in the bulk is called the bulk potential, ϕ_b , and its value at the surface, the surface potential, ϕ_s .

The potential barrier V is defined as

$$V \equiv \phi - \phi_{b} \tag{43}$$

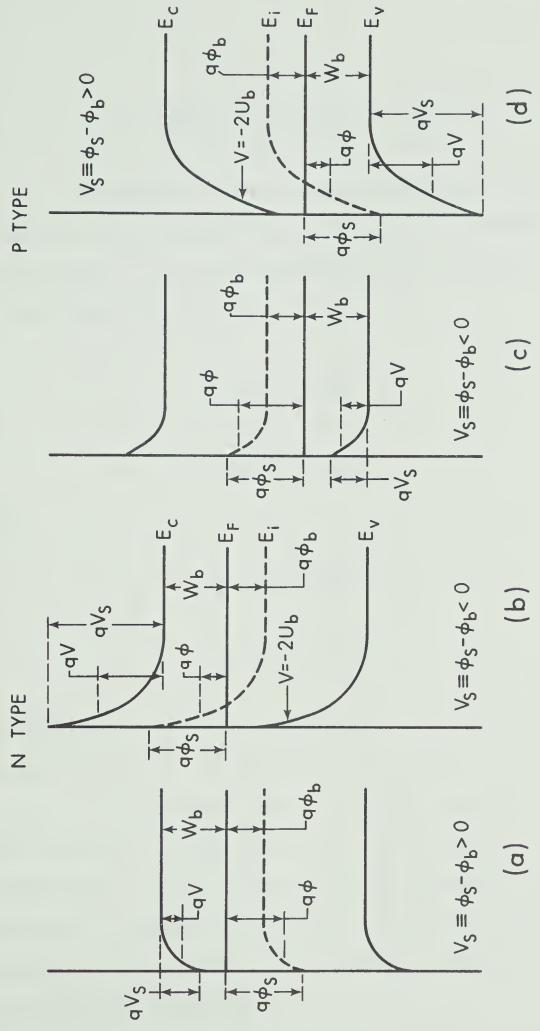
and represents the potential at any point in the space-charge region with respect to its value in the bulk. In particular the barrier height V_s ($\equiv \phi_s - \phi_b$) is the total potential difference between the surface and the bulk.

It is convenient to define dimensionless potentials u, v by the equations

$$u \equiv \frac{q\phi}{kT} = \frac{E_F - E_i}{kT}; \qquad (44)$$



(c) Inversion layer.



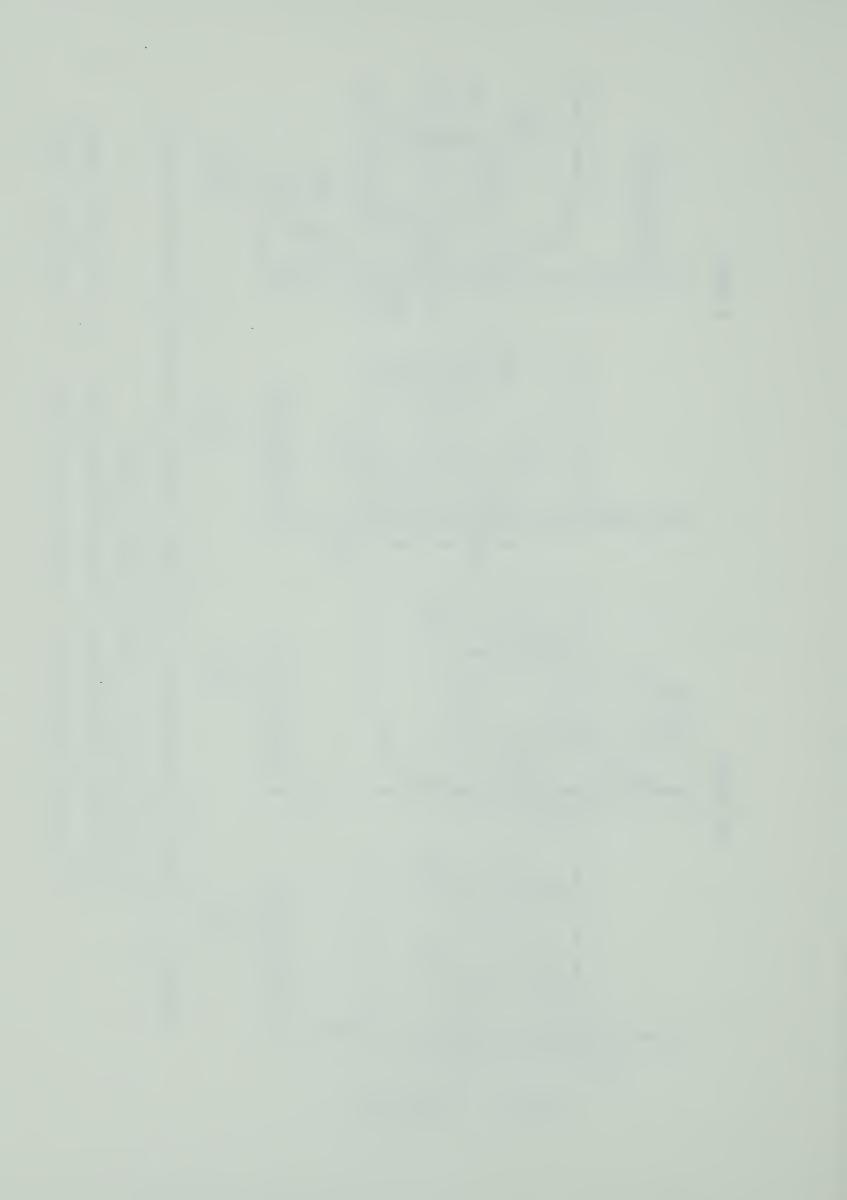
parameters used Energy-level diagram indicating the various energy Figure 7.

to characterize the space-charge region,

(b) Inversion layer. (a) n-type semiconductor, accumulation layer.

(c) p-type semiconductor, accumulation layer.

ELECTRON ENERGY



$$v \equiv \frac{qV}{kT} = \frac{q(\phi - \phi_b)}{kT} = u - \frac{q\phi_b}{kT}$$
 (45)

By means of the intrinsic carrier concentration n_i and the above definitions, the electron density n and hole density p in a non-degenerate semiconductor are given at every point by

$$n = n_i e^{u} = n_b e^{v}; (46)$$

$$p = n_i e^{-u} = p_b e^{-v},$$
 (47)

where

$$n_{b} = n_{i}e^{q\phi}b^{/kT},$$

$$p_{b} = p_{i}e^{-q\phi}b^{/kT}.$$
(48)

The condition u > 0 signifies that at that point n > p, and conversely; v > 0 implies $n > n_b$ and $p < p_b$, and conversely. At the point where u = 0 the carrier densities are intrinsic; in particular $u_b = 0$ corresponds to an intrinsic bulk, $u_s = 0$ to an intrinsic surface. When $v_s = 0$ there is no bending of the energy bands and they continue straight from the bulk to the surface. This is known as the <u>flat-band</u> condition.

When the majority-carrier density in the space-



charge region is greater than that in the bulk, the space-charge region is termed an accumulation layer. This condition obtains when the sign of v_s is the same as that of u_b [eqs. (46), (47)]: positive for n-type and negative for p-type. When the sign of v_s is opposite to that of u_b , we have either a depletion or an inversion layer. The space-charge region up to the point where the minority carrier density equals the majority-carrier bulk density ($v = -2u_b$) is called the depletion region. Between this point and the surface the minority-carrier density exceeds the majority-carrier bulk density, and this region is called the inversion region. Figure 7 illustrates the above definitions for an n- and p-type semiconductor.

2.2.2.2 Poisson's Equation 1,14,15,16

We shall derive the relations between the surface potential, space charge, and electric field in this subsection.

Figure 8 shows a more detailed band diagram at the surface of a p-type semiconductor. The potential V is defined as zero in the bulk of the semiconductor, and is measured with respect to the intrinsic Fermi level $\rm E_i$ as shown. At the semiconductor surface V = V_s, and V_s is called the surface potential. The electron and hole concentrations as functions of V are given by the following



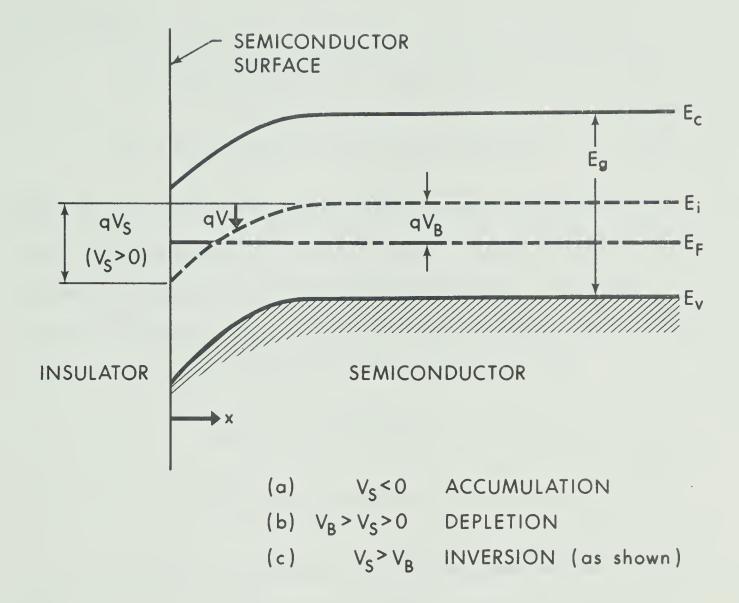
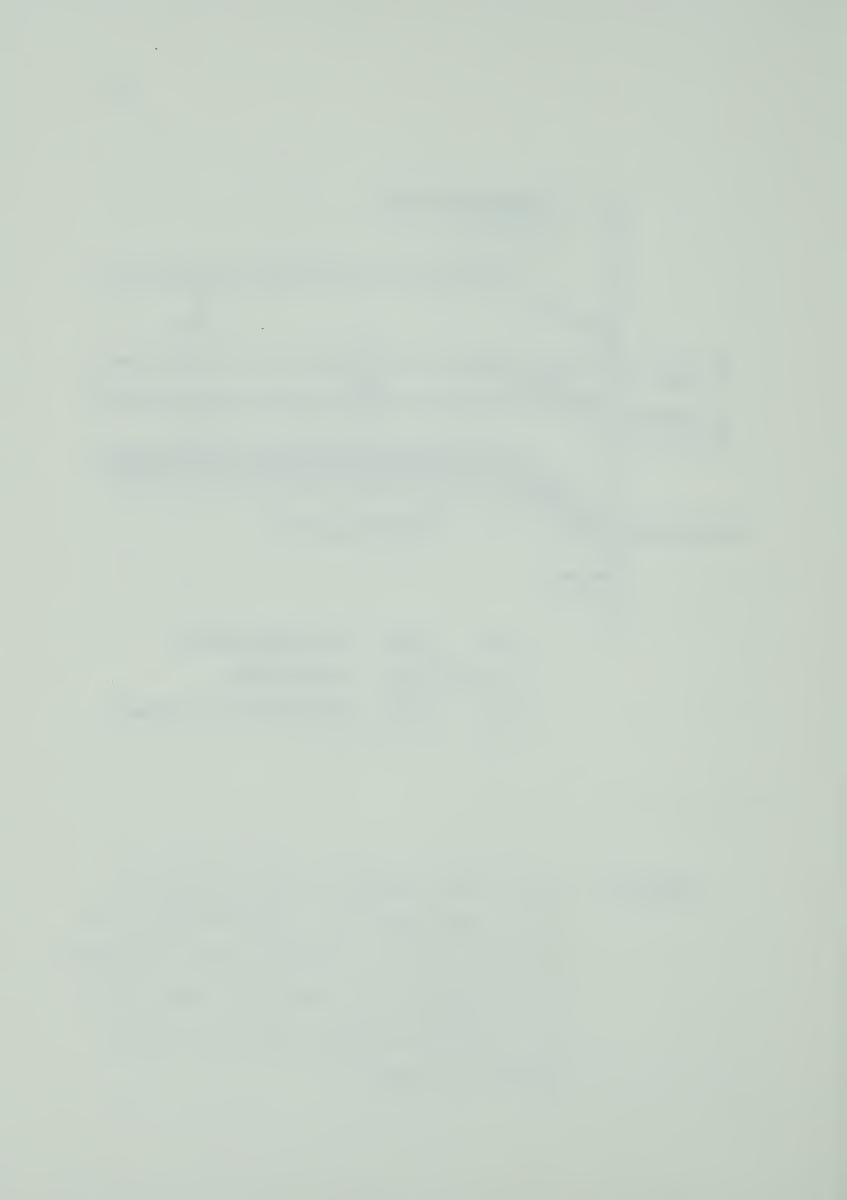


Figure 8. Energy band diagram at the surface of a p-type semiconductor. The potential V is defined as zero in the bulk and is measured with respect to the intrinsic Fermi level E_i . V_s is the surface potential and is positive as shown.



relations:

$$n_p = n_{po} \exp(qV/kT) = n_{po} \exp(\beta V);$$
 (49)

$$p_{p} = p_{po} \exp(-qV/kT) = p_{po} \exp(-\beta V), \qquad (50)$$

where V is positive when the band is bent downward (as shown in Figure 8), n_{po} and p_{po} are the equilibrium densities of electrons and holes respectively in the bulk of the semiconductor $[n_{po} = n_b, p_{po} = p_b, in eqs. (46), (47)]$, and $\beta \equiv q/kT$. At the surface the densities are

$$n_s = n_{po} \exp(\beta V_s),$$

$$p_s = p_{po} \exp(-\beta V_s).$$
(51)

It is obvious from the previous discussions and with the help of eq. (51) that the following regions of surface potential can be distinguished:

 $V_{\rm S}$ < 0 Accumulation of holes (bands bend upward), $V_{\rm S}$ = 0 Flat-band condition, $V_{\rm B}$ > $V_{\rm S}$ > 0 Depletion of holes (bands bend downward), $V_{\rm S}$ = $V_{\rm B}$ Midgap with $v_{\rm S}$ = $v_{\rm B}$ (intrinsic concentration),

 $V_{s} > V_{B}$ Inversion (electron enhancement, bands bend downward).



The potential V as a function of distance can be obtained by using the one-dimensional Poisson equation

$$\frac{\partial^2 V}{\partial x^2} = \frac{-\rho(x)}{\varepsilon_0 \varepsilon_s} \tag{52}$$

where ϵ_s is the permittivity of the semiconductor (or the dielectric constant of the semiconductor) and $\rho(X)$ is the total space-charge density given by

$$\rho(X) = q(N_D^+ - N_A^- + p_D - n_D)$$
 (53)

where N_D^+ and N_A^- are the densities of the ionized donors and acceptors respectively. Now, in the bulk of the semiconductor, far from the surface, charge neutrality must exist. Therefore $\rho(X)=0$ and V(X)=0, when $X\to\infty$, and we have

$$N_{D}^{+} - N_{A}^{-} = n_{po} - p_{po}$$
 (54)

In general for any value of V, we have from eqs. (49) and (50)

$$p_{p} - n_{p} = p_{po}e^{-\beta V} - n_{po}e^{\beta V}.$$
 (55)

The resultant Poisson's equation to be solved is therefore



$$\frac{\partial^2 V}{\partial x^2} = \frac{-q}{\varepsilon_0 \varepsilon_s} \left[p_{po} \left(e^{-\beta V} - 1 \right) - n_{po} \left(e^{\beta V} - 1 \right) \right]. \tag{56}$$

Integration of eq. (56) from the bulk toward the surface 17

$$\int_{0}^{\frac{\partial V}{\partial X}} \left(\frac{\partial V}{\partial X}\right) d\left(\frac{\partial V}{\partial X}\right) = \frac{-q}{\varepsilon_{o} \varepsilon_{s}} \int_{0}^{V} [p_{po}(e^{-\beta V} - 1) - n_{po}(e^{\beta V} - 1)] dv, \quad (57)$$

gives the relation between the electric field $\left[E=-\frac{\partial V}{\partial X}\right]$ and the potential V:

$$E^{2} = \left(\frac{2kT}{q}\right)^{2} \left(\frac{qp_{po}\beta}{2\varepsilon_{o}\varepsilon_{s}}\right) \left[\left(e^{-\beta V} + \beta V - 1\right) + \frac{n_{po}}{p_{po}}\left(e^{\beta V} - \beta V - 1\right)\right]. \tag{58}$$

We shall introduce the following abbreviation:

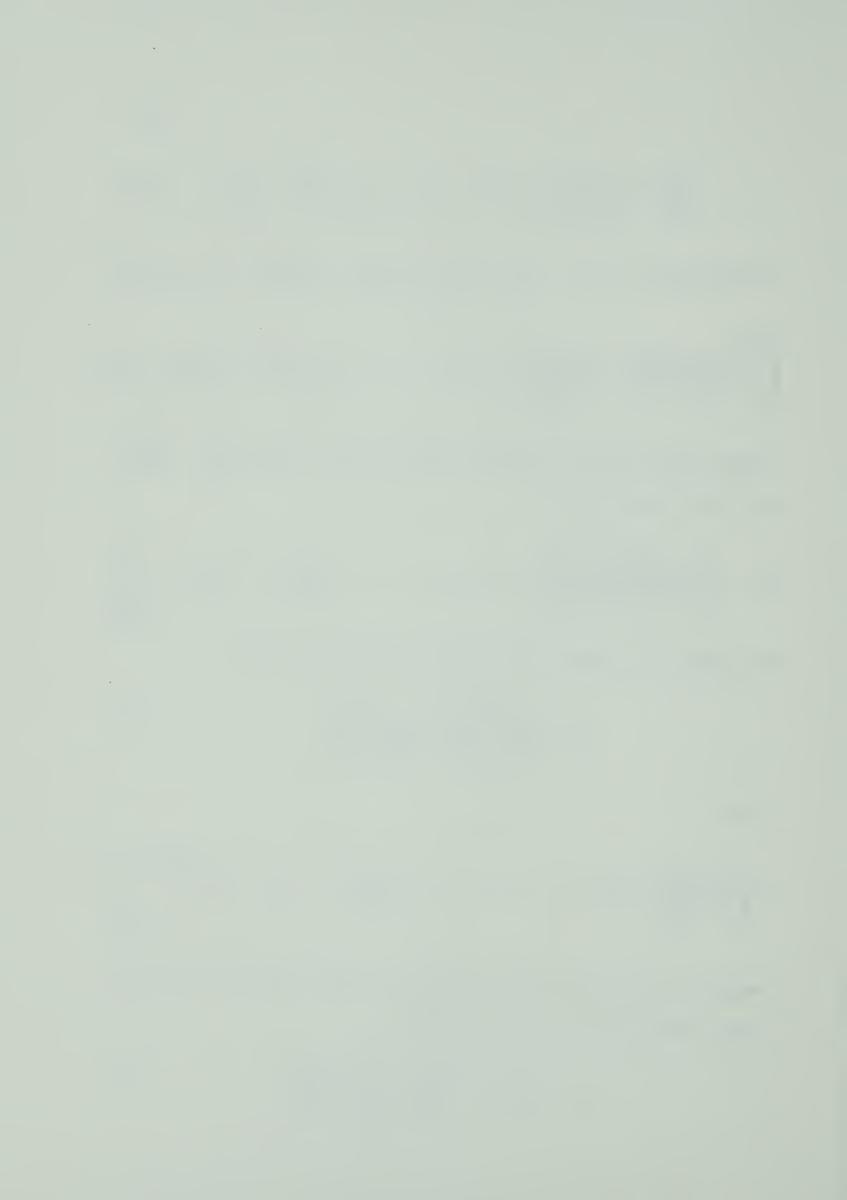
$$L_{D} = \sqrt{\frac{2kT\varepsilon_{o}\varepsilon_{s}}{p_{po}q^{2}}} = \sqrt{\frac{2\varepsilon_{o}\varepsilon_{s}}{qp_{po}\beta}}$$
 (59)

and

$$F\left(\beta V, \frac{n_{po}}{p_{po}}\right) \equiv \left[\left(e^{-\beta V} + \beta V - 1\right) + \frac{n_{po}}{p_{po}}\left(e^{\beta V} - \beta V - 1\right)\right]^{1/2} \geqslant 0,$$
(60)

where \mathbf{L}_{D} is called the extrinsic Debye length for holes. Thus the electric field becomes

$$E = -\frac{\partial V}{\partial X} = \pm \frac{2kT}{qL_D} F \left(\beta V, \frac{n_{po}}{p_{po}}\right)$$
 (61)



with positive sign for V > 0 and negative sign for V < 0. To determine the electric field at the surface, we let $V = V_s$:

$$\begin{split} \mathbf{E}_{\mathbf{S}} &= \pm \frac{2 \mathbf{k} \mathbf{T}}{q \mathbf{L}_{\mathbf{D}}} \, \mathbf{F} \left(\beta \mathbf{V}_{\mathbf{S}}, \frac{\mathbf{n}_{\mathbf{po}}}{\mathbf{p}_{\mathbf{po}}} \right) \\ &= \pm \left(\frac{2 \mathbf{k} \mathbf{T} \mathbf{p}_{\mathbf{po}}}{\varepsilon_{\mathbf{o}} \varepsilon_{\mathbf{S}}} \right)^{1/2} \left[(\mathbf{e}^{-\beta \mathbf{V}_{\mathbf{S}}} + \beta \mathbf{V}_{\mathbf{S}} - 1) + \frac{\mathbf{n}_{\mathbf{po}}}{\mathbf{p}_{\mathbf{po}}} (\mathbf{e}^{\beta \mathbf{V}_{\mathbf{S}}} - \beta \mathbf{V}_{\mathbf{S}} - 1) \right]^{1/2}. \end{split}$$

Similarly, by Gauss' law the space charge per unit area required to produce this field is

$$Q_{s} = \varepsilon_{o} \varepsilon_{s} E_{s} = \frac{1}{2} \frac{2\varepsilon_{o} \varepsilon_{s} kT}{qL_{D}} F\left(\beta V_{s}, \frac{n_{po}}{p_{po}}\right)$$

$$= \frac{1}{4} (2\varepsilon_{o} \varepsilon_{s} kTp_{po})^{1/2} [(e^{-\beta V_{s}} + \beta V_{s} - 1) + \frac{n_{po}}{p_{po}} (e^{\beta V_{s}} - \beta V_{s} - 1)]^{1/2}$$

with negative sign for $V_s > 0$ and positive sign for $V_s < 0$.

2.2.3 The Excess Surface-Carrier Densities Δn and Δp

The excess surface-carrier densities are defined as the number (per unit surface area) of mobile electrons Δn and holes Δp in the space-charge layer with respect to their number at flat bands. It should be noted that if Δn is positive then Δp is negative, and conversely. To determine the change in hole density, Δp , and electron density,



 Δn , per unit area when the potential V at the surface is shifted from zero to a final value V_s , it is necessary to evaluate the following expression 18 :

$$\Delta p = \int_{0}^{\infty} (p_{p} - p_{po}) dx = p_{po} \int_{0}^{\infty} (e^{-\beta V} - 1) dx$$

$$= \frac{qL_{p}p_{po}}{2kT} \int_{V_{s}}^{0} \frac{(e^{-\beta V} - 1) dv}{F(\beta V, \frac{n_{po}}{p_{po}})}$$
(64)

$$\Delta n = \int_{0}^{\infty} (n_{p} - n_{po}) dx = n_{po} \int_{0}^{\infty} (e^{\beta V} - 1) dx$$

$$= \frac{qL_{D}n_{po}}{2kT} \int_{V_{S}}^{0} \frac{(e^{\beta V} - 1) dv}{F(\beta V, \frac{n_{po}}{p_{po}})} = \frac{qL_{D}p_{po}}{2kT} \left[\frac{n_{po}}{p_{po}} \int_{V_{S}}^{0} \frac{(e^{\beta V} - 1) dv}{F(\beta V, \frac{n_{po}}{p_{po}})} \right].$$
(65)

It should be noted that, in terms of these quantities, the surface space-charge density $Q_{_{\mathbf{S}}}$ [in eq. (63)] can be expressed as

$$Q_{S} = q(\Delta p - \Delta n). \tag{66}$$

2.2.4 Surface Conductance, $\Delta \sigma$ (See Many et al¹)

The surface conductance $\Delta\sigma$ at any barrier height V_s is defined as the change in sample conductance per square area of its surface resulting from a change in bar-



rier height from 0 to V_s . For a homogeneous sample of uniform cross section, we have

$$\Delta\sigma = \frac{\ell^2}{A} \left(\frac{1}{R} - \frac{1}{R_0} \right). \tag{67}$$

Here A is the total surface area parallel to the direction of current flow, ℓ is the sample length, R is the sample resistance, and R_O is the value of R at V_S = 0. If we assume that the carrier mobilities in the space-charge layer are the same as those in the bulk then evidently

$$\Delta \sigma = q(\mu_n \Delta n + \mu_p \Delta p)$$

$$= q\mu_{p} (\Delta p + \frac{\mu_{n}}{\mu_{p}} \Delta n) \tag{68}$$

$$= q\mu_{p} (\Delta p + b\Delta n)$$

$$= \left(\frac{q}{kT}\right) \cdot \left(\frac{\varepsilon_{o} \varepsilon_{s} kT}{2} p_{po}\right)^{\frac{1}{2}} \mu_{p} \int_{V_{s}}^{0} \left[\left(e^{-\beta V} - 1\right) + b\left(\frac{n_{po}}{p_{po}}\right)\left(e^{\beta V} - 1\right)\right] dv$$

where b = $\frac{\mu_n}{\mu_p}$ = mobility ratio, μ_n is the electron mobility and μ_p is the hole mobility.

The dependence of surface conductance on barrier height can be seen from eq. (68). Conversely, if the surface conductance can be measured, it may be used to derive



the corresponding value of barrier height 17,18,19 . It is apparent that both accumulation and inversion layers are characterized by high conductances. In accumulation layers this is due to the large number of majority carriers, in inversion layers to the large number of minority carriers. The surface conductance is less in depletion layers and passes through a minimum value $\Delta\sigma_{\min}$ where very few mobile carriers are present in the space-charge region. The exact value V_{sm} of the barrier height at which the minimum occurs can be evaluated by differentiating (68). We then obtain 1

$$v_{sm} = \frac{qV_{sm}}{kT} \approx -2u_b - \ln\left(\frac{\mu_n}{\mu_p}\right). \tag{69}$$

In order to determine the surface conductance, the sample is provided with two non-rectifying end contacts and its resistance is measured while the potential barrier is varied by external means. Obviously the maximum in sample resistance corresponds to the minimum in surface conductance $\Delta\sigma_{\min}$. As can be seen from (69), the value v_{sm} for which this occurs is a unique (and known) function of temperature and impurity concentration.

2.3 <u>Surface States</u> 1,14,15,20

The surface states have been theoretically studied by $Tamm^8$, Shockley and others 21,22 and have been



shown to exist within the forbidden gap due to the interruption of the periodic lattice structures at the surface of a crystal. The existence of surface states was first found experimentally by Shockley and Pearson lin their surface conductance measurement. Surface states have been classified into fast and slow states. The fast states exchange charge with the conduction or valence band rapidly, and are assumed to lie close to the interface between the semiconductor and the insulator. Slow states, on the other hand, exist at the interface of the air and insulator and require a longer time for charge exchange.

2.3.1 Occupation Statistics of Single-Charge Surface States States

Consider the simplest case, that in which each centre at the surface can capture or release only one electron, thereby introducing a single allowed energy level $E_{\rm t}$ in the forbidden gap. All centers are assumed to have identical characteristics and to be present with a density $(N_{\rm t})$ that is sufficiently low to eliminate any mutual interaction. The equilibrium densities of occupied $(n_{\rm t})$ and unoccupied $(p_{\rm t} \equiv N_{\rm t} - n_{\rm t})$ centres are given by Fermi-Dirac statistics in terms of energy position of the surface states with respect to the Fermi level at the surface, in a manner analogous to that in section (2.1.3). Now,



however, N_t , n_t , p_t refer to densities per unit area. As in the case of bulk states, we introduce an effective energy level E_t^f [eq. (9)] to allow for possible multiplicity of the surface states. Recalling, further, that at the surface [see section (2.2.2.1)]

$$(E_{t}^{f} - E_{f})/kT = (E_{t}^{f} - E_{i})/kT - u_{s}$$
 (70)

 $(u_s$ being the surface potential), we have that

$$n_{t}/N_{t} = f_{n}(E_{t}^{f});$$

$$p_{t}/N_{t} = f_{p}(E_{t}^{f}),$$

$$(71)$$

where the Fermi distribution functions $f_n(E_t^f)$ and $f_p(E_t^f)$ are given by

$$f_{n}(E_{t}^{f}) = \frac{1}{1 + \exp[(E_{t}^{f} - E_{i})/kT - u_{s}]};$$

$$f_{p}(E_{t}^{f}) = \frac{1}{1 + \exp[u_{s} - (E_{t}^{f} - E_{i})/kT]}.$$
(72)

From (70) - (72) we see that when $u_s = (E_t^f - E_i)/kT$, then $n_t = p_t = 1/2 N_t$. The main change in occupation takes place within a few units of u_s ; the steepest slope occurs at $f_n(E_t^f) = 1/2$ and is equal to 1/4.



In general, we can expect the surface to have several such independent levels at energies E_{tj} and of densities N_{tj} . In this case the density of electrons captured in all surface states will be given by the sum $\sum_{j=1}^{N} t_{j} f_{n}(E_{tj}^{f})$.

2.3.2 The Variation of Surface Potential with External Field

The value of the surface potential in the absence of an external electric field is determined by the density and energy distribution of the surface states. The neutrality condition requires that

$$Q_{SS}^{O} + Q_{S}^{O} = 0;$$

 $Q_{\rm SS}$ is the charge density (per unit area) in the surface states and is equal to $-qn_{\rm t}$ for acceptor-like states and $+qp_{\rm t}$ for donor-like states, and $Q_{\rm s}$ is the space-charge density as defined in section (2.2.2.2). The superscript "o" indicates the absence of an external field. By substituting for $n_{\rm t}$, $p_{\rm t}$, $Q_{\rm s}$ from (71) and (63), we obtain

$$\frac{2\varepsilon_{o}\varepsilon_{s}^{kT}}{q^{2}L_{D}}F\left(\beta V_{s},\frac{n_{po}}{p_{po}}\right) = N_{t}f(E_{t}^{f})$$
 (73)



where the distribution function $f(E_t^f)$ represents $f_n(E_t^f)$ for acceptor-like states and $f_p(E_t^f)$ for donor-like states. It is seen that for large surface state densities

$$N_{t} > \frac{2\varepsilon_{o}\varepsilon_{s}^{kT}}{q^{2}L_{D}}$$
,

 E_t^f will be removed from E_F and donor-like states will remain relatively full and acceptor-like states relatively empty. In general, u_s (or v_s) will be determined by several levels of this type, and then in place of $N_t^f(E_t^f)$ there will appear in (73) the sum $\sum_{i=1}^{N} f(E_{t_i}^f)$ over all surface levels present.

We shall now see how the surface potential changes under the effect of an external electrostatic field applied normal to the surface. For such a case we obtain that

$$Q_{SS} + Q_{S} = Q_{T}$$

where \mathbf{Q}_{T} is the total charge induced by the field. This equation expresses the fact that the induced charge \mathbf{Q}_{T} is distributed between the surface states and the space-charge region. Under equilibrium conditions we have, similarly to (73), that

$$= \frac{2\varepsilon_0 \varepsilon_s kT}{q^2 L_D} F \left(\beta V_s, \frac{n_{po}}{p_{po}} \right) = N_t f(E_t^f) = \frac{Q_T}{q} .$$
 (74)



Here the upper sign before the second term (minus) refers to acceptor-like states and the lower sign (plus) to donor-like states. As for the first term, its sign is actually that of $Q_{\rm S}$ (negative for $V_{\rm S} > 0$, positive for $V_{\rm S} < 0$). Equation (74), which determines the new value of the surface potential, is difficult to solve in the general case. Experimentally, one usually measures $Q_{\rm S}$ and $Q_{\rm T}$ and in this way determines the surface-state density.

2.4 D. C. Field Effect

The d. c. field effect consists of the steady-state changes in surface conductance induced by electrostatic fields. For each applied field the system is allowed to reach equilibrium and the sample resistance is measured when no further change in its value is detectable. The measuring voltage across the sample is kept small compared to that applied at the field plate so as to maintain the entire surface at effectively the same potential. It is known that the geometric capacitance C_g is usually much smaller than the surface capacitance C_s . The total charge density Q_s induced at the semiconductor surface is then practically independent of the barrier height and is given by

$$Q_T = C_g V_A$$



where V_A is the voltage applied at the field plate. The induced charge is distributed between the space-charge region and the surface states, giving rise to changes δQ_S and δQ_{SS} in the free and trapped charge densities, respectively:

$$Q_{T} = \delta Q_{S} + \delta Q_{SS}. \tag{75}$$

The change in resistance that one measures results almost entirely from δQ_s [or Q_s as in eq. (63)], the mobility of the carriers in the surface states being normally orders of magnitude lower than that of the free carriers in the space-charge region. If the range of variation in sample resistance can be made to include the maximum value R_{M} , then the barrier height $V_{\rm S}$ can be determined for each value of applied field. Since for a given semiconductor (and temperature) δQ_s [or Q_s] is a known function of V_s [eq. (63)], the trapped charge δQ_{ss} can be evaluated from (75) as a function of V_s . By comparing these results with the theoretical expression for the occupation statistics (see section 2.3.1), one can determine, at least in principle, the density and energy distribution of the various surface states 23. This procedure is straightforward only if the distribution of the surface states is discrete and if the dominant sets of states are widely separated in



energy. Otherwise the comparison does not yield the distribution in a unique manner.

It should be noted that in the case being considered—d. c. fields and steady—state conditions—all the surface states participate, whatever their time constants. Thus on real surfaces of semiconductors, charge is trapped in both the fast and the slow states. The slow states, however, are usually present with a much higher density than the fast states, so that they will completely dominate the trapping process.

Care should be taken in measurements to maintain the sample at a constant temperature. The changes in surface conductance are typically of the order of 1% of the overall sample conductance.



CHAPTER III

THEORETICAL CALCULATIONS

3.1 Theoretical Calculation of the Space-Charge Density, Q_s , and the Electric Field at the Surface, E_s , as the Functions of the Surface Potential, V_s .

Using equations (62) and (63), the theoretical calculations of $Q_{\rm S}$, $E_{\rm S}$ as a function of $V_{\rm S}$ were made and the results are given graphically in Figures 9, 10, 11, and 11.

The values of parameters of Cu_2^0 in our calculations are as the following:

at room temperature, T = 300°K (deg),
$$\varepsilon_{\rm O} = 8.85 \times 10^{-12} \ {\rm farad/meter}, \\ k = 1.38 \times 10^{-23} \ {\rm Joule/deg}, \\ kT = 0.026 \ {\rm ev}, \\ q = 1.6 \times 10^{-19} \ {\rm coulomb}, \\ 8 = \frac{{\rm q}}{{\rm kT}} = 38.46 \ {\rm V}^{-1}, \\ \varepsilon_{\rm S} = 7.5 \ {\rm [for \ Cu_2O]}, \\ p_{\rm O} = 1.26 \times 10^{20} \ {\rm m}^{-3} = 1.26 \times 10^{14} \ {\rm cm}^{-3}, 24, 25, 26, 27 \\ n_{\rm O} = 7.45 \times 10^{-2} \ {\rm m}^{-3} = 7.45 \times 10^{-8} \ {\rm cm}^{-3}, 24, 25, 26, 27 \\ {\rm Therefore}, \qquad \left(\frac{{\rm n}_{\rm O}}{p_{\rm O}}\right) = 5.9 \times 10^{-22}, \\ (2kT\varepsilon_{\rm S}\varepsilon_{\rm O}p_{\rm O})^{1/2} = 1.25 \times 10^{-6} \ {\rm coulomb/m^2}, \\ \end{cases}$$



$$\left(\frac{2kTp_{o}}{\varepsilon_{s}\varepsilon_{o}}\right)^{1/2} = 1.25 \times 10^{5} \text{ volt/m.}$$

The calculations were done on the PDP-8E computer and the numerical results are presented in Tables 1, 2, 3 and 4.



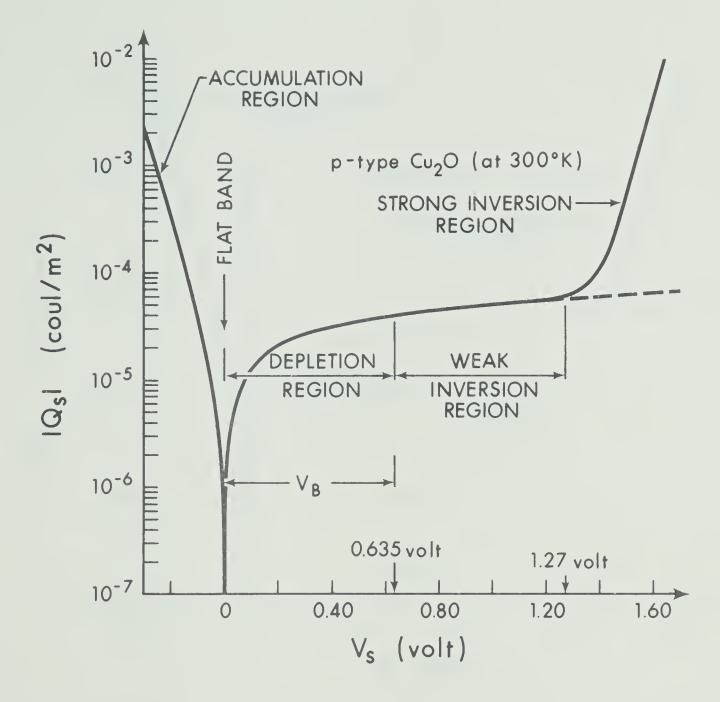


Figure 9. Theoretical curve of $|Q_s|$ vs V_s with $|Q_s|$ in coul/m².



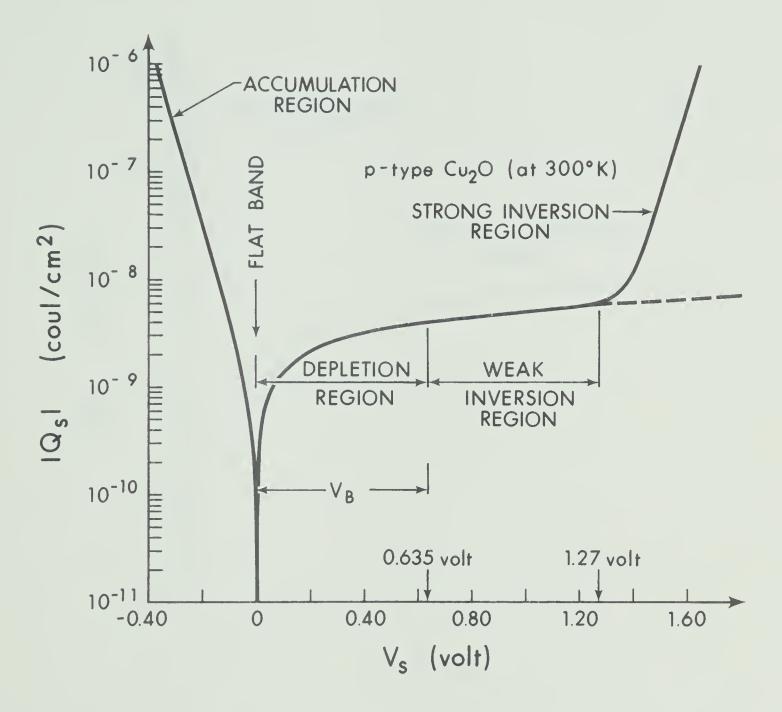


Figure 10. Theoretical curve of $|Q_s|$ vs V_s with $|Q_s|$ in coul/cm².



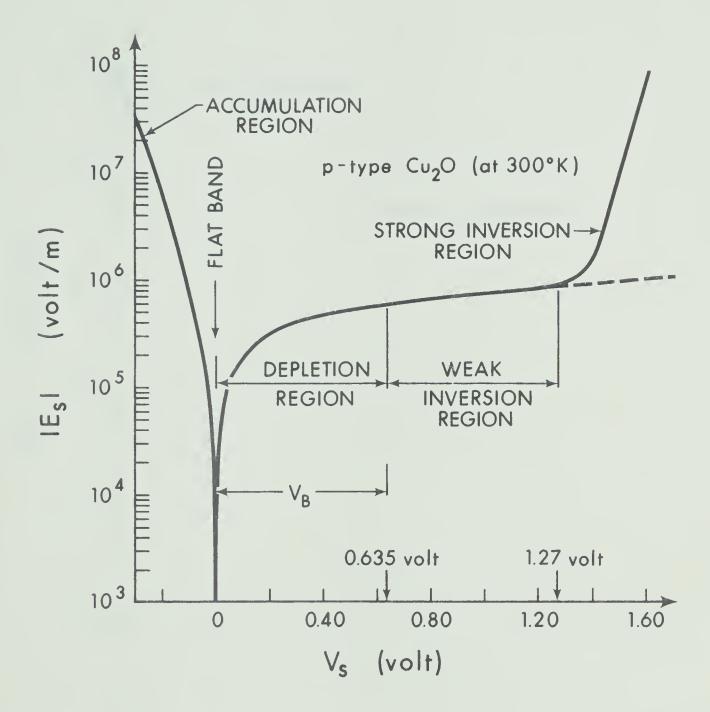


Figure 11. Theoretical curve of $|E_s|$ vs V_s with $|E_s|$ in volt/m.



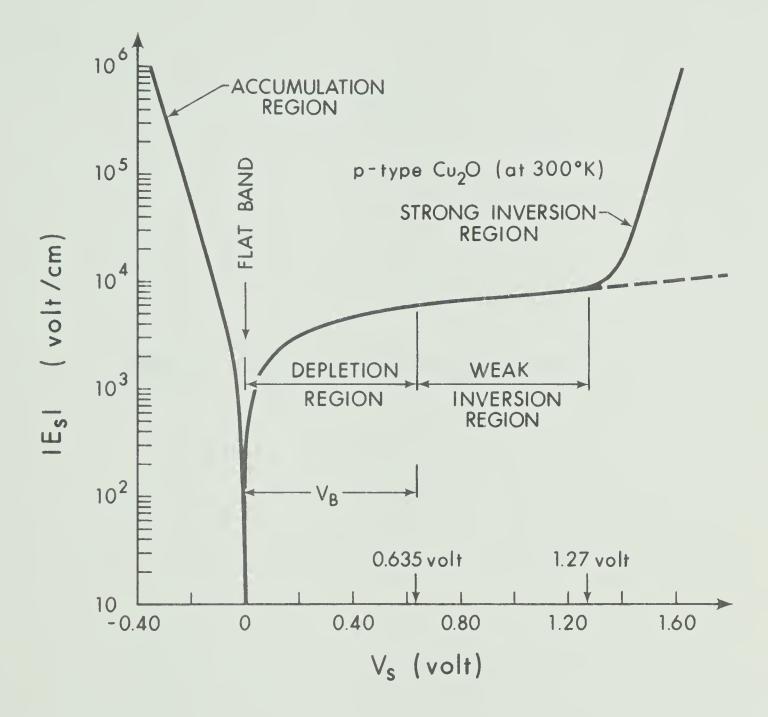


Figure 12. Theoretical curve of $|E_s|$ vs V_s with $|E_s|$ in volt/cm.



Table 1. Relation between Q_s , E_s and V_s .



C-FOCAL, 1969

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01.01 FOR V=0.00,0.05,2.00; DO 02.00
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スラメラリ リッ スリンキ1圧-23. TYPE \$3.02, U," ", 8,-0," ", 8,-0*1E-4," ", G=FEXP(C)-C-1 0=A*FS0T(D+5.9E-22*G) D=FEXP(-C)+C-1 B=6.64E-11 C=38.46*V A=8.32E-6 X=0/B N N [H] [H] 02 03 02 03 92.04 92.05 92.07 800 - 08 *GO

ET] O	(volt/cm)	8 • 0000000E+00	Ø.129562E+Ø4	0.212176E+M4	0.273723E+04	Ø.324151E+04	0.367777E+04	0.406756E+04	M.442315E+M4	0.475220E+A4	Q.505990E+04	A.534993E+NA	M . 562503E+0A	A.5887299F+64	A.613835E+A4	0.637954E+04	A • 661194所+94	0.683644E+84	Q.705380E+02
		- 11	П	11	Ш	11	11	Н	11	11	11	11	П	11	П	11	11	11	11
년 ග	(volt/m)	0 - GOBOOGOE+GO	0.129562E+06	0.212176E+06	0.273723E+06	0.324151E+06	Ø.367777E+06	0.406756E+06	M.442315E+06	0.475220E+06	9-505990E+06	M . 534993E+06	0.5625@3E+06	M.588729E+A6	M.613835E+M6	9.637954E+06	Ø.661193E+06	9.683644E+06	M.705380E+96
		П	11	П	-11	-11	11	11	11	11	-11	11	-11	-11	11	11	11	П	11
O, W	$(coul/cm^2)$	= 0.000000E+00	=-0.860292E-09	=-0.140885E-08	=-0.181752E-08	=-0.215236E-08	=-0.844264E-08	=-A.270086E-08	=-@.293697E-@8	=-0.315546E-08	=-0.335977E-08	=-0.355235E-08	=-@.3735A2E-A8	=-0.390916E-08	=-0.4075865-98	=-Ø.423601E-08	=-9.439032E-04	=-0.453939E-08	=-0.468372E-98
	1/m ²)	MONE+MO	292E-05	385E-04	752E-04	236E-04	204E-64	∞	697E-64	546E-04	977E-04	235E-04	5年2年-64	916E-M4	586E-04	601E-04	032E-04	93	3725-04
O _S	[con]	= @ • Ø Ø Ø Ø	=-0.860	=-0.1408	=-0.181	=-0.215	=-W.84420	=-0.8700	=-0.293	=-0.315	=-0.335	=-0.355	=-0.373	=-6.3909	=-0.407	=-0.423	=- 0.439	=-0.453	=-0.468



(A	(volt/cm)	9979	M.746957E+M4	0.7569回1至+月4	9.786340E+04	M.805321E+04		72E+0	-	9の4ののの五十の	6178E+0	752	2584E+B	• 1 図29 四2五十四	A . 268190F+86	91103E+0	78+3	0.4796A3E+C7	A.12544774AR	G.328121E+98	回。ならなどの以出中でな	0.2244815+09	A.587160E+40	0.153577E+10	
		11	11	П	11	11	H	П	li	11	11		11	11	Н	11	П	П	Н	11	11	П	Ш	Ш	
ក្ម ល	(volt/m)	0.726466E+06	.7469	0.766900E+06	Ø.786340E+06	0.805321E+06	0	425	771E+0	0	.1061	75299E+M	·40258	回29回8田+回		01103	9.183367E+49	5	0.1954473+10	@.328121E+10	0.858232E+10	0.224481E+11	0.587160E+11	0.153577E+12	
		11	11	П	11	11	П	П	11	11	П	П	П	11	П	П	П	П	11	[]	11	П	П	11	
O S	(coul/cm ²)	=-0.482373E-08	=-Ø.495979E-Ø8	=-0.509222E-08	=-Ø.522130E-08	=-0.534733E-08	0	8E-0	=-Ø.573544E-08	=- M • 6 M Ø S 5 6 E - 9 B	05022E-	16399E-Ø	316E-8	83271E-@	(三 (三) (三)	10	の田一の	=-0.3184611-05	=-0.8329678-05	17872	=-0.569866E-MA	=-0.149055E-d3	=-0.389R74E-B3	=-9.1019758-02	
O S	(con1/m ²)	2373	.495979	09222	130	33	(F)	.559468	3544E-	256E-0	•7Ø5@22E	16399E-0	67316	3271E-0	78078	65532E-	S= = S	8461	[7873	=-M.569866E+M9	=-0.149055E+01	=-@.389874E+01	=-0.101975E+02	
S	(volt)	•	0.	\bigcirc	1.0	•	1 • 1	1.2	N.	1.3	• 3	1 • 4	1 • 4	1.5	1.5	4-1	1.6	1 • 7	1 • 7	1.2	<u>-</u>	•	-	[P • P i	*



Table 2. Relation between Q_s , E_s and V_s .



C-FUCAL, 1969

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01.01 FOR V=0.00,0.01,1.75; DU 02.00
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次。××1五-2。 23 Y3 H H3 %, -〇米1五-4, 11, " ". CO-6% " ", U, CO, CS, EGYT O-A*FSQT(D+5.9E-20%G) D=FEXP(-C)+C-1 G=FEXP(C)-C-1 B=6.64E-11 A=8.32E-6 C=38.46*V X=0/B SET SET SET SET SET SET S SET 950 · 30 02.04 02 · 05 90.30 68.07 02.02 02 · 03 ₩C3 O

反・320万248円+54 のフェ国のガルマガン・ガ 9.108749E+94 9.148634E+M4 @.166228FF+94 ロ・1 42566円+64 M.197832E+94 0.212176E+04 Q. 225721E+04 グラ・アングスの27に出土の人 A . 25 5 5 5 5 7 5 + 8 4 ひ・どんグラロジャナログ 0.873783E+AA ロ・グタム51以上ナウム 区・めりないのののと、日本のの アガードのりいののに・の V5+3V167066.0 (volt/cm П 11 П 11 11 11 Π 11 M • 108740E+06 @.148534E+@6 M.166228E+06 0.212176E+06 A . 225721E+@6 0.0300570E+a6 ロ・2000505511100 0.294914E+05 2・3ののののなのの日十回の の・6の428の五十回5 回・202222日十回5 ほ・1 名のじんの田+のん 6.19783851166 ひ。 いいののいのと 日子のの 0.873723E+46 **6.28848181466** A.129562E+46 (volt/m) П 11 П [] П || 11 11 =-0.140885E-08 =-0.149879E-08 =-A.166536E-08 =-0.195823E-08 =-0.212645E-09 =-0.722032E-09 100100431001111 =-0.131361E-08 --同・158410円-08 =-0.174343E-48 =-0.181752E-08 =-0.188916E-68 =-0.401248E-09 =-0.569926E-09 のの一国ののののののの・ガー= =-0.986924E-09 =-0.110375E-08 $Q_{\rm s}$ ($coul/cm^2$) 11 =-0.188916E-04 図・6000000HH QC =-0.212645E-95 =-0.401248E-05 =-0.722032E-05 =- G - 86@292E-45 =-0.986928E-05 =-0.121224E-04 =-0.131361E-04 =-0.140885E-04 =-0.149879E-04 =-0.158410E-04 =-0.1743A3E-04 =-A.181752E-AA =- 0.195823E-04 =-図・569926周-位5 =-0.110375E-04 =-4.166536E-@4 $(coul/m^2)$ [] (volt) E. 13 O.14 Q. 0.22 0.05 J. A8 Ø • 10 M • 12 7.15 0.16 0.01 Q . Q3 0.04 0.96 70.8 0.09 U 0.11 П 11 [] П 11 П 11 П



[1]	(volt/cm)	968	0.314735E+74	2415	M • 333332E+44	4226	0.359976E+A4	59	6777	.3758	$\mathcal{C}\mathcal{I}$.391630	.39996	6756	141123	1340E	8446	$ \infty $	231	9789	.455	8339	C,	5000	3		G. 493912E+64	4.49998887404	M.5059908442	1192	0.5177463+04	4 · 5 9 3 5 3 5 5 5 + 6 4
		П	-11																											11		
团	(volt/m)	@4888E+@	4705E+0	24151E+0	M • 333332E+06	.342267E+A	50976E+0	.359474E+0	67777E+9	•375896臣	•383844至+0	91630E+0	•3992655+0	•496756五+9	14112E+M	D+E017	8446年中	35月+四	2315E+0	ことの用する	57695+9	+	8945+N	+	9	761E+0	0.4939128+06	4.499988E+06	A.545990E+46	1922E	•517786E+0	23585540
		11	11	11	11	П	11	П	11	11	11	П	П	11	11	11	11	11	11	11	11	П	11	11	11	11	11	11	П	11	11	11
Ø	$(coul/cm^2)$	667	コード・20年8964月-68	15236五-0	332E-0	265E-0	048E-0	.238691E-0	204E-0	=-0.849595E-08	872E-0	-@.26@@42E-9	5112年-6	70086E-0	74971E-0	.279770E-9	84488E-0	129	9697三-9	195E-0	2626年-0	0.6993	1299E-A	.315546E-@	9737E-0	873	958E-0	=-0.331992E-08	977E-0	1	0-E0	=-Ø.347669E-@8
Q	$(cou1/m^2)$	-0.202499年-	208964E-0	-215236E-0	-221332E-0	-827266E-0	-0.233048E-0	-0.238691E-0	44204E-0	-1	-0.254872E-0	-0.260042E-0	-0.265112E-0	-0.27@@86E-@	-0.274971E-0	79770E-0	-0.284488E-0	89129压-网	.293697E-9	-0.298195E-0	·342626E-0	- 何。396993至- 何	11299E-4	-0.315546E-	19737E-0	•323873E-Ø	27958E-0	31992E-	35977E-	165-0	RICE	=-0.347660E-04
>	(volt	•		0	Q.1 •	N	ÇŬ •	Q.		0.26	S	3	N •	O	°	$ \mathcal{C} $	ლ •	°	°	ന	3		(Y)	ī7 •	0.41			0.44	4.45	0.46	4	0.48
	_																													11		



$E_{\rm S}$ (volt/cm)	0.529320E+04 0.534993E+94 0.540607E+04	.546163E+A	51664	•557119里+0	.56250	.567845	7313	7838	G.583578E+64	887	938	.598897	3918	MRR96	Q.613×355+04	187	233	84	a . 63	n.6379	0.642	0.6473	9.651997E+94	回・656611E+aか	N.661193E+na	0.66574475+94	0.6749648+34	G. 674753E+0A	G-679213E+64
$E_{\rm S}$ (volt/m)	0.529320E+06 = 0.534993E+06 = 0.540607E+06 = 0.540607E+06	.546163E+06	·551663E+96	·557110E+06	•5625A3E+A	·567845E+96	•573137E+Ø	·578381E+06	•583578E+06	.588729E+0	·593835E+06	·598897E+06	M3918E+06	·608896五十四	•613835E+06	.618734E+0		84175+06	33293E+0	•637954五+86	42669E+M6	@.647359E+06 =	7E+06	@.656611E+06 =	A.6611938+96 =	0.665744E+A6 =	G.67026/18+06 =		M.679213E+86 =
$Q_{\rm s}$ (coul/cm ²)	=-0.351468E-08 = =-0.355235E-08 = =-0.358963E-08 =	-0.362652E-08	9-368699	-Ø.369921E-AB	-Ø.3735@2E-@8	-0.377049E-08	.38M563E-M8	-M.384045E-08	874955-08	6月-08	-394306E-08	-0.397668E-08	-08	-0.404307E-08	86E-08	-0.419839E-08	6표-의왕	7269E-08	=-0.420447E-08 =	=-0.423601E-08 =	=-0.426732E-08 =	=-0.429840E-08 =		=-4.435990E-08 =	=-0.439@32E-08 =	=-M.442054E-98 =	=-0.4456558-04 =	=-0.448036E-08 =	=-0.450997E-08 =
$Q_{\rm s}$ (coul/m ²)	=-0.351468E-04 =-0.355235E-04 =-0.358963E-04	-0.362652E-0	.366305	.69921E-Ø	MSE-M	77049E-0	Ø563E-Ø	4045E-0	87495E-0	M916E-G	.394306E-0	-0.397668E-0	.401001E-	307E-0	.407586E-0	10839E-0	4966E-0	0-I69	0447E-0	01E-0	2E-0	2		=-Ø.435990E-04	=-0.439932E-04	=-0.448054E-04	=-0.4450558-04	=-0.448836E-04	=-0.450997E-04
$V_{\rm S}$ (volt)	= 8 · 49	0. S	0.5	0.5	0.5	0.5	0.5	Ø • 5	0.5	9 · 6	0 · 0	6.6	9.0	Ø • 6	0.6	0.6	0.6	0.6	0.0	0.7	0.7	0.7	N - 7	0.7	0.7	1.0	0.7	0.7	D • 7



$E_{\rm S}$ (volt/cm)	0.683644=+04 0.688046E+64 0.692420E+04	·696767E+0	7/// 1// 8/8// 1// 7// 1// 8/8// 1// 7// 1// 8/8// 1// 1// 1// 1// 1// 1// 1//	·/四538924 ·/四9647E+	.713889	·7181068+0	7222	· 738619出+9	34731	388	968₽	• 746	54988	54997	8986	8953	Q.7669AAE+AQ	M.770827E+04	0.774735E+04	0.7786828+44	0.788491E+64	P.786340E+P4	0.790171E+M4	G.7939848+04	0.7977865+04	G.801558E+04	0.805321E+04
E _s (volt/m)	0.683644E+96 = 0.688946E+86 = 0.692428E+96 = 0.692428E+96	.696766E+96	•701086E+0	0.1003808+00 = 0.1009647E+06 =	•713889五+06	·718105E+0	•722298五+回6 706266日+B6	2612日十26	•734730E+	.738828E+0	.742903E+0	•746957五+四	•750988E+06	•754997三+46	·758985E+46	•762953五+月	669@@E+#6	· 7708	•774735E+0	0.778622E+@6 =	M.782491E+86 =	M.786349E+86 =	A.790171E+06 =	0.79398435+06 =	9.797780E+06 =	558E+06	A.805321E+46 =
$Q_{\rm s}$ (coul/cm ²)	=-0.453939E-08 = =-0.456862E-08 = ==-0.456862E-08 = ==	-0.462653E-08 =	-@.465521E-08 =	x x	21111111111111111111111111111111111111	-0.476822E-98 =	• 4796@5E-88 ==	-0.485185E-08 II	.487861E-98 =	0582E-08 =	3288E-98 =	79E-38 =	98656三-四名 =	-A.5@1318E-@8 =	43966E-68 =	@1E-38 ==	= ダロー国るなるらい	11829E-08 =	14424年-68 =	17005E-08 =	=-0.519574E-68 = (22130E-48 =	=-0.524674E-A9 =	=-0.587205E-93 =	=-0.529726E-48 =	=-0.532235E-08 =	=-0.534733E-98 =
$Q_{\rm s} \qquad ({\rm coul/m}^2)$	=-0.453939E-04 =-0.456862E-04 =-0.459767E-04	-0.462653E-9	-Ø.465521E-Ø	アンドロの日	.474682E-0	•476822E-9	479605E-	-Ø.485185E-Ø	-9.487861E-0	.490582E-0	.493288E-	.495979E-0	-0.498656E-0	-0.591318E-0	-0.573966E	·506601E-G	A9222E-	11829	14484	1700	-0.519574形-	=-0.522130E-94		272		- M • 53223	=-0.534733E-04
V S (volt		©.	S C	Ξ & 	© •	©	20 13 20 00		(C)	0,	6.0	9.0	0.0	0.0	0.0	6 · E	1.0	0 -	•	1 • (3	(C) -	•	1.0	1.0	•	-	•



ETJ OX	(volt/cm)	M - 8090	G.812800	0.8165	0	: Ø・823930E+Ø4	0.8876	6.8313	0.83	0.838	0.84257	0.84	0.85040	0.8545	0.858967	ي. ب	M.869152	M . 87538@	の・882847月+の	n.892118	0.903999E+0	M.91963	9.940635	Ø.96919	0.100829E+0	0.106178E+0	•	G-193255E+G	N-136276E+0	- A - 15335988+05	の・175099円+の	 □ □ • □ □ □ □ □ □ □ □ □ □ □ □ □ □ □ □ □
trj W	(volt/m)	Q.	·812800	16519年406	·820228日+06	・823930五+内6	27629E+@6	·831331E+06	835回45五+96	•838786臣+何6	·842571E+06	464315+96	•850406E+46	*854555E+06	・858967日+96	0.863771E+96 =	• 869158日+46	•875380压+06	·882847E+06	·892118E+06	•9月3999日+月6	.919637E+06	.94@635E+Ø6	69197E+06		06178E+07	0.113455E+07 =	G.123255E+47 =	M.136276E+07 =	M.153320E+M7 =	0.175299E+07 =	M.2M3253E+07 =
Q	$(coul/cm^2)$	2	39699E-MR	169E-08		=-0.547089E-08 =		04E-08	14470E-08	6954E-08	9467E-08	62030E-08	64669里-网络	67424E-08	70354E-08	五-08	77117E-08	81252E-98	6210E-08	92366压-可8	0255E-08	Ø639E-Ø8	4581E-08	47E-08			=-0.753342E-08 =	=-0.818410E-08 =	=-0.9048708-08 =	=-0.1018045-07 =	=-0.116398E-07 =	=-0.134960E-07 =
	$(coul/m^2)$	-Ø.5372	=-Ø.539699E-04	.542169E-	44631E-	0-国(7	52004	470E-0	56954五-四	467E-0	62030E-0	669E-0	67424E-0	70354E-0	=-0.573544E-04	77117E-8	81252E-	86210E-0	92366E-0	00255E-0	10639E-	24581E-0	43547E-0	504E-0	221E-0	3342E-0	=-0.818410E-04	=-0.904870E-04	176	8日-四	=-A.13496AE-B3
> S	(volt	•	1.12	•		= 1 • 15	= 1.16	= 1 • 17	• -	1 • 1	1.2	1.2	1.2	1.00		= 1.25	1.2	1.2	1.2	1.2	1.3	1.3	1.3	1.3	1 • 3	1.3	1.3	1.3	1.3		= 1.400	= 1 • 41



터 0	(volt/cm)	@ - 238388F+B	四,282126三十四	0.336171E+A	A - 4 M 2 5 8 2 E + M	M • 483855E+0	0.583026E+0	M.703790E+0	0.850639E+0	0.102902E+0	M.124555E+0	Ø • 15@888E+€	0.182695E+0	Ø.221337E+Ø	A - 268190E+0	例・324989日+8	9-393843E+0	0.477308E+0	0.578475E+@	0.701A99E+A	回・849788四十回	G - 100900001+0	回・124823E+A	M • 151288E+E	M.1833655+4	M. 222244E+G	G • 269366医+C	M.326480E+0	0.3957@3E+@	0.479607E+0	0.581299E+0	M.70455284+0	· 853	Q • 1 Q 8 5 Q 1 E + B	0.125447E+0
<u>ন</u> জ	(yolt/m)	38388E+07	·282126E+07	36171E+07	.402582E+07	•483855五+97	83026E+07	.703790E+07	·850639E+07	•102902五+08	•124555E+08	•150828E+08	•182695E+08	·221337E+08	·268190E+08	•384989日+68	• 393843E+08	•477398至+68	578475E+08	•701099E+08	·849728E+08	1月2988日十月9	· 124823E+09	·151288E+49	833658+49	· 222244E+09	69366E+09	•326480至+99	957A3E+A9	79697E+09	1299压+49	94552E+09	G.853939E+49	01E+10	47E+10
·	oul/cm ²)	8289E-07	7331E-07	3217E-07	7315E-07	1279E-07	7129E-97	7316E-07	4824E-07	3267E-07	7046E-07	0149E-06	1309E-06	90-38969	8078E-06	5793E-06	1512E-06	6932至-96	ıΩ	5530E-A6	4219E-M6	3841E-06	8885里-66	0455E-05	1754E-05	75708-05	8859E-45	6783E-05	2747E-05	459E-05	5982E-05	883E-05	0	248E-05	67E-05
	()	$-03 = -0 \cdot 1$	-0.3 = -0.1	-M3 =-0.2	- M3 = - M · P	-03 =-0.3	-03 =-0.3	-03 =-0.4	-03 = -0.5	-03 =-0.6	-03 =-0.8	-02 =-0.1	-02 =-0.1	-M2 =-M.1	-02 =-0.1	2.0-= 20-	-02 =-0·D	-02 =-0.3	-02 =-M·3	-02 =-0.4	-02 =- W.5	-08 =-W.6	-02 II-8.2	-01 =-0.1	-01 =-0.1	-01 =-0.1	-01 =-0.1	-01 =-9.	-01	$-\varnothing 1 = -\varnothing .$	-Ø1 =	\subseteq	E-01 =-0.5	-01 =-0	1 0 -
Q S	(coul/m	- @ • 158289	-0.187331	-A.223217	-M.267315	-0.321279	-0.387129	-0.467316	-0.564824	83267	-0.827046	-0.100150	-0.121309	-0.146968	-0.178078	-9.215793	-0.261512	-M.316932	.384107	-9.465530	-M.564219	-M.683841	- a . 828826	90455	-0.121754	-0.147570	-0.178859	-Ø.216783	62747	18459	988	67823	=-0.567016	687248	32967
N S	(volt)	1.4	7 • 7	1.4	1.4	1 • 4	1.4	1 • 4	1.4	1.5	1 • 5	1 • 5	1.5	1.5	1 • 5	1.5	•	1.5	5	1.5	1.6	1.6	1.6	1.6	1.6	• 0	1.6	1.00	1.6	1.07	1 • 7	1.7	= 1.73	1 . 7	1 . 7



Table 3. Relation between Q_s , E_s and V_s .



C-FUCAL, 1969

```
01.01 FOR V=-1.50,0.05,-0.05; DO 02.00
```

02.01	T A
30·30	SET B=6.64E-11
02 · 03	
02.04	
08.05	
08.00	Ċ
T0.30	[1]
05·08	TYPE \$3.02.00.11 11, \$3.0, 11 11, \$3.0*1E-4, 11 11, \$3x, 11 11, \$3x, 1
05%	

Es (volt/cm)	=-0.421869E+16 =-0.161289E+16 =-0.616638E+15 =-0.901328E+14 =-0.901328E+14 =-0.901328E+14 =-0.131745E+14 =-0.131745E+14 =-0.131745E+14 =-0.131745E+14 =-0.131745E+14 =-0.131745E+14 =-0.131745E+14 =-0.131745E+11 =-0.28147E+15 =-0.117614E+15
$E_{\rm S}$ (volt/m)	=-0.421869E+18 =-0.151289E+18 =-0.535752E+17 =-0.981328E+17 =-0.981328E+16 =-0.131745E+16 =-0.131745E+16 =-0.131745E+16 =-0.131745E+16 =-0.131745E+16 =-0.131745E+16 =-0.131745E+16 =-0.131745E+13 =-0.137297E+14
$Q_{\rm s}$ (coul/cm ²)	
$Q_{\rm s}$ (coul/m ²)	0.280121E+08 = 0.107096E+08 = 0.409448E+07 = 0.598488E+07 = 0.288812E+06 = 0.874790E+05 = 0.874790E+05 = 0.187866E+05 = 0.187866E+05 = 0.186900E+04 = 0.714556E+03 = 0.104445E+03 = 0.1044445E+03 = 0.1044445E+03 = 0.104445E+03 = 0.104445E+03 = 0.104445E+03 = 0.10
V _s (volt)	



<u>ក</u> ្ម ល	(volt/cm)	=-0.6M1376E+10	E - 8899918E+16	=-4.879@20E+@9	=-0.3360665+49	=-0.1284R5E+49	=-0.491223E+Ø8	=-0.1878045+98	=-0.7180103+07	=-0.874509E+n7	=-0.104949E+07	=-0.4018805+96	=-0.153349E+06	=-0.585327 8+95	=-0.221844E+05	=-0.811673E+A4	=-6.848A43E+AA	
[<u>1</u>]	(volt/m)	=-0.601376E+12	=-0.229918E+12	=-0.879何19五+11	=-0.336066E+11	=-0.128485E+11	=-0.491223E+10	=-0.187804E+10	=-0.718Ø1ØE+Ø9	=-0.2745095+09	=-0.104949E+09	=-0.401220E+08	=-0.153349E+08	=-0.585327E+07	=-0.2218445+07	=-0.811673E+06	=-0·248043E+06	
O, o,	(coul/cm ²)	M・399313王-M2	0.152665E-02	0.583669E-03	Ø.223148E-03	0.853138E-04	Ø.326172E-04	0.124702E-04	0.476759E-05	0.182274E-05	0.696861E-06	0.266410E-96	0.101824E-06	0.388657E-07	0.147305E-07	Ø.538951E-08	Ø.1647@1E-08	
		11	11	11	11	11	11	11	Н	П	Ħ	11	11	11	11	11	11	
S O	(coul/m ²)	例 - 399313 五十四2	0.152665E+02	0.583669E+01	M.223148E+01	M.853138E+00	0.326172E+00	Ø.124702E+00	Ø-476759E-01	0.182274E-01	Ø-696861E-02	0.266410E-02	0.101824E-02	Ø.388657E-03	Ø • 147305E - 03	M.538951E-04	0.164701E-04	
	_	П	11	11	11	11	}	11	11	11	Н	Н	11	11	11	Н	11	
> %	(volt	=-0.80	=-0.75	=-0.70	=-0.65	=-0.60	=-0.55	=-0.50	=-0.45	=-0.40	=-0.35	=-0.30	=-0.25	=-03.80	=-0.15	$=-\emptyset \cdot 1\emptyset$	=-0.05	-X-



<u>Table 4</u>. Relation between Q_s , E_s and V_s .



=- 0 - 19 1648 E+1

=-A.19A64RE+13 =-A.157295E+13 =-A.129778E+13

M.126594E-41 0.104444E-41

=-0.157295WF1

=-0-1070748+1

=-0.1070748+13

0.710974E-02

6-861728E-92

0.1044448+43 0.861728E+48 0.714974E+08

点・126590円+03

=-U.86

=-0.85

=-0.83

```
01.01 FOR V=-1.00.0.01.-0.01; DO 02.00
01.02 OUIT
```

8.5 ○*1 王-4.5 11 11, 8.5 - × 1 五-2.5 1 1 1 1 8.5 - × 1 五 - 2.5 =-0.281473E+19 -- 8-832832五十12 -- 0・1916661+10 11-20・1000000円+10 =- @ • 13@43@E+19 =-0.107613412 11+国のツガーンカ・ガー川 =-0.7325454+1 =-0.498660E+1 =-0.411494941 11日の33のないの国土1 =-0.931071E+1 -- 0・6月4394日+1 =- M . 28 M M 66 13 + 1 (volt/cm) =-0.281473E+14 =-Ø.232232E+14 =-0.191606E+14 =- 年・158686日+14 =-Ø.130430E+14 =-0.107613E+14 =-0.732545E+13 =- M • 6 M 4 3 9 4 E + 1 3 =-0.498660E+13 =-0.33945@H+13 =-W.2899466E+13 =-6.2316718+13 =-c - 887868E+13 =-0.411484E+13 (volt/m) 0.154202E+00 Ø • 186898E+ØØ M.127226E+00 0.1049695+00 M.486410E-01 M . 331110E-01 **3・866回58円-回1** 0.714549E-41 M.225395E-01 G-153431E-91 0.589544E-01 で・ピアの184円・ピーロー 0.401318E-01 0.185964E-0 $(coul/cm^2)$ TYPE \$3.02, V, " ", S, O, " ", SET 0=A*FSOT(D+5.9E-22*G) D=FEXP(-C)+C-1 11 11 11 11 11 11 11 11 11 11 11 G=FEXP(C)-C-1 M.273186E+03 Ø・186898日+Ø4 Ø.127226E+04 0.486410E+03 0.331110E+03 月 - 225395日+ 43 M • 185964压+03 Ø • 153431E+@3 0 • 154202E+44 Ø • 104969E+64 の・なんんのいな田中のの 0.714549E+03 Ø.589544E+Ø3 0.401318E+03 B=6.64E-11 $Q_{\rm s}$ (coul/m²) A=8.32E-6 C=38.46*V SET X=0/B s (volt) SET SET SET SET SET 11 11 11 11 11 11 11 11 11 =-1.000 66 · Ø-= =-0.98 96.0-= M6.0-= -- W • 97 =-0.95 =-0·04 =-@·98 =-U.89 =-0.93 =-0.91 =-0.88 78.0-= 02.08 08 · 06 08.04 04 02.05 92.07 02.02 02.03



円 20	(volt/cm)	42	=-0.7283815+10	1371	.496166	- 0 - 409367三+1	.3377	78665E+1	66	200	-0.1565493+1	9	06539E+1	79012EF49	-A.725237E+0	.598365	-U-493686B+G	0738AE+0	-0.3364	.977979F+A	- 2 · 22 8	-0.188746	55727E+0	484	=-0.1060165+49	C. X74616E+68	1.78	=-M.595372E+d8	=-0.491218E+98	G • 4050 X X X + C X	-0.3343K3E+0	11・ロ・の12の対象のの第十点の
EŢ W	(voit/m)	429E+1	3881E+1	3715+1	6166E+1	.40936	7752E+1	8665E+1	9915E+1	89694E+1	- 6 - 156569至+1	9129E+1	•186539五+1	79912日+1	- 0.725237至+1	-0.598364E+1	-0.493686E+1	7329年1	6063月+1	7272E+1	66E+1	7465+1		=-0.128484E+11	=-0.106006E+11	6E+1	21612E+1	=-n.595372E+10	区压+1		-@.334383E+1	=-0.275886E+19
O O	(conj/cm ²)	86597E-0	483977E-	Ø • 399310E-9	0.329454E-0	271820	Ø-224267E-A	0.185034E-0	例・152664五-例	0.125957E-0	0.103922E-0	0.857418E-9	0.707420E-6	0.583664E-0	0.481557E-0	0.397314E-6	0.327807E-0	0-270469E-0	0.223146E-0	0.184109E-6	0.151901E-0	0.125327E-0	0.103403E-0	= 0.853131E-64	0.703	0.580	0.4791	•395	•386	S. 200	0.222830E-0	= M • 183188E-M4
o S	(coul/m ²)	·586597E+02	.483977E+02	.399310E+02	•329454E+02	.271820E+02	.284267E+02	·185034E+02	•152664E+02	•125957E+02	• 103922E+02	·857418E+01	•707420E+01	•583664E+M1	•481557E+01	•397314五+91	•327807年+01	.270460E+01	•223146E+01	•1841@9E+@1	•151901E+01	•125327E+Ø1	•103403E+01	•853131E+00	•703883E+00	•580745E+00	7915ØE+00	•395327E+00	.326169E+00	69108E+00	.222031E+00	•183188E+0M
\sells	(volt)	- 1	-0.31	-08.80	-0.79	-0.78	-0.77	-0.76	-0.75	-@ · 74	-0.73	-0.72	-0.71	-0.7@	-Ø-69	-0.68	-Ø-67	99.0-	-0.65	-9.64	-0.63	-M·62	-0.61	-W-69	-0 · 59	-0.58	-9.57	-0.56	-0.55	-U.54	=-0.53 =	-0.58



$E_{\rm S}$ (volt/cm)		·1278415+0	-M·8702445+M	=-0.592395E+07	-M-4887623+M	=-8.483257547 =-6.332711E+07	·2745063+0	84378	•186862五十四	·154172E+9	-@.187801E+@	•104948五十可	-G-865881E+G	ロードログラフローロ	-0.486297E+	17840	5	=-0.8731998+96	=-0.2053195+66	- 4.125342F+		サードのの	=-0.8607018+05	=-0.7094388+45
Es (volt/m)	=-0.227622E+10 =-0.187892E+10 =-0.154948E+10	7841E+1	-M·870244E+0	003E+0	-0-488762E+Ø	=-0.332711E+09	·2745@6E+@	26483E+0	•186862E+例	-0.154172E+0	- 0 - 12720111+0	- 例・1 例49 48 医+例	- 点。865881E+	7143998+2 559416E+Q	-0.486297E+0	Ø1217E+	$\overline{\mathbb{C}}$	=-0.273100E+08	=- G • 925312E+GR	-0.1858898+0			701E+0	=-0.7498388+47
0s (coul/an ²)	222	·848865E-0	0.577842E-0		Ø • 324538E - 0	1000~700回に、1000~2000~2000~2000~2000~2000~2000~2000	Ø • 182272E - 0	0.150385E-0	0.124077E-9	0.102370E-0	0.844615E-0	@ • 696855E-0	0.574945E-0	G - 27 / 436 E - C	• 32 32 32 34 34 34 34 34 34 34 34 34 34 34 34 34	0.266408E-0	0.219797E-0	M.181339E-0	0-149607E-0	G-123426E-0		で の の の で の で で で で で で で で で で で で で	0.5715¤6	= 0.471332E-07
$Q_{\rm s}$ (coul/m ²)	1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	.848865E-01	·577842E-01	• 476754E-Ø1 • 393350E-Ø1	·324538E-01	• 2667763至-01 • 229203日-01	·182272E-01	·150385E-01	•124077E-01	·102370E-01	•844615E-02	•696855E-02	• 574945E-02	•474361E-88	• 3229 8 1 E - 22	.2664M8E-02	-219797E-02	•181339E-02	•149607E-02	• 123426E-02	・ 12 1 次 N 公 元 1 で 2 C C C C C C C C C C C C C C C C C C	• 698887E-98	.571506E-Ø3	71332E-03
V _S (volt)	= -0.51 = = -0.50 = = -0.49 = =	0.48	-0.46	0.45	0.43		0.40	0.39	0.38	0.37	0.36	Ø • 35	Ø • 34	ന ന ന ന		M . 3 M	0.29	€ 000. 000.	M . 27	-9.86			-0.22	



ທ -	(VOIt/cm)	=-0.585322E+05	=-0.482537E+05	=-0.397674E+Ø5	=-Ø.327591E+05	=-0.2696941E+05	=-0.2218435+05	=-0.182270E+05	=-0.1495185+45	=-0.122383E+85	=-0.9987222+64	=-@.811667E+@4	=-@.6559@3E+U4	11-A-525858E+A4	=-0.416942E+44	=-0.3253738+04	=-0.2480418+94	=-4.182392E+04	=-U.126330E+G4	=-9.781380E+#3	=-0.364113E+03	
м ·	(volt/m)	=-0.585322E+07	=-0.482537E+07	=-0.397674E+07	=-0.327591E+07	=-0.269694E+07	=-0.221843E+07	=-0.182270E+07	=-Ø.149518E+G7	=-0.122383E+07	22E+@	67E+0	=-0.6559035+06	=- @ • 525258E+46	=-0.416942E+06	=-A.325373E+A6	=-0.248041E+06	=-0.182392E+06	=-0.126339E+06	=-G.781380E+05	=-0.364113E+05	
	(cont/cm)	= 0.388654E - 07	= M.320404E-07	= 0.264056E-07	= 0.217520E-07	= 0.179077E - 07	= Ø.147303E-07	= 0.121027E-07	= Ø.992797E-08	$= \emptyset.812621E - \emptyset8$	= 0.663151E-08	= Ø.538947E-Ø8	= 0.435529E-08	= 0.349170E-08	= M.275850E-08	= 0.216047E-03	= Ø.164699E-J8	= 0.121108E-08	= 0.838832E-09	= 0.518836E-09	= M.241771E-09	
י מ	(conT/m_)	4E-03	0.320404E-03 :	0.264056E-03 =	0.217520E-03	0.179077E-03	0.1473Ø3E-Ø3	0.121027E-03	7五-同4	12621E-04	3151E-04	.538947E-04	5520E-04	•349170E-04	ロ王-64	0.216047E-94	- (34	0.121108E-04	E-05	Ø.518836E-M5	0.241771E-05	
> .	(volt)	=-0.80 ==		=-0.18 =	=-0 • 17 =	=-0.16 =	=-0 • 15 =	=-0.14 =	=-0.13 =		=-0.11 =	=-0.10 =	= 60.0-=	=-0.08 =	= -0.07 =	= 90.0-=	=-W•05 ==	=-0.04 =	=-0.03 =	=-0.02 =	=-0.01 =	-X



3.2 Theoretical Calculation of the Surface Conductance, $\Delta \sigma$, as the Function of the Surface Potential, V_s .

From equation (68), the theoretical calculations of surface conductance, $\Delta\sigma$, as a function of surface potential V_s were made by numerical integration with small intervals and the results are given in Figures 13, 14 and 15.

The values of parameters of Cu₂O in our calculations are the same as given in section 3.1, with

$$b = \frac{\mu_n}{\mu_p} \simeq 1,$$

$$\mu_p = 1.5 \times 10^{-2} \text{ m}^2/\text{V-sec} = 150 \text{ cm}^2/\text{V-sec.}^{28}$$

The calculations are also made by using the PDP-8E computer and the numerical results are shown in the Tables 5 and 6.



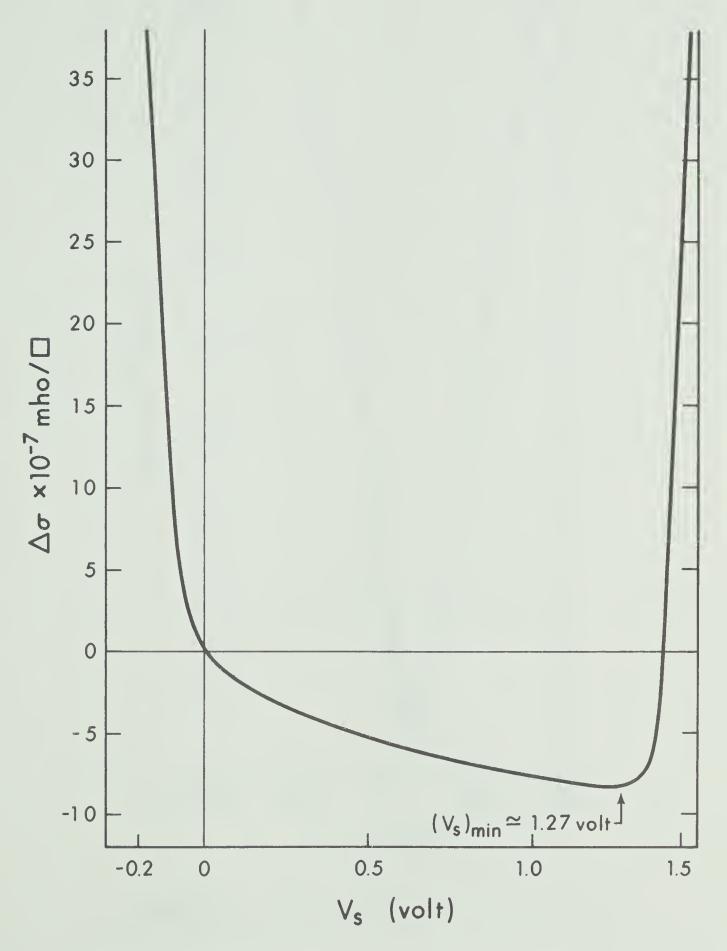


Figure 13. Theoretical curve of $\Delta\sigma$ vs V_s .



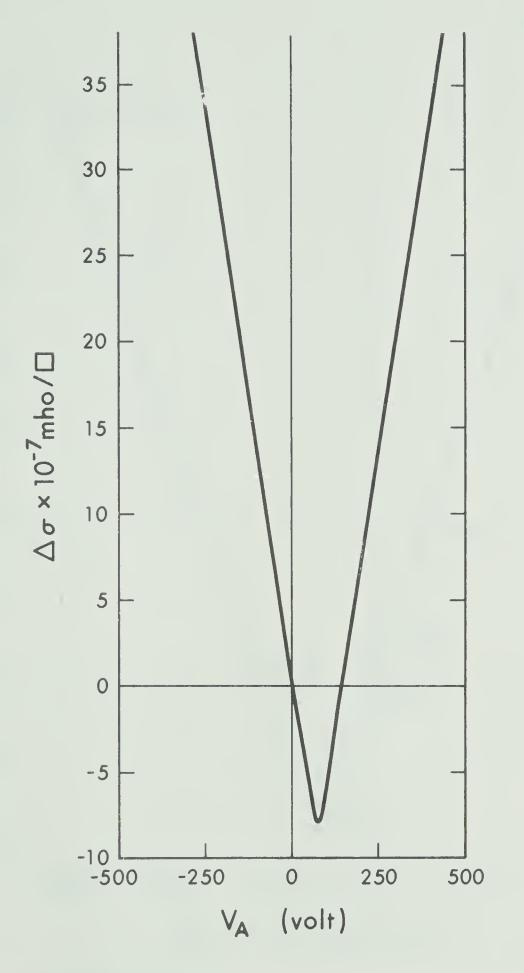


Figure 14. Theoretical curve of $\Delta\sigma$ vs V_A .



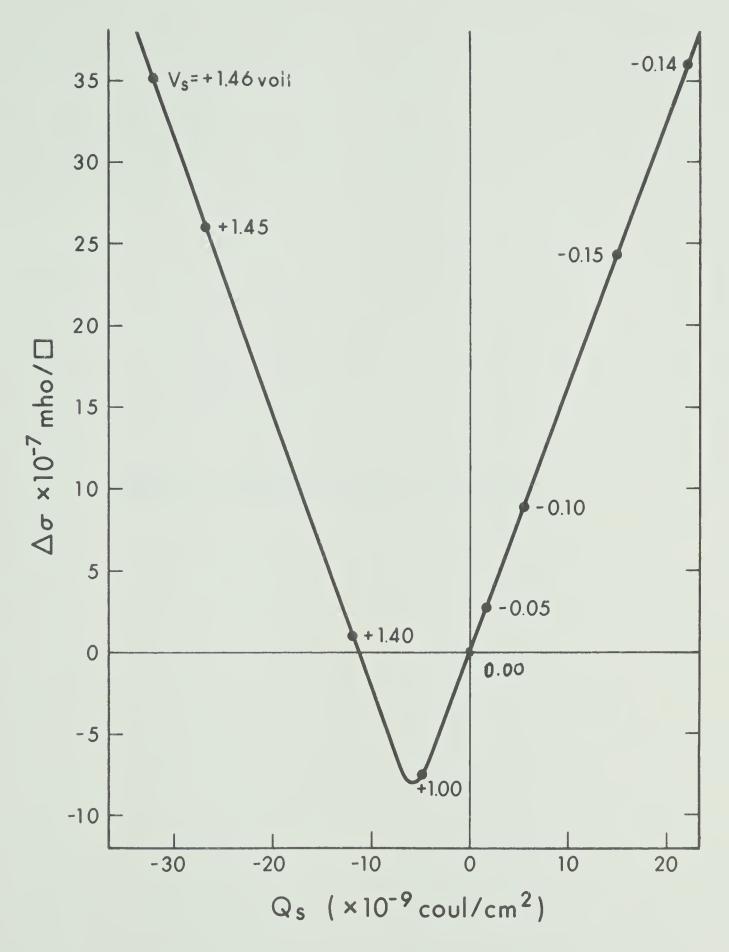


Figure 15. Theoretical curve of $\Delta \sigma$ vs Q_s .



Table 5. Relation between $\Delta \sigma$ and V_s .



C-FOCAL, 1969

```
01.01 SET S=0.00

01.02 FOR I=0.01,0.01,2.00; DO 02.00

01.03 OUIT

02.01 SET A=38.46*I

02.02 SET B=FEXP(A)

02.03 SET C=(1/B-1+5.9E-22*(B-1))/FSOT(1/B+A-1+5.9E-22*(B-A-1))

02.04 SET Y=2.4E-6*0.01*C; SET S=S+Y

02.05 TYPE % 3.02,I," ", %,S*1E7,!

*GO
```

	Vs	Δσ	Δσ
,	(volt)	(mho/□)	$(x 10^{-7} \text{ mho/}\Box)$
=	Ø • Ø 1	=-0.299811E-07	=-0.299811E+00
=	0.08	=-Ø.566857E-Ø7	=-0.566857E+00
=	Ø • Ø3	=-0.806701E-07	=-0.806702E+00
=	Ø • Ø4	=-0.102387E-06	=-0.102387E+01
=	Ø • Ø 5	=-0.122205E-06	=-0.122205E+01
=	0.06	=-0.140425E-06	=-0.140425E+01
=	0.07	=-0.157290E-06	=-0.157290E+01
=	0.08	=-0.173003E-06	=-0.173003E+01
=	0.09	=-0.187727E-06	=-0.187727E+01
=	0 • 1 0	=-0.201597E-06	=-0.201597E+01
=	0 • 1 1	=-0.214726E-06	=-0.214726E+01
=	Ø • 12	=-0.227206E-06	=-0.227207E+01
=	Ø • 13	=-0.239116E-06	=-0.239116E+01
=	0 • 14	=-0.250519E-06	=-0.250519E+01
=	0 • 15	=-0.261471E-06	=-0.261472E+01
=	Ø • 16	=-0.272019E-06	=-0.272019E+01
=	0 • 17	=-0.282201E-06	=-0.282201E+01
	0.18	=-0.292052E-06	=-0.292052E+01
=	0.19	=-0.301602E-06	=-0.301602E+01
=	0.50	=-0.310875E-06	=-0.310875E+01
=	0.21	=-Ø•319893E-Ø6	=-0.319894E+01
=	W • SS	=-0.328678E-06	=-0.328678E+01
=	Ø • 23	=-0.337245E-06	=-0.337245E+01
=	0.24	=-0.345610E-06	=-0.345610E+01
==	0.25	=-0.353786E-06	=-0.353786E+01
=	0.26	=-0.361786E-06	= -0.361786E + 01
=	0.27	=-0.369620E-06	=-0.369620E+01
=	0.28	=-0.377299E-06	=-0.377299E+01
=	0.29	=-0.384830E-06	= -0.384831E+01
=	0.30	=-0.392224E-06	=-0.392224E+01
=	Ø • 31	=-0.399485E-06	=-0.399486E+01
=	0.32	=-0.406623E-06	=-0.406623E+01
=	0.33	=-0.413642E-06	= -0.413642E + 01
=	0.34	=-Ø·420548E-06	= -0.420548E + 01
=	Ø • 35	=-0.427347E-06	= -0.427347E + 01
=	Ø • 36	= -0.434043E - 06	= -0.434043E + 0.1
=	0.37	= -0.440641E - 0.06	= -0.440642E + 01
=	0.38	=-0.447146E-06	=-Ø.447146E+Ø1



	V _s	Δσ		Δσ
((volt)	(mho/o)	(x 10	$7 \text{ mho/}\Box)$
=	0.39	=-0.453560E-06	=-0.453	561E+01
=	(7) • 41 (7)	=-0.459888E-06	=-0.459	889E+01
=	0 • 41	=-0.466133E-06	=-0.466	134E+01
=	0.42	=-0.472299E-06	=-0.472	299E+01
=	0.43	=-Ø•478388E-Ø6	=-0.478	388E+01
=	Ø • 414	=-0.484402E-06	=-0.484	
=	0.45	=-0.490345E-06	=-0.490	
=	0.46	=-0.496220E-06	=-0.496	
=	0 • 47	=-0.502028E-06	=-0.502	
=	M • 48	= -0.507771 E - 06	=-0.507	
=	0.49	=-0.513453E-06	=-0.513	
=	0.50	=-0.519074E-06	=-0.519	
=	Ø • 51	=-0.524637E-06	=-0.524	
=	Ø • 52	=-0.530143E-06	=-0.530	
=	Ø • 53	=-0.535594E-06	=-0.535	
=	Ø • 54 Ø • 55	=-0.540992E-06	=-0.540° =-0.546	
=	0.56	=-0.546338E-06 =-0.551634E-06	= -0.540 = -0.551	
=	Ø • 57	=-0.556881E-06	= -0.551	
=	0.58	=-0.562081E-06	= -0.562	
=	0.59	=-0.567234E-06	= -0.567	
=	0.60	= -0.572342E - 0.0000000000000000000000000000000000	= -0.572	
=	0.61	= -0.572342.E %6	= -0.572	
=	Ø • 62	=-0.582428E-06	=-0.582	
=	0.63	=-0.587407E-06	= -0 . 587	
=	0.64	=-0.592346E-06	=-0.592	
=	0.65	=-0.597245E-06	=-0.597	
=	0.66	=-0.602105E-06	=-0.602	
=	M • 67	=-0.606928E-06	=-0.606	
=	Ø • 68	=-0.611713E-06	=-0.611	714E+01
=	0.69	=-0.616463E-06	=-0.616	463E+Ø1
=	0.70	=-0.621176E-06	=-0.621	177E+01
=	0.71	=-0.625856E-06	=-0.625	856E+01
=	0.72	=-0.630501E-06	=-0.630	502E+01
=	Ø • 73	=-0.635114E-06	=-0.635	114E+01
=	M • 74	=-0.639693E-06	=-0.639	694E+01
=	Ø • 75	=-0.644242E-06	= - (1) • 6 4 4	242E+01
=	0.76	=-0.648759E-06	=-0.648	
=	0.77	=-Ø·653246E-Ø6	=-0.653	
=	Ø • 78	=-0.657702E-06	= -0 .657	
=	0.79	=-Ø.66213ØE-Ø6	=-0.662	
=	0.80	=-Ø.666529E-Ø6	=-0.666	
=	Ø • 81	=-0.670900E-06	=-0.670	
=	0.82	=-0.675243E-06	= -0.675	
=	Ø • 83	=-0.679559E-06	=-0.679	
=	0.84	=-0.683848E-06	=-0.683	
=	Ø 85	=-0.688112E-06	=-0.688 =-0.692	
=	Ø • 86	=-0.692349E-06 =-0.696562E-06	==0.698	
=	Ø · 87	W • 030208E-M0	(/ • /) 7 ()	JOC.15701



Vs Δσ Δσ (volt) (mho/o) (x 10 ⁻⁷ mho = 0.88 = -0.704750E-46 = -0.704750E = 0.89 = -0.744913E-66 = -0.744913E = 0.90 = -0.749952E-66 = -0.709452E = 0.91 = -0.717962E-66 = -0.717962E = 0.92 = -0.717962E-66 = -0.717962E = 0.93 = -0.721332E-66 = -0.721332E = 0.94 = -0.723380E-66 = -0.721332E = 0.95 = -0.729466E-66 = -0.729346E = 0.95 = -0.729466E-66 = -0.72946E = 0.96 = -0.733414E-66 = -0.73341E = 0.97 = -0.737393E-66 = -0.73341E = 0.98 = -0.741356E-66 = -0.741356E = 0.99 = -0.741356E-66 = -0.741356E = 0.99 = -0.745297E-06 = -0.74529KE = 1.00 = -0.757601E-66 = -0.757961E = 1.01 = -0.757601E-66 = -0.757961E = 1.03 = -0.76476E-06 = -0.76476KE = 1.04 = -0.768529E-06	
= 0.89)/0)
= 0.90 = -0.709052E-06 = -0.709053E = 0.91 = -0.713169E-06 = -0.71216 E = 0.93 = -0.717262E-06 = -0.72132EE = 0.93 = -0.725380E-06 = -0.725380E = 0.94 = -0.725380E-06 = -0.725380E = 0.95 = -0.729066E-06 = -0.729066E = 0.95 = -0.733417E-06 = -0.733411E = 0.97 = -0.737393E-06 = -0.741356E = 0.97 = -0.741356E-06 = -0.741356E = 0.99 = -0.741356E-06 = -0.745298E = 0.99 = -0.745297E-06 = -0.745298E = 1.00 = -0.757001E-06 = -0.757001E = 1.00 = -0.757001E-06 = -0.757001E = 1.00 = -0.7568529E-06 = -0.768530E = -0.768530E = 1.00 = -0.768529E-06 = -0.768530E = -0.768530E = 1.00 = -0.776334E-06 = -0.776334E = 1.00 = -0.776334E-06 = -0.776334E = 1.00 = -0.776334E-06 = -0.776334E = -0.776334E-06 = -0.776336E-06 = -0.776336E-06 = -0.776336E-06 = -0.7763362E-06 = -0.7763636E-06 = -0.7763362E-06 = -0.787365E-06	+151
= 0.91	+91
= 0.93 = -0.717962E-06 = -9.717262E = 0.93 = -0.721332E-06 = -0.721332E = 0.94 = -0.725380E-06 = -0.725380E = 0.95 = -0.729466E-06 = -0.729466E = 0.96 = -0.733417E-06 = -0.733411E = 0.97 = -0.741356E-06 = -0.741356E = 0.98 = -0.741356E-06 = -0.745298E = 0.99 = -0.745297E-06 = -0.745298E = 1.00 = -0.749218E-06 = -0.749219E = 1.01 = -0.75312ME-06 = -0.757001E = 1.02 = -0.757001E-06 = -0.757001E = 1.03 = -0.764706E-06 = -0.764706E = 1.05 = -0.764706E-06 = -0.764706E = 1.06 = -0.772334E-06 = -0.776324E = 1.07 = -0.779887E-06 = -0.779887E = 1.09 = -0.783635E-06 = -0.783636E = 1.09 = -0.783635E-06 = -0.783636E = 1.09 = -0.783635E-06 = -0.783636E	+ (1)
= 0.93	+(1)
= 0.94	+011
= 0.95	+141
= 0.96	+/11
= 0.97	+ 13.1
= 0.98	+01
= 0.99	+ (4.1
= 1.00 = -0.749218E-06 = -0.749219E = 1.01 = -0.75312ME-06 = -0.753120E = 1.02 = -0.757001E-06 = -0.757001E = 1.03 = -0.760863E-06 = -0.760363E = 1.04 = -0.764706E-06 = -0.764706E = 1.05 = -0.768529E-06 = -0.768530E = 1.06 = -0.772334E-06 = -0.772334E = 1.07 = -0.776120E-06 = -0.776120E = 1.09 = -0.783635E-06 = -0.783636E = 1.09 = -0.783635E-06 = -0.787365E	F 01 1
= 1.01	+ 0 1
= 1.02 = -0.757001E-06 = -0.757001E = 1.03 = -0.760863E-06 = -0.760363E = 1.04 = -0.764706E-06 = -0.764706E = 1.05 = -0.768529E-06 = -0.768530E = 1.06 = -0.772334E-06 = -0.772334E = 1.07 = -0.776120E-06 = -0.776120E = 1.08 = -0.779887E-06 = -0.779887E = 1.09 = -0.783635E-06 = -0.787365E	
= 1.03	
= 1.04 = -0.764706E-06 = -0.764706E = 1.05 = -0.768589E-06 = -0.768530E = 1.06 = -0.778334E-06 = -0.778334E = 1.07 = -0.776180E-06 = -0.776120E = 1.08 = -0.779887E-06 = -0.779887E = 1.09 = -0.783635E-06 = -0.783636E = 1.10 = -0.787364E-06 = -0.787365E	
= 1.05 = -0.768589E-06 = -0.768530E = 1.06 = -0.778334E-06 = -0.778334E = 1.07 = -0.776180E-06 = -0.776180E = 1.08 = -0.779887E-06 = -0.779887E = 1.09 = -0.783635E-06 = -0.783636E = 1.10 = -0.787364E-06 = -0.787365E	
= 1.06 = -0.772334E-06 = -0.772334E = 1.07 = -0.776120E-06 = -0.776120E = 1.08 = -0.779887E-06 = -0.779887E = 1.09 = -0.783635E-06 = -0.783636E = 1.10 = -0.787364E-06 = -0.787365E	
= 1.07 ==0.776120E-06 ==0.776120E = 1.08 ==0.779887E-06 ==0.779887E = 1.09 ==0.783635E-06 ==0.787362E = 1.10 ==0.787364E-06 ==0.787365E	
= 1.08 = -0.779887E - 06 = -0.779887E = 1.09 = -0.783635E - 06 = -0.783636E = 1.10 = -0.787364E - 06 = -0.787365E	
= 1.09 =-0.783635E-06 =-0.783626E = 1.10 =-0.787364E-06 =-0.787365E	
$= 1 \cdot 10 \qquad = -0.787364 \text{ m} - 06 \qquad = -0.787365 \text{ m}$	
= 1.11 = -0.791074E - 06 = -0.701074E	
= 1.12 = -0.794763 E - 06 = -0.794763 E	
= 1.13 $= -0.798429E-66$ $= -0.708439E$	
= 1.14 $= -0.802072H-06$ $= -0.802072H$	
= 1.15 =-0.805687E-06 =-0.805688E = 1.16 =-0.809270E-06 =-0.809270E	
= 1.17 $= -0.812813E-06$ $= -0.812813E= 1.18$ $= -0.816305E-06$ $= -0.816306E$	
= 1.19 $= -0.819731E-06$ $= -0.819732E$	
= 1.20 $= -0.823068E-06$ $= -0.823968E$	
= 1.21 $= -0.826289E-06$ $= -0.826281E$	
= 1.82 $= -0.829319E-46$ $= -0.829319E$	
= 1.23 $= -0.832110E-06$ $= -0.832111E$	
= 1.84 $= -0.834548$ $= -0.33454$ $= -0.33454$	_
= 1.85 $= -0.836476$ E-66 $= -0.836476$ E	
= 1 · 86 = -0 · 837668E - 96 = -0 · 837668E	
= 1.87 =-9.837795E-06 =-0.837796E	
= 1.88 =-0.836383E-06 =-0.836384E	
= 1.89 =-0.838750E-06 =-0.838750E	
= 1.3M =-M.885981E-M6 =-M.885988E	
= 1.31 =-0.814527E-06 =-0.814520E	
= 1.32 =-0.796663E-06 =-0.796663E	+ 1
= 1.33 $= -0.769738$ E-06 $= -0.769739$ E	F ()]
= 1.34 =-0.730320E-06 =-0.730320E	+01
= 1.35 =-M.674MM2E-M6 =-M.674MM2E	+41
= 1.36 =-0.595338E-M6 =-0.595338E	+01



```
ys
                      Δq
                                          (x 10^{-7} \text{ mho/o})
 (volt)
                    (mho/\Box)
= 1.37
               =-0.487808E-06
                                        = -0.487808E + 01
  1.38
               =-0.343909E-06
                                        =-0.343910瓩+01
  1.39
               =-0.155099E-06
                                        = -0.155099E + 01
  1.40
                  ؕ882964E-07
                                           0.882964E+00
=
  1 • 41
                  Ø.39737ØE-Ø6
                                           Ø.39737ØE+01
  1.42
                  0.785080E-06
                                           0.785081E+01
  1.43
                                           の・126684E+02
                  0.126684E-05
  1.44
                  0.186119E-05
                                           0.186119E+02
=
                                           Ø.259Ø63E+Ø2
  1.45
                  0.259063E-05
=
  1.46
                  0.348250E-05
                                           ؕ34825ØE+Ø2
  1.47
                  0.457006E-05
                                           0.457006E+02
  1.48
                                           0.589377E+02
=
                  Ø • 589376E - Ø 5
                  0.750281E-05
                                           0.750281E+02
  1.49
=
  1.50
                  0.945691E-05
                                           0.945691E+02
=
               =
                                        =
  1.51
                  Ø • 118286E - Ø4
                                           0.118286E+03
=
               =
                                        =
==
  1.52
                  0.147059E-04
                                           0.147059E+03
               =
=
  1.53
               ___
                  Ø • 181955E - Ø4
                                           Ø • 181955E+Ø3
=
  1.54
                  0.224269E-04
                                           Ø • 224269E+03
                                           Ø.275571E+03
  1.55
               ==
                  0.275571E-04
                                           の・337763五+03
  1.56
                  Ø • 337763E - 04
                                           0.413153E+03
  1.57
                  0.413153E-04
                  0.504538E-04
                                           ؕ5Ø4538E+Ø3
  1.58
                                           0.615306E+03
  1.59
                  0.615306E-04
  1.60
                  0.749567E-04
                                           ؕ749567E+Ø3
=
                                           0.912301E+03
  1.61
                  Ø • 9 12301E - 04
=
                  0.110954E-03
                                           0 • 1 1 0 9 5 4 E + 0 4
=
  1.62
                                           0 • 134861月+04
  1.63
                  0.134861E-03
                                           Ø • 163838E+04
  1.64
                  0 • 163838E - 03
  1.65
                                           0.198958E+04
                  Ø.198958E-Ø3
  1.66
                  0.241525E-03
                                           0.241525E+04
                                        =
=
                                           Ø • 293119E+Ø4
=
  1.67
                  0.293119E-03
                                        ---
                  0.355651E-03
                                           の・355651 国+の4
=
  1.68
=
  1.69
                  Ø • 431443E = Ø3
                                           Ø • 431443E+Ø4
  1.70
                  0.523306E-03
                                        =
                                           M•5233M6E+04
=
               =
                                           Ø • 634647E+04
  1.71
                  0.634647E-03
=
                  Ø • 769595E - Ø3
                                           Ø·769595用+Ø4
=
  1.72
  1.73
                  0.933157E-03
                                           ؕ933157E+Ø4
  1.74
                  0.113140E-02
                                           0.113140E+05
=
  1.75
                  Ø.137168E-Ø2
                                           Ø • 137168E+Ø5
  1.76
                  0.166291E-02
                                           ؕ166291E+Ø5
                  0.201588E-02
                                           0.201588E±05
=
  1.77
                                           0.244370E+05
  1.78
                  0.244370E-02
=
                                           M.296222E+05
                  0.296222E-02
  1.79
                                        =
==
  1.80
                  0.359069E-02
                                           Ø·359079E+05
=
                  0.435242E-02
                                        =
                                           Ø・435242E+Ø5
  1.81
=
=
  1.82
                  ؕ527567E-Ø2
                                           Ø • 527567E+05
                                           ؕ639468E+Ø5
  1.83
                  0.639468E-02
\equiv
                  Ø.775095E-02
                                           ؕ775095E+05
=
  1.84
                  0.939479E-02
  1.85
                                           0.939479E+95
```



	Vs		Δσ			vQ
,	(volt)		(mho/\Box)		$(x 10^{-7})$	mho/o)
=	= 1.86	-	0.113872E-01	==	0.1138	72E+06
:	= 1.87	=	0.138020E-01	=	Ø • 1380	12ME+96
	= 1.88		0.167289E-01	=	M.1672	89E+06
:	= 1 • 89	=	0.202764E-01	=	0.2027	64E+06
:	= 1.90		0.245760E-01		0.2457	60E+06
:	= 1.91		0.297874E-01	=	0.2978	74E+06
:	= 1.92	****	0.361038E-01	=	0.3610	37E+06
:	= 1.93	=	0.437594E-01	==	Ø • 4375	94E+96
:	= 1.94	==	0.530382E-01	=	0.5303	182E+06
:	= 1.95	=	0.642845E-01	==	0.6428	445+06
	= 1.96	=	0.779153E-01	#**** ****	9.7791	53E+06
:	= 1.97	energ desid	0.944363E-01	=	0.9443	63E+96
	= 1.98	-	0.114460E+00	games arrow	6.1144	605+07
;	= 1.99	=	0.138730E+00	=	0.1387	30五+67
	= 2.00	=	0.168146E+00		0.1681	463+07
	;					



Table 6. Relation between $\Delta\sigma$ and V_s .



C-FUCAL, 1969

```
M1.01 SET S=0.00

M1.02 FOR I=0.01,0.01,1.00; DU 02.00

01.03 OUIT

M2.01 SET A=-38.46*I

M2.02 SET R=FEXP(A)

M2.03 SET C=(1/B-1+5.9E-22*(B-1))/FSOT(1/B+A-1+5.9E-22*(B-4-4-1))

M2.04 SET Y=2.4E-6*0.01*C; SET S=S+Y

M2.05 TYPE % 3.02,-I," ", %,S," ", %,S*1E7,!

*GO
```

(volt) (mho/n) (x 10 ⁻⁷ mho/n) =-0.01 = 0.387408E+07 = 0.387408E+08 =-0.02 = 0.833115E-07 = 0.233115E+00 =-0.03 = 0.134974E-06 = 0.134974E+01 =-0.04 = 0.195274E-06 = 0.195274E+01 =-0.05 = 0.266097E-06 = 0.266097E+01 =-0.06 = 0.349745E-06 = 0.406097E+01 =-0.07 = 0.449022E-06 = 0.709826E+01 =-0.08 = 0.567338E-06 = 0.567338E+01 =-0.09 = 0.708836E-06 = 0.709836E+01 =-0.09 = 0.708836E-06 = 0.708836E+01 =-0.10 = 0.878548E-06 = 0.709836E+01 =-0.11 = 0.18825E-05 = 0.19828E+02 =-0.12 = 0.132832E+02 = 0.11 =-0.13 = 0.162476E-05 = 0.162476E+02 =-0.13 = 0.162476E-05 = 0.162476E+02 =-0.14 = 0.198275E-05 = 0.142454E+02 =-0.15 = 0.293890E-05 = 0.293890E+02 =-0.17 = 0.3526805E-05 = 0.433927E+02 =-0.	Vs	Δσ	Δσ
=-0.00	·-	(mho/\Box)	$(x 10^{-7} \text{ mho/o})$
=-0.002	=-0.01	= 0.387408E-07	= 0.387408E+00
=-0.03	=-0.05	= 0.833115E-07	
=-0.05	=-0.03	= 0.134974E-06	= 0.134974E+01
=-0.06	=-0.64	= 0.195274E-06	= 0.195274E+01
=-0.07	=-0.05	= 0.266097E-06	= 0.266097E+01
=-0.08	=-0.06	= 0.349745E-06	= 0.349745E+01
=-0.09	=-0.07	= 0.449022E-06	= 0.44992E+91
=-0.10	=-0.08	= 0.567338E-06	= Ø·567338E+Ø1
=-0.11	=-0.09	= 0.708836E-06	= 0.708836E+01
=-0.12	= - (1) • 1 (3)	= 0.878548E-06	= M.8/8549F+M1
=-0.13	=-0 • 1 1	= 0.108258E-05	= M.108258E+32
=-0.14	=-0.12	= 0.132832E-05	= M.132832E+02
=-0.15	=-0.13	= 0.162476E-05	= 0.1624768+02
=-0.16	=-0.14	= 0.198275E-05	= (1·198275H+M2
=-0.17	=-0.15	= 0.241548E - 05	= 0.841548E+02
=-0.18 = 0.433927E-05 = 0.433927E+02 =-0.19 = 0.526805E-05 = 0.526805E+02 =-0.20 = 0.639310E-05 = 0.639310E+02 =-0.21 = 0.775611E-05 = 0.940761E+02 =-0.22 = 0.940761E-05 = 0.940761E+02 =-0.23 = 0.114088E+04 = 0.114088E+03 =-0.25 = 0.157730E-04 = 0.138340E+03 =-0.25 = 0.2661E-04 = 0.203349E+03 =-0.27 = 0.246518E-04 = 0.203349E+03 =-0.28 = 0.246518E-04 = 0.298839E+03 =-0.29 = 0.362250E-04 = 0.298839E+03 =-0.30 = 0.439106E+04 = 0.532256E+03 =-0.31 = 0.532256E-04 = 0.532256E+03 =-0.32 = 0.645156E-04 = 0.645156E+03 =-0.33 = 0.781994E+03 =-0.34 = 0.947845E+03	=-0.16	= 0.293890E-05	= 0.293890H+02
=-0.19	=-0.17	= 0.357235E-05	= M.357235E+M2
=-0.20 = 0.639310E-05 = 0.639310E+02 =-0.21 = 0.775611E-05 = 0.940761E+02 =-0.22 = 0.940761E-05 = 0.940761E+02 =-0.23 = 0.114088E-04 = 0.114088E+03 =-0.25 = 0.167730E-04 = 0.138340E+03 =-0.25 = 0.203349E-04 = 0.203349E+03 =-0.26 = 0.203349E-04 = 0.203349E+03 =-0.27 = 0.246518E-04 = 0.208839E+03 =-0.28 = 0.298839E-04 = 0.298839E+03 =-0.29 = 0.368250E-04 = 0.362250E+03 =-0.30 = 0.439106E+04 = 0.532256E+03 =-0.31 = 0.532256E-04 = 0.645156E+03 =-0.31 = 0.645156E-04 = 0.645156E+03 =-0.32 = 0.781994E-04 = 0.781994E+03 =-0.34 = 0.947845E+03	=-0.18	= 0.433927E-05	= 0.433927E+02
=-0.21	=-0.19	= 0.526805E-05	= M•5268Ø5E+Ø2
=-0.28	=-0.50	= 0.639310E-05	= 0.639314E+62
=-0.23	=-0.21	= 0.775611E-05	= 0.775611E+02
=-0.24	=-4.55	= 0.940761E-05	= 0.940761E+92
=-0.25	=-0.23	= 0 • 1 1 4 (8 8 E + 0 4	= M.114M88E+M3
=-0.26 = 0.203349E-04 = 0.203349E+03 =-0.27 = 0.246518E-04 = 0.246518E+03 =-0.28 = 0.298839E-04 = 0.298839E+03 =-0.29 = 0.368250E-04 = 0.368250E+03 =-0.30 = 0.439105E-04 = 0.439106E+03 =-0.31 = 0.538256E-04 = 0.538256E+03 =-0.32 = 0.645156E-04 = 0.645156E+03 =-0.33 = 0.781994E-04 = 0.781994E+03 =-0.34 = 0.947845E-04 = 0.947845E+03	=-0.84	= Ø.138340E-04	= 0.138340£+d3
=-0.27 = 0.246518E-04 = 0.246518E+03 =-0.28 = 0.298839E-04 = 0.298839E+03 =-0.29 = 0.362250E-04 = 0.362250E+03 =-0.30 = 0.439106E-04 = 0.439106E+03 =-0.31 = 0.532256E-04 = 0.532256E+03 =-0.32 = 0.645156E-04 = 0.645156E+03 =-0.33 = 0.781994E-04 = 0.781994E+03 =-0.34 = 0.947845E-04 = 0.947845E+03	=-0.25	= 0.167730E-04	= M • 16773MH+M3
=-0.28 = 0.298839E-04 = 0.298839E+03 =-0.29 = 0.362250E-04 = 0.362250E+03 =-0.30 = 0.439106E-04 = 0.439106E+03 =-0.31 = 0.532256E+04 = 0.532256E+03 =-0.32 = 0.645156E-04 = 0.645156E+03 =-0.33 = 0.781994E-04 = 0.781994E+03 =-0.34 = 0.947845E-04 = 0.947845E+03	=-9.26	= 0.203349E-04	= 0.203349E+03
=-0.89 = 0.362250E-04 = 0.362250E+03 =-0.30 = 0.439106E-04 = 0.439106E+03 =-0.31 = 0.532256E-04 = 0.532256E+03 =-0.32 = 0.645156E-04 = 0.645156E+03 =-0.33 = 0.781994E-04 = 0.781994E+03 =-0.34 = 0.947845E-04 = 0.947845E+03	=-0.51	= Ø.246518E-Ø4	= Ø•246518E+Ø3
$\begin{array}{lll} = -0.30 & = 0.439106E - 0.4 & = 0.439106E + 0.3 \\ = -0.31 & = 0.532256E - 0.4 & = 0.532256E + 0.3 \\ = -0.32 & = 0.645156E - 0.4 & = 0.645156E + 0.3 \\ = -0.33 & = 0.781994E - 0.4 & = 0.781994E + 0.3 \\ = -0.34 & = 0.947845E - 0.4 & = 0.947845E + 0.3 \end{array}$	=-0.28	= 0.298839E-04	= 0.298839E+03
=-0.31 = 0.532256E-04 = 0.532256E+03 =-0.32 = 0.645156E-04 = 0.645156E+03 =-0.33 = 0.781994E-04 = 0.781994E+03 =-0.34 = 0.947845E-04 = 0.947845E+03	=-0.29	= 0.36225ME-04	= Ø • 362259E+93
$\begin{array}{lll} = -0.32 & = 0.645156E - 04 & = 0.645156E + 03 \\ = -0.33 & = 0.781994E - 04 & = 0.781994E + 03 \\ = -0.34 & = 0.947845E - 04 & = 0.947845E + 03 \end{array}$	=-0.30	= 0.439105E-04	= 0.439106E+03
= -0.33 = 0.781994E - 0.4 = 0.781994E + 0.3 = 0.947845E - 0.4 = 0.947845E + 0.3	=-0.31	= 0.532256E-04	= 0.5388568+03
=-0.34 = $0.947845E-04$ = $0.947845E+03$	=-0.32	= 0.645156E - 04	= 0.645156E+03
	=-0.33	= 0.781994E - 04	= M.781994E+M3
=-0.35 $= 0.114886E-03$ $= 0.114886E+04$	=-0.34	= 0.947845E - 04	= 0.9478458+03
	=-0.35	= Ø • 114886E - 03	= 0 • 11/4886E+64
=-0.36 $= 0.139250E-03$ $= 0.139250E+04$	=-0.36	= 0.139250E-03	= 0.139250E+04
=-0.37 $= 0.168780E-03$ $= 0.168780E+04$	=-0.37	= 0.168780E-03	= 0.1687809+04
=-0.38 = $0.204570E-03$ = $0.204570E+04$	=-0.38	= 0.204570E-03	= 0.2045/08+04



Vs	Δσ	Δσ
(volt)	(mho/o)	$(\times 10^{-7} \text{ mho/o})$
=-0.39	= Ø.84795ØR-03	= 0.247950F+04
=-0.40	= 0.3M0528E-03	= 0.300528E+04
=-0.41	= 9.364254E - 03	= 0.364254E+04
=-0.42	= 0.441491E-03	= 0.441491E+04
=-0.43	= 0.535106E-03	= 0.535106E+04
=-0.44	= Ø.648579E-03	= 0.648571E+04
=-0.45	= 0.786093E-03	= 0.786A93E+A4
=-0.46	= 0.958775E-03	= Ø.952775E+Ø4
=-0 • 47	= 0.115480E-02	= Ø•115480E+Ø5
=-0.48	= 0.139966E-02	= 0.139966E+05
=-0.49	= 0.169644E-02	= 0.169644E + 05
=-0.50	= 0.205614E-02	= 0.205615E+05
=-0.51	= 0.249212E-02	= 0.249212E+05
=-0.52	= 0.302054E-02	= 0.302054E+05
=-0.53	= 0.366100E-02	= 0.366100E+05
=-0.54	= 0.443726E-02	= 0.443726E+Ø5
=-0.55	= 0.537811E-02	= 0.537811E+05
=-0.56	= 0.651845E-02	= 0.651845E+05
=-0.57	= 0.790058E-02	= 0.790059E+05
=-0.58	= 0.957578E-02	= 0.957578E+05
=-4.59	= 0.116062E-01	= 0.116062E+06
=-0.60	= 0.140671E-01	= 0.140671E+06
=-9.61	= 0.170498E-01	= Ø • 17Ø498E+Ø6
=-0.62	= 0.206649E-01	= 0.206649E+06
=-0.63	= 0.250466E-01	= 0.250466E+06
=-0.64	= 0.303573E-01	= 0.303573E+06
=-0.65	= M.36794ØE-Ø1	= 0.3679418+96
=-0.66	= 0.445956E-01	= 9.445956F + 96
=-0.67	= 0.540514E-01	= 0.5405145+96
=-0.68	= 0.655121E-01	= 0.655121E+06
=-0.69	= 0.794029E-01	= 0.794029E+06
=-0.70	= 0.962391E-01	= 0.968391E+06
=-0.71	= 0 • 116645E+00	= 0.116645E+07
=-0.72	= 0.141378E+00	= 0.141378E+07
=-0.73	= Ø • 171355E+@@	= 0.171355E + 07
=-0.74	= 0.207687E+00	= 0.207687E+07
=-0.75	= 0.251724E + 00	= 0.251724E+07
=-0.76	= 0.305098E+00	= 0.305098E+07
=-0.77	= Ø.369789E+ØØ	= 0.369789E+07
=-0.78	= 0.448197E + 00	= 0.448197E+07
=-0.79	= Ø.54323ØE+ØØ	= 0.543230E+07
=-0.80	= Ø•658414E+ØØ	= 0.658414E + 07
=-0.81	= 0.798020E+00	= 0.798020E+07
=-0.82	= Ø•967227E+ØØ	= 0.967227E+07
=-0.83	$= \emptyset \cdot 117231E+\emptyset 1$	= 0.117231E+08
=-0.84	= 0.142088E+01	= 0.14208XE+08
=-0.85	= Ø • 172216E+Ø1	= 0.172216E+08
=-0.86	= 0.208731E+01	= 0.208731F+04
=-0.87	= 0.252989E+01	= 0.2529898+08



Vs		Δσ			7α
(volt)		(mho/D)		(x 10	7 mho/ $_{\square}$)
=-0.88	=	Ø.306632E+01	=	M.3066	32E+08
=-0.89	=	0.371648E+01	=	M.3716	48E+03
=-0.90	=	0.450449E+01	=	0.4504	49E+08
=-0.91	=	Ø • 54596ØE+Ø1	=	0.5459	50E+08
=-0.92	=	0.661722E+01	=	0.6617	22E+08
=-0.93	=	0.802029E+01	=	0.8020	29E+08
=-0.94	=	Ø•972086E+Ø1	=	0.97208	R6E+08
=-0.95	=	0.117820E+02	=	0.1178	20E+09
=-0.96	=	Ø • 1428Ø2E+Ø2	=	M.1428	72E+09
=-0.97	=	Ø • 173081E+02	=	0.1730	81E+09
=-0.98	=	0.209780E+02	==	0.2097	80E+09
=-0.99	=	0.254260E+02	=	0.2542	60E+09
=-1 • Ø Ø	=	0.308172E+02	=	0.3081	72E+09
sle.					



3.3 Determination of the Value of the Surface Potential, \underline{V}_{sm} , which Gives the Minimum Value of Surface Conductance, $\Delta \sigma_{min}$

By differentiating equation (68), we obtain

$$\frac{d\Delta\sigma}{dV} = \left(\frac{q}{kT}\right) \left(\frac{\varepsilon_{o}\varepsilon_{s}kT}{2}p_{o}\right)^{\frac{1}{2}} \mu_{p} \frac{\left[e^{-\beta V} - 1 + \left(\frac{n_{o}}{p_{o}}\right)b\left(e^{\beta V} - 1\right)\right]}{\left[e^{-\beta V} + \beta V - 1 + \frac{n_{o}}{p_{o}}\left(e^{\beta V} - \beta V - 1\right)\right]^{\frac{1}{2}}}$$

To determine $V_{\rm sm}$, one sets $\frac{{\rm d}\Delta\sigma}{{\rm d}V}=0$, and then solves for the value of V which now becomes $V_{\rm sm}$. In practice, we calculate the values of $\frac{{\rm d}\Delta\sigma}{{\rm d}V}$ as the function of V and then plot $\frac{{\rm d}\Delta\sigma}{{\rm d}V}$ vs V, and from the graph we can find the value of V $(V_{\rm sm})$ which gives $\frac{{\rm d}\Delta\sigma}{{\rm d}V}=0$. The results are given in Figure 16 and in the Tables 7 and 8.





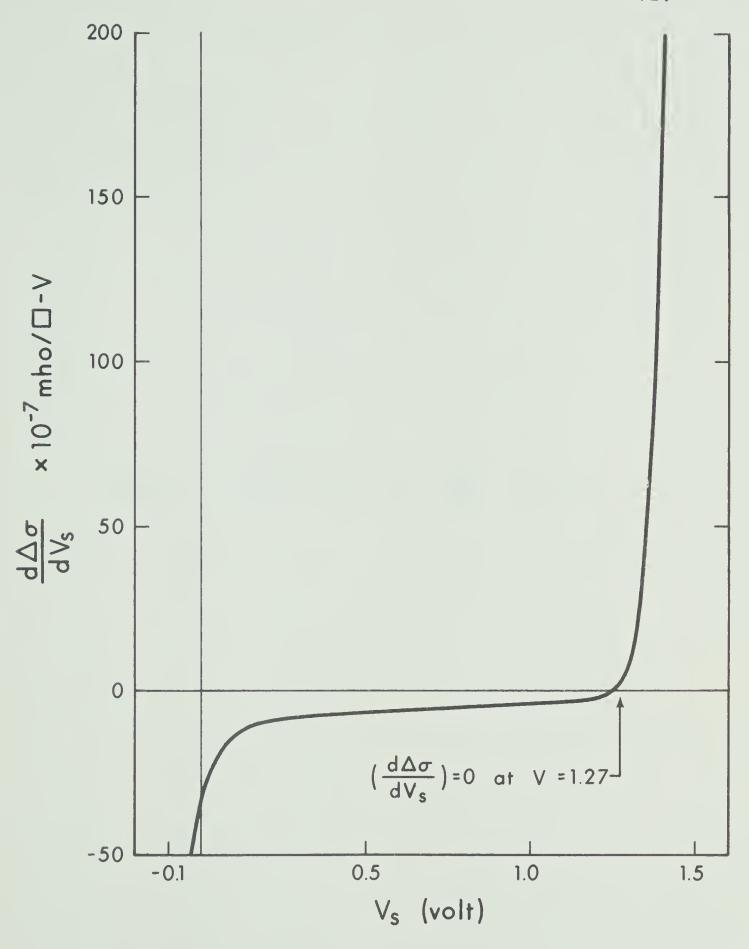


Figure 16. Theoretical curve of $\frac{d\Delta\sigma}{dV_s}$ vs V_s .



Table 7. Relation between $\frac{d\Delta\sigma}{dV_s}$ and V_s .



C-FOCAL, 1969

01.01 FOR V=0.01,0.01,2.00; DO 02.00 01.02 OUIT 02.01 SET A=38.46*V 02.02 SET B=FEXP(A) 02.03 SET C=(1/B-1+5.9E-22*(B-1))/FSOT(1/B+A-1+5.9E-22*(B-A-1)) 02.04 SET Y=2.4E-6*C 02.05 TYPE % 3.02,V," ", %,Y," ", %,Y*1E7,! *GO

 $d\Delta\sigma/dV_s$ $d\Delta\sigma/dV_{s}$ $(x 10^{-7} \text{ mho/}\Box - V)$ (volt) $(mho/\Box-V)$ =-0.299811E-05 = 0.01 =-0.299811E+02= 0.02=-0.267046E-05 =-0.267046E+02 $= \emptyset \cdot \emptyset 3$ =-0.239844E-05 =-0.239845E+02 0.04 = -0.217170E - 05= -0.217170E + 020.05 = -0.198180E - 05=-0.198181E+02 0.06 = -0.182193E - 05=-0.182193E+02 $= \emptyset \cdot \emptyset 7$ =-0.168657E-05 =-0.168657E+02 0.08 = -0.157125E - 05=-0.157125E+02 =-0.147238E+02= 0.09= -0.147238E - 050.10 =-0.138704E-05= -0.138705E + 02 $= \emptyset \cdot 11$ = -0.131290E - 05= -0.131290E + 02= 0.12= -0.124804E - 05=-0.124805E+02 = 0.13= -0.119094E - 05= -0.119094E+02= (0.14)= -0.114033E - 05=-0.114034E+02=-0.109521E+02 $= 0 \cdot 15$ = -0.109521E - 05= -0.105473E - 05=-0.105473E+02 0.16 -0.17= -0.101822E + 02=-0.101822E-05 = 0.18 =-0.985108E-06 = -0.935108E+01=-0.954930E-06 = 0.19= -0.954931E+010.20 =-0.927300E-06 = -0.927300E + 010.21 =-0.991892E+01 = -0.901892E - 060.22 =-0.878434E-06 = -0.878434E+01=-0.856695E+01 = 0.23=-0.856695E-06 =-0.836481E+01 0.24 = -0.836480E - 06=-0.817623E-06=-0.817623E+010.25 = 0.26= -0.799979E - 06= -0.799980E+010.27 = -9.783427E - 96= -0.783427E+01= 0.28 =-0.767858E-06 =-0.767859F+01 0.29 = -0.753180E - 06= -0.753181E+01 $= \emptyset \cdot 3\emptyset$ = -0.739312E - 06= -0.739312E+01=-0.726182E+01 = 0.31=-0.726182E-06 =-0.7137275+01= 0.32= -0.713727E - 06= -0.791891E + 010.33=-0.701890E-06 =-0.690625E+01 = 0.34=-0.690624E-06 =-0.6798841+01 =-0.679883E-06 0.35 =-0.669628E+01 =-0.669628E-06 = 0.36=-0.659824E+01=-0.659823E-06 0.37 =-0.6504381+01 = 0.38 =-0.650437E-06 =-0.6414418+01= -0.641441E-06= 0.39



	Vs	$d\Delta\sigma/dV_s$	dΔσ,	/dV _s
	(volt)	$(mho/\Box-V)$	$(x 10^{-7})$	mho/o-V
	0.40	=-0.632807E-06	=-0.632	807E+01
=	0 • 41	=-0.624513E-06	=-0.624	513E+01
=	0.42	=-0.616537E-06	=-0.616	537E+Ø1
=	0.43	=-0.608859E-06	=-0.608	859E+01
=	0.44	= -0.601460E - 06	=-0.601	461E+01
=	9.45	=-0.594325E-06	=-0.594	326E+01
=	0.46	=-0.587438E-06		439E+01
=	0.47	=-0.580785E-06		1786E+01
=	Ø.48	= -0.574353E - 06		354E+01
=	Ø • 49	=-0.568131E-06		131E+01
=	0.50	=-0.562196E-96		106E+01
=	0.51	=-0.556269E-06		269E+#1
=	Ø • 52	=-0.550609E-06		1610E+01
=	0.53	=-0.54512ØE-Ø6		120E+01
=	Ø.54	=-0.539791E-06		791E+Ø1
=	0.55	=-0.534616E-06		1616E+Ø1
=	0.56	=-0.529586E-06		586E+Ø1
=	Ø • 57 Ø • 58	=-Ø.524696E-Ø6		1696E+Ø1
=	0.59	=-0.519939E-06 =-0.515309E-06		939E+01 309E+01
=	0.60	= -0.510309 R - 000		1801E+01
=	Ø • 61	=-0.506408E-06		408E+01
=	0.62	=-0.508408E-06		128E+01
=	Ø • 63	=-0.497953E-06		954五+91
=	0.64	=-0.493882E-06		882E+01
=	0.65	=-0.489908E-06		909E+01
=	0.66	=-0.486029E-06		030E+01
=	0.67	=-0.482241E-06		241E+01
=	0.68	=-0.478540E-06		540E+01
=	0.69	=-0.474922E-06	=-0.2174	923E+01
=	0.70	=-0.471386E-06	=-0.471	387E+01
=	0.71	=-0.467928E-06	=-0.467	928E+01
=	0.72	=-0.464544E-06	=-0.464	545E+01
=	0.73	=-0.461233E-06	=-0.461	234E+01
=	0.74	=-0.457992E-06	=-0.457	992E+01
=	M.75	=-0.454818E-06	=-0.454	8185+01
=	0.76	=-0.451709E-06	=-0.451	709E+01
=	0.77	=-0.448663E-06	=-0.448	663E+Ø1
=	9.78	=-0.445678E-06	=-0.445	678E+Ø1
=	0.79	=-0.442752E-06	=-0.442	752E+01
=	0.80	=-0.439882E-06	=-10.439	882E+01
=	0.81	=-0.437068E-06		068E+01
=	0.82	=-0.434307E-06		307E+01
=	0.83	= -0.431597E - 0.6		598E+Ø1
=	0.84	=-0.428938E-06		938E+Ø1
=	0.85	=-0.426327E-06		328E+01
=	0.86	= -0.423764E - 06		764E+01
=	0.87	=-0.421246E-06		246E+01
=	a • 88	=-0.418772E-06	=-0.418	7 7 尺字, 千仞子



Vs	dΔσ/dV _s	dΔσ/dV _s
(volt)	(mho/O-V)	$(x 10^{-7} \text{ mho/}\square-V)$
= 0.89	=-0.416342E-06	=-0.416342E+01
= (4.90)	=-0.413953E-06	=-0.413953E+01
= 0.91	=-0.411605E-06	=-0.411605E+01
= 0.92	=-0.409296E-06	=-0.409296E+01
= 0.93	=-0.407026E-06	=-0.407026E+01
= 0.94	=-Ø•404793E-Ø6	=-0.404793E+01
= 0.95	=-0.402596E-06	=-0.402596E+01
= 0.96	= -0.400434E - 06	= -0.400434E+01
= 0.97	=-0.398306E-06	=-0.398306E+01
= 0.98	=-0.396211E-06	=-0.396211E+01
= (4.99	=-0.394148E-06	=-0.394148E+01
= 1 • 00	=-0.392116E-06	=-0.392116E+01
= 1 • Ø 1	=-0.390113E-06	= -0.390113E+01
= 1 • 02	=-0.388137E-06	=-Ø•388138E+Ø1
= 1 • Ø 3	=-0.386188E-06	=-0.386188E+01
= 1 • Ø4	=-Ø.384262E-Ø6	=-0.384262E+01
= 1.05	=-0.382356E-06	=-0.382356E+01
= 1.06	=-0.380465E-06	=-0.380465E+01
= 1 • 07	=-0.378585E-06	= -0.378585E+01
= 1 · Ø8 = 1 · Ø9	=-0.376706E-06	=-0.376706E+01 =-0.374817E+01
$= 1 \cdot 09$ $= 1 \cdot 10$	=-0.374817E-06 =-0.372900E-06	=-0.372900E+01
$= 1 \cdot 10$ $= 1 \cdot 11$	=-0.370930E-06	= -0.379930E+01
= 1.12	= -0.368871E - 06	=-Ø•368871E+Ø1
= 1.13	= -0.366671E - 06	=-0.366672E+01
= 1 • 1 4	=-Ø.364254E-Ø6	=-0.364254E+01
= 1.15	=-0.361506E-06	=-0.361507E+01
= 1 • 16	=-0.358266E-06	=-0.358266E+01
= 1 • 17	=-0.354295E-06	=-0.354295E+01
= 1 • 18	=-0.349244E-06	=-0.349244E+01
= 1 • 19	=-0.342604E-06	=-0.342604E+01
= 1.20	=-0.333633E-06	=-0.333633E+01
= 1.21	=-0.321243E-06	=-0.321243E+01
= 1.22	=-0.303851E-06	=-0.303851E+01
= 1.23	=-0.279144E-06	=-0.279145E+01
= 1.24	=-0.243759E-06	=-0.243759E+01
= 1.25	=-0.192804E-06	=-0·192804E+01
= 1.26	=-M.119201E-06	=-0.119201E+01
= 1.27	=-0.127377E-07	=-0 • 127377E+00
= 1.28	= 0.141208E-06	= 0.141208E+01
= 1.29	= 0.363391E-06	= 0.363391E+01
= 1.30	= 0.682837E-06	= 0.682837E+01
= 1 • 31	= Ø.113942E-Ø5	= 0.113942E+02
= 1.32	= M • 178641E - 05	= 0.178641E+02
= 1.33	= 0.269249E-05	= 0.269249E+02
= 1.34	= M·394187E-M5	= 0.394187E + 02
= 1.35	= 0.563181E-05 $= 0.786698E-05$	= 0.563181E+02 = 0.786698E+02
= 1.36	0 1000010 01	= 0.107524E+03
= 1 • 37	= 0.107524E-04	- // · I // / / / / / / / / / / / / / / /



Vs	dΔσ/dV _s		dΔσ/dV _s
(volt)	(mho/o-V)	(x	10^{-7} mho/ \Box -V)
= 1.38	= Ø • 143899E - Ø4	=	Ø.143899E+Ø3
= 1.39	= Ø•188811E-Ø4	=	0.188811E+03
= 1 • 40	= 0.243395E-04	=	0.243395E+03
= 1 • 41	= 0.309074E-04	=	0.309074E+03
= 1.42	= 0.387710E-04	=	0.387710E+03
= 1 • 43	= 0.481756E-04	=	0.481756E+03
= 1 • 44	= 0.594354E-04	=	0.594354E+03
= 1.45	= 0.729443E-04	=	0.729443E+03
= 1 • 46	= 0.891869E-04	=	0.891869E+03
= 1 • 47	= 0.108756E-03	=	0 • 108756E+04
= 1 • 48	= 0.132371E-03	=	Ø • 132371E+Ø4
= 1.49	= 0.160904E-03	=	0 • 160904E+04
= 1.50	= 0.195410E-03	=	0.195411E+04
= 1 • 51	= 0.237169E-03	=	0.237169E+04
= 1.52	= 0.287727E-03	=	M.287727E+M4
= 1.53	= 0.348962E-03	=	0.348962E+04
= 1 • 54	= 0.423141E-03	=	Ø • 423141E+Ø4
= 1.55	= 0.513019E-03	=	0.513019E+04
= 1.56	= ؕ621925E-03	=	0.621925E+04
= 1.57 =	= 0.753900E-03	=	0.753900E+04
= 1.58	= Ø•913845E-Ø3	=	0.913846E+04
= 1.59	= Ø•110768E-Ø2	=	Ø • 110768E+Ø5
= 1.60	= Ø•134261E-Ø2	=	Ø • 134261E+Ø5
	= Ø•162734E-Ø2	=	0 • 162734E+05
	= Ø•197244E-Ø2	=	0.197244E+05
* - 0.0	= 0.239069E-02	=	0.239069E+05
	= 0.289763E-02	=	0.289763E+05
2 00	= 0.351204E-02	=	0.351204E+05
	= 0.425674E-02	=	0.425675E+05
	= 0.515933E-02	=	0.515933E+05
	= Ø • 625328E - Ø2	=	0.625328E+05
	= 0.757919E-02	=	0.757919E+05
	= 0.918628E-02	=	0.918628E+05
	= 0.111341E-01	B-70	0.111341E+06
	= 0.134949E-01	=	0.134949E+06
	= Ø • 163562E - Ø 1	=	Ø • 163562E+Ø6
	= Ø · 198245E - Ø 1	=	0.198245E+06
	= 0.240279E-01	=	0.240279E+06
	= 0.291225E-01	=	0.291225F+96
	= Ø•352975E-Ø1	=	0.352975E+06
	= Ø • 427817E - Ø1	=	0.427817E+06
* ' ' '	= 0.518527E-01	=	0.518527E+06
	= 0.628472E-01	=	0.628472E+06
	= 0.761728E-01	=	0.761728E+06
	= 0.923249E-01	=	0.923248E+06
- 00	= 0.111901E+00	=	0.111901E+07
	= 0.135627E+00 = 0.164384E+00	=	Ø • 135627E+Ø7 Ø • 164384E+Ø7
2 1 1 0	~ 40000000	=	0.199239E+07
= 1 • 86	= M • 199239E+00	dic-o	の • 1 クラムのソルギの <i>[</i>



Vs	dΔσ/dV _s	$d\Delta\sigma/dV_{s}$
(volt)	(mho/□-V)	$(x 10^{-7} \text{ mho/}\square-V)$
= 1.87	= Ø.241486E+ØØ	= 0.241486E+07
= 1.88	= 0.292688E+00	= 0.292688E+07
= 1.89	= 0.354747E + 00	$= \emptyset \cdot 354747E + 07$
= 1.90	= 0.429965E+00	= 0.429965E+07
= 1.91	= 0.521137E+00	= 0.521137E+07
= 1.92	= Ø•631635E+ØØ	= 0.631635E+07
= 1.93	= 0.765561E+00	= Ø•765561E+Ø7
= 1.94	= ؕ927885E+00	= 0.927885E+07
= 1.95	= Ø•112463E+Ø1	= ؕ112463E+08
= 1.96	= Ø•1363Ø8E+Ø1	= ؕ136308E+08
= 1.97	= ؕ165210E+01	= Ø•16521ØE+Ø8
= 1.98	= 0.200240E+01	= 0.200240E+08
= 1.99	= 0.242700E+01	= 0.242700E+08
= 2.00	= 0.294160E+01	= 0.294160E+08

*



Table 8. Relation between $\frac{d\Delta\sigma}{dV_s}$ and V_s .



```
C-FUCAL, 1969
01.01 FOR V=-1.00,0.01,-0.01; DO 02.00
01.02 QUIT
       SET A=38.46*V
02.01
02.02 SET R=FEXP(A)
       SET C=(1/R-1+5.9E-22*(R-1))/FSOT(1/B+A-1+5.9E-22*(P-A-1))
95.03
02.04 SET Y=2.4E-6*C
02.05 TYPE % 3.02,V,"
                                  11, %, -Y, 11
                                                      ", %,-Y*1E7,!
*G0
 Vs
                                             d\Delta\sigma/dV_s
                       d\Delta\sigma/dV_s
                                        (x 10^{-7} \text{ mho/}\Box - V)
(volt)
                      (mho/\Box - V)
=-1 \cdot \bigcirc \bigcirc
                = -0.539128E+03
                                          = -0.539128E + 10
=-0.99
               = -0.444814E + 03
                                         = -0.444814E + 10
=-0.98
                =-0.366998E+03
                                          =-0.366998E+10
= -0.97
               =-0.302796E+03
                                         =-0.302796E+10
=-0.96
                =-0.249824E+03
                                          =-0.849884E+10
=-9.95
               =-0.206120E+03
                                          =-0.206120E+10
```

=-0.94 = -0.170061E+03= -0.170061E + 10=-0.93 =-0.140311E+03 =-0.140311E+10=-0.92 =-0.115765E+03= -0.115765E + 10=-0.91=-0.955125E+02 =-0.955125E+09 =-0.90 =-0.788036E+02=-0.788036E+09 =-0.89 = -0.650177E + 02=-0.650177E+09=-0.88 =-0.536435E+02 =-0.536435E+09=-0.87 =-0.442590E+02 =-0.442590E+09=-0.365163E+09 =-9.86 =-0.365164E+02= -0.301281E + 02=-0.301281E+09 =-0.85 =-0.84 =-0.248575E+02 =-0.248575E+09=-0.205089E+02 =- G • 205089 E+ 99 =-0.83 =-0.82 =-0.169211E+02 =-0.169211E+09 =-0.1396098+09 =-0.81 =-0.139609E+02 = -0.115186E+09=-0.80 =-0.115186E+02 =-0.79 =-0.950350E+01=-0.950350E+08 =-0.7840968+08 = -0.78=-0.784096E+01 =-0.646925E+08 =-9.77 =-0.646925E+01 =-0.533751E+08 = -0.76= -0.533751E + 0.1= -0.440376E + 08=-0.75 = -0.440376E + 01=-0.3633378+08=-0.363337E+01 = -0.74=-0.299774E+01 =-0.8997748+08 =-0.73 =-0.247332E+01 =-0.247332E+08 =-0.72= -9.71=-0.204063瓦+01 =-0.2040638+08 =-0.70 =-0.168365E+01 =-0.168365E+08 = -0.69= -0.138911E+01 $= -0.1389119 \pm 08$ =-0.68 = -0.114610E+01=-0.1146191+08 =-0.67 =-0.945598日+00 =-0.9455988+67 = -0.7801741+07=-0.66 =-0.780174E+00 =-6.6436918+67 =-0.643691E+00 =-0.65 =-0.531083E+07 =-0.531083E+00 =-0.64 =-0.4381768+07 = -0.438176E + 00= -0.63=-0.3615215+00 =-0.361520H+07 =-0.62



Vs	dΔσ/dV _s	d∆o/dV _s
(volt)	$(mho/\Box - V)$	$(x 10^{-7} \text{ mho/}\square-V)$
= -0.61	=-J.298276E+ØA	=-M.298276E+M7
=-0.60	=-0.246095E+00	=-0.246095E+07
=-(1.59	=-0.203043E+00	=-0.203043E+07
=-0.58	=-0.167523E+00	=-0.167523E+07
=-0.57	=-0.138217E+00	=-0.138217E+07
=-0.56	=-0.114037E+00	=-0.114037E+07
=-0.55	= -0.940871E - 01	=-0.940871E+96
=-0.54	=-0.776274E-01	=-0.7762749+06
=-0.53	=-0.640473E-01	=-M.640473E+06
=-0.52	=-0.528428E-01	=-0.528428E+06
= -0 • 51	=-0.435984E-01	=-0·435984E+06
=-0.59	= -0.359713E - 01	=-M·359713E+M6
=-0.49	=-0.296785E-01	=-0.296785E+Ø6
=-4.48	=-0.244865E-01	=-0.844865E+06
=-0.47	=-0.202028E-01	=-0.2028E+06
=-0.46	=-0.166685E-01	=-0.166685E+06
= -0.45	=-0.137525E-01	=-0.137525E+06
=-0.44	=-0.113466E-01	=-0.113466E+Ø6
=-0.43	=-0.936167E-02	=-0.936168E+05
=-0.42	=-0.772393E-02	=-0.772393E+Ø5
= - () • 41	=-0.637271E-02	=-0.637271E+05
= -ল.ধল	=-0.525786E-02	=-0.585786E+05
=-0.39	=-0.433805E-02	=-0.4338056+05
=-0.38	=-0.357916E-02	=-0.357916E+05
=-0.37	=-0.295302E-02	=-0.2953028+05
=-0.36	=-0.243642E-02	=-0.243642E+05
=-0.35	=-0.201020E-02	=-0.2010205+05
=-0.34	=-Ø·165854E-Ø2	=-0.165854E+05
=-0.33	=-0.136840E-02	=-0.136849E+05
=-0.32	=-0.112902E-02	=-0.118902E+05
=-0.31	=-0.931519E-03	=-0.931519E+04 =-0.768571E+04
=-0.30 =-0.29	=-0.768571E-03 =-0.634130E-03	= -0.634130E+04
=-0.28	=-0.523211E-03	=-0.523211E+04
=-0.27	=-0.431698E-03	=-0.431698E+04
=-0.26	=-0.356198E-03	=-0.356198E+04
=-0.25	=-0.293909E-03	=-0.293909E+04
=-0.84	=-0.242520E-03	=-0.242520E+04
=-0.23	=-0.200126E-03	=-0.200126E+04
=-0.22	=-M · 165153E-03	=-0.165153E+04
=-0.21	=-0.136303E-03	=-0.136304E+04
=-17.20	=-0.112507E-03	=-0.112507E+04
=-0.19	=-0.988797E-04	=-0.928797E+03
=-0.18	=-0.766934E-04	=-0.766934E+03
=-0.17	=-M.633465E-04	=-0.633465E+03
=-0.16	=-0.523430E-04	=-0.5234306+03
=-0.15	= -0.438734E - 04	=-0.4327348+03
= - 61 • 1 41	=-0.358000E-04	=-0.3580018+03
=-0.13	=-0.296440E-04	=-0.296440E+03



V S	$d\Delta \sigma/dV_s$	$\frac{d\Delta\sigma/dV}{s}$ (x 10 mho/D-V)
(volt)	(mho/□-V)	$(X \perp U mno/U-V)$
=-0.12	=-0.245751E-04	=-0.245751E+03
=-0 • 1 1	=-0.204032E-04	=-ؕ204032E+03
=-0.10	=-0.169715E-04	=-0.169715E+03
=-0.09	=-0.141501E-04	=-0.141501E+03
=-0.08	=-0.118318E-04	=-0.118318E+03
=-0.07	=-0.992784E-05	=-0.992785E+02
=-0.06	=-0.836495E-05	=-0.836495E+02
= -0.05	=-0.708241E-05	=-0.798241E+02
=-0.04	=-0.603004E-05	=-0.603004E+02
=-0.03	=-0.516636E-05	=-0.516636E+02
=-0.08	=-0.445713E-05	=-0.445713E+02
= -0 • 0 1	= -0.387413E - 05	=-0.387413E+02
*		



3.4 The Approximated Calculation of the Relation Between the Surface Potential, $V_{\rm S}$, and the Applied Electric Potential, $V_{\rm A}$

Consider the system which consists of metal-dielectric material-semiconductor as illustrated in Figure 17. By applying equations (39) and (63), we have the following relations:

$$\varepsilon_{d}^{E}_{d} = \varepsilon_{s}^{E}_{s}$$

$$\varepsilon_{d} \frac{(V_{A} - V_{s})}{Z_{d}} = \varepsilon_{s}^{E}_{s} = \frac{Q_{s}}{\varepsilon_{s}}$$

Therefore,

$$\varepsilon_{o}\varepsilon_{d}\frac{(V_{A}-V_{S})}{Z_{d}}=Q_{S}=$$

$$= \pm (2kT\epsilon_{0}\epsilon_{s}p_{0})^{\frac{1}{2}}[(e^{-\beta V}s + \beta V_{s} - 1) + \frac{n_{0}}{p_{0}}(e^{\beta V}s - \beta V_{s} - 1)]^{\frac{1}{2}}$$

$$V_{A} = V_{S} \pm \frac{Z_{d}}{\varepsilon_{o} \varepsilon_{d}} (2kT \varepsilon_{o} \varepsilon_{s} p_{o})^{\frac{1}{2}} \left[(e^{-\beta V} s + \beta V_{s} - 1) + \frac{n_{o}}{p_{o}} (e^{\beta V} s - \beta V_{s} - 1) \right]^{\frac{1}{2}}.$$

From the above expression, the calculations of applied electric potential, $V_{\rm A}$, as the function of surface potential, $V_{\rm S}$, were done and the result is given in Figure 18, and the numerical results are also shown in the Tables 9, and 10.



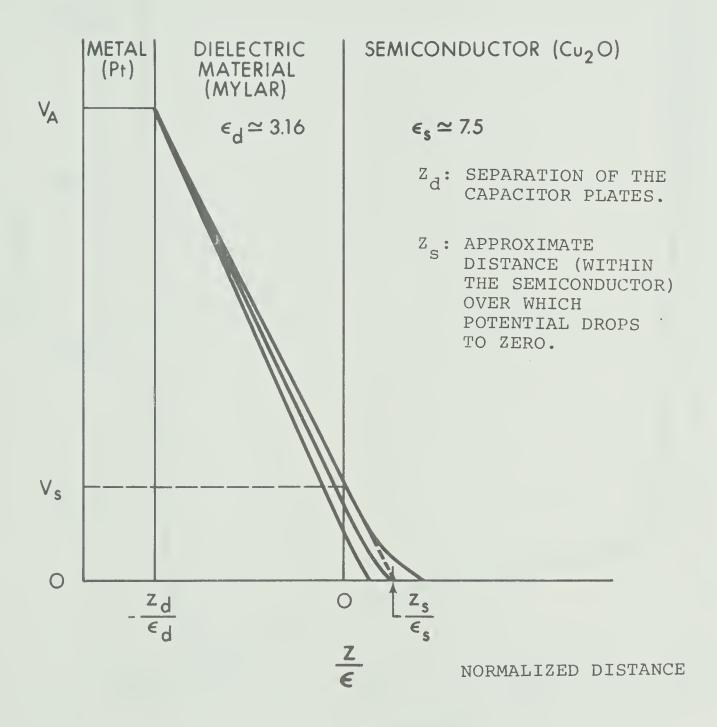


Figure 17. Schematic diagram of system of metal--dielectric material--semiconductor.



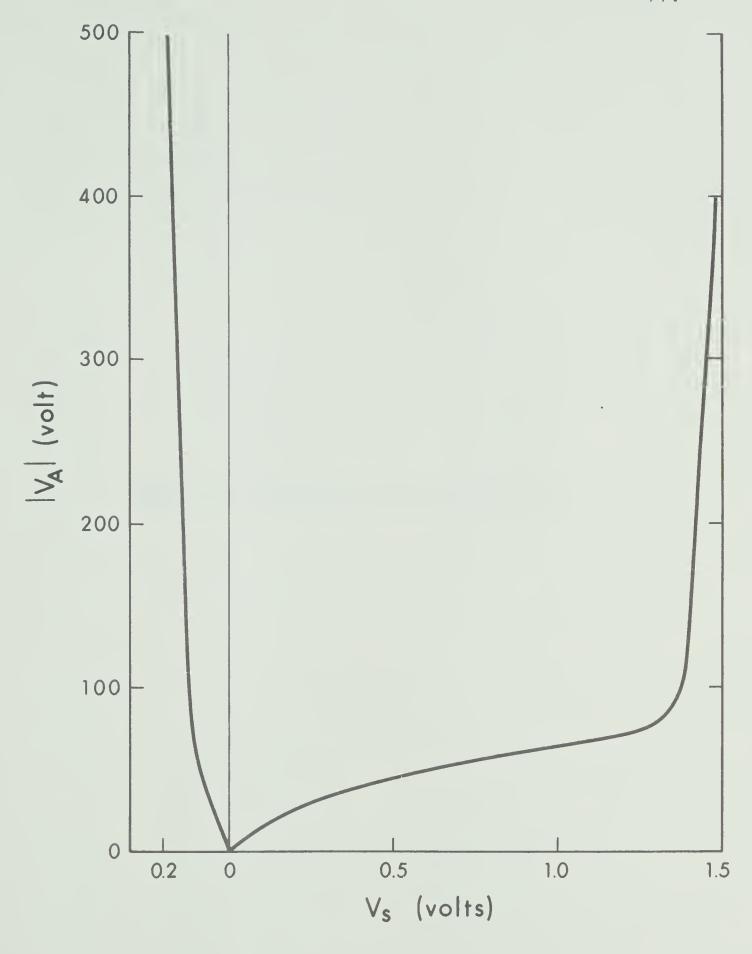


Figure 18. Theoretical curve of $|V_A|$ vs V_S .



Table 9. Relation between V_s and V_A .

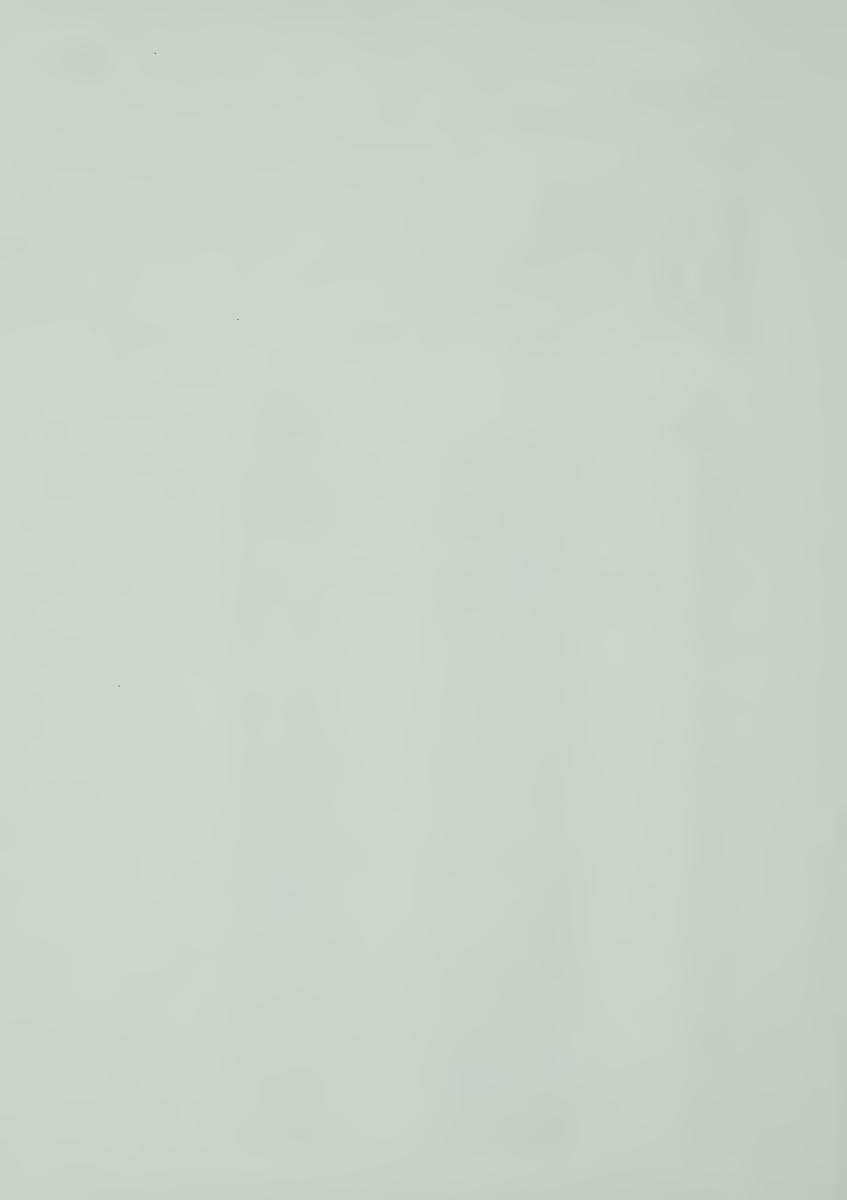


C-FUCAL, 1969

01.01 FOR V=0.00,0.01,2.00; DO M2.00
01.02 OUIT

02.01 SET A=8.32E-6
02.02 SET B=1.25E6
02.03 SET C=38.46*V
02.04 SET D=FEXP(-C)+C-1
02.05 SET G=FEXP(C)-C-1
02.06 SET O=A*FSOT(D+5.9E-22*G)
02.07 SET Y=V+B*O
02.08 TYPE % 3.02,V," ", %,O," ", % 7.06,Y,!

	Vs				$V_{\mathbf{A}}$
	(volt)				(volt)
=	0.00	=	0.000000E+00	=	a.aaaaaa
=	Ø • Ø 1	=	0.212645E-05	==	2.668060
=	0.02	=	0.401248E-05	=	5.035690
=	0.03	=	9.569926E-05	=	7.154080
=	0.04	=	0.722032E-05	=	9.465400
=	9.05	=	0.860292E-05	=	10.80370
=	0.06	=	0.986928E-05	=	12.39660
=	0.07	=	0.110375E-04	=	13.86690
=	9.98	=	9.181884E-94	=	15.23300
=	0.09		0.131361E-04	=	16.51919
=	Ø • 1 Ø	=	0.140885E-04	=	17.71060
=	0.11	=	0.149879E-04		18.84480
=	9.12	=	0.158410E-04	=	19.92130
=	Ø • 13	=	0.166536E-04	=	20.94700
=	0.14	=	0.174303E-04	=	21.99/90
=	Ø • 15	=	0.181752E-04	=	22.86900
=	Ø • 16	=	0.188916E-04	=	23.77450
	Ø • 17	=	0.195823E-04	=	24.64799
=	0.18	=	0.202499E-04	=	25.49240
=	Ø • 19	=	0.208964E-04	=	26.31959
==	0.20	=	9.215236E-04	=	27 - 19469
=	0.21	=	0.221332E-04		27.87650
=	Ø • SS	=	9.887866E-04	=	28.62820
=	0.23	=	0.233048E-04	=	29.36199
=	0.24	=	0.238691E-04	=	34.47644
=	0.25	=	0.244204E-04	=	30.77550
=	0.26	=	0.249595E-04	=	31 • 45940
=	0.27	=	0.254872E-04	=	32 • 12900
=	0.28	=	0.260042E-04	=	32.78530
=	0.89	=	0.265112E-04	=	33.42900
=	M • 3M	=	0.270986E-04	=	34.46080
=	0.31	=	何。274971月-04		34.68130
=	0.32	=	9.279779H-94	Service consider	35.29120
=	0.33	=	0.284488E-04	=	35.89100
=	0.34	=	M.289129H-M4	==	36 • 48114
=	4.35	=	0.293697H-04	=	37.46214



V _s (volt)	V_{A}
	(volt)
	7 • 63449
	3.19820
	3.75419
	3.30240
	9.84330
	7.37710
	7.97427
	1.42479
	1.939
	2.44720
	2.94950
	3 • 44630
	3.93750
	4.42350
	4.90440
	5.38040
	5 • 85160
	6.31810
	5.78919
	7 • 23770
	7 • 69 1 1 4
	3.14040
	3.58560
	9.42694
	9.46459
	9.89830
	0.32850
	3.75520 1.17840
	1.59830
	2.61496
	2.42830
	2.83860
	3 • 2459 M
	3.65020
	4.05150
, , , , ,	4.45000
	4.84580
	5.23870
	5.62910
	6.91680
7 7 7 1 1 7 1 1 1 1 1 1 1 1 1 1 1 1 1 1	6.40190
	6.78450
= 0.77 = 0.445055E-04 = 5	
= 0.77 = 0.445055E - 0.4 = 50 $= 0.78 = 0.448036E - 0.4 = 50$	7.15470
	7 • 16470 7 • 54240
	7 • 54240
= 0.77 = 0.445055E-04 = 50 = 0.78 = 0.448036E-04 = 50 = 0.79 = 0.450997E-04 = 50 = 0.80 = 0.453939E-04 = 50 = 0.81 = 0.456862E-04 = 50 = 0.82 = 0.459767E-04 = 50	7 • 54240 7 • 91780



	Vs				$^{V}_{A}$
	(volt)				(volt)
-	· ·		0 4.6720707 01		
=	0.85	=	0.468372F-04		59 • 39654
=	0.86	=	0.471205E-04	-	59.76070
=	9.87	=	9.474022E-04	=	60.12280
=	Ø - 88	=	Ø • 476822E - Ø4	==	60.48280
=	Ø • 89	=	0.479605E-04	=	60.84070
=	0.90	=	0.482373E-04	=	61 • 19660
=	Ø • 9 1	=	0.485125E-04	=	61.55060
=	0.92	=	0.487861E-04	=	61.90260
=	ؕ93	=	0.490582E-04	=	62.25270
=	0.94	=	0.493288E-04	=	62 • 60100
=	0.95	=	0.495979E-04	=	62.94740
=	0.96	=	0.498656E-04	=	63.29200
=	0.97	=	0.501318E-04	=	63.63480
=	0.98	=	0.503966E-04	=	63.97580
=	0.99	=	0.506601E-04	=	64.31510
=	1 • Ø Ø	=	0.509222E-04	=	64.65270
=	1 • Ø 1	=	0.511829E-04	=	64.98870
=	1 • 02	=	0.514424E-04	=	65.32300
=	1.03	=	0.517005E-04	=	65.65569
=	1.04	=	0.519574E-04	=	65.98670
=	1.05	=	0.522130E-04	=	66.31620
=	1.06	=	0.524674E-04	=	66.64420
=	1.07	=	0.527205E-04	=	66.97970
=	1.08	=	0.529726E-04	=	67.29570
=	1.09	=	0.532235E-04	=	67 • 61949
=	1 • 1 0	=	0.534733E-04	=	67.94169
=	1 • 1 1	=	0.537221E-04	=	68.26260
=		=	0.539699E-04	=	68 • 58240
=	1.13	=	Ø.542169E-04	=	68.90110
=	1 • 1 4	=	0.544631E-04	=	69 • 21890
=	1.15	=	0.547089E-04	_	69 • 53620
=	1.16	=	0.549545E-04	=	69 • 85320
=	1.17	=	0.552004E-04	=	70.17050
=	1.18	=	0.554470E-04	=	70.48880
=	1.19	=	Ø • 556954E • Ø4	=	70.80920
	1.20	=	Ø • 559467E - Ø4	=	71 • 13340
=	1.21		0.562030E-04	=	71 • 46380
=		=	0.564669E-04		
=	1.22	=		=	71 - 80370
=	1.23	=	0.567424E-04	=	72 • 15810
=	1.24	=	Ø • 570354E - 04	=	72.53430
=	1.25	=	Ø • 573544E - Ø4	=	72.94300
=	1.26	=	Ø • 577117E - Ø4	=	73 - 39960
=	1.27	=	0.581252E-04	=	73 • 92650
=	1.28	=	0.586210E-04	=	74.55630
=	1.29	=	0.592366E-04	=	75.33580
=	1.30	=	0.600255E-04	=	76 • 33190
=	1 • 3 1	=	0.610639E-04	=	77.63994
=	1 • 32	=	0.624581E-04	=	79 • 39270
=	1 • 33	=	0.643547E-04	=	81.77340



	Vs				V_{A}
(volt)				(volt)
	, VOIC)				(())
=	1.34	=	0.669504E-04	=	85.02800
=	1.35	=	0.705021E-04	=	89 • 47769
=	1.36	=	0.753342E-04	=	95.52780
=	1.37	=	0.818410E-04	=	103.6710
=	1 • 38	=	0.904870E-04	=	114.4890
=	1 • 39	=	0.101804E-03	=	128.6450
=	1 • 40	=	0.116398E-03	=	146.8980
=	1 • 41	=	0.134960E-03	=	170.1100
=	1.42	=	0.158289E-03	=	199.2820
=	1 • 43	==	0.187331E-03	=	235.5940
=	1 • 44	=	0.223217E-03	=	280.4620
=	1 • 45	=	0.267315E-03	=	335.5930
=	1 • 46	=	0.321279E-03	=	403.0590
=	1 • 47	=	0.387129E-03	=	485.3820
=	1 • 48	=	0.467316E-03	=	585.6269
=	1 • 49	=	0.564824E-03	=	707.5200
=	1.50	=	0.683267E-03	=	855.5840
=	1.51	=	0.827046E-03	=	1035.320
=	1.52	=	0 • 100150E - 02	=	1253 • 390
=	1.53	=	0.121309E-02	=	1517.990
=	1.54	=	0.146968E-02	=	1838 • 640
=	1.55	=	0.178078E-02	=	2227 • 530
	1.56	=	0.215793E-02	=	2698.970
=	1.57	=	0.261512E-02	=	3270.470
=	1.58	==	0.316932E-02	=	3963 • 240
=	1.59	=	0.384107E-02	=	4802.930
=	1.60	=	0.465530E-02	=	5820.720
=	1.61	=	0.564219E-02	=	7054-350
=	1.62	=	0.683841E-02	=	8549 • 640
=	1.63	=	0.828826E-02	=	10361.90
=	1 • 64	=	0.100455E-01	=	12558 • 60
=	1.65	=	0.121754E-01	=	15220.90
=	1.66	=	0.147570E-01	=	18447.90
=	1.67	=	0.178859E-01	=	22359 • 10
=	1.68	=	0.216783E-01	=	27099.50
=	1.69	=	0.262747E-01	=	32845 • 10
=	1.70	=	0.318459E-01	=	39809.10
=	1 • 7 1	=	0.385982E-01	=	48249.50
=	1.72	=	0.467823E-01	=	58479.60
=	1.73	=	0.567016E-01	=	70878 - 70
=	1.74	=	0.687248E-01	=	85907.80
=	1.75	=	0.832967E-01	=	104123.0
=	1.76	=	0 • 100958E+00	=	126200.0
=	1.77	=	0 • 122365E+00	=	152957.0
=	1.78	=	0 • 148310E+00	=	185389 • 9
=	1.79	=	0.179756E+00	=	224697 • 9
=	1.80	=	Ø • 21787ØE+ØØ	=	272339 • 9
=	1.81	=	0.264066E+00	=	330084.0
=	1.82	=	0.320059E+00	=	499076.0



```
V<sub>A</sub>
    Vs
  (volt)
                                           (volt)
= 1.83
              = 0.387922E + 00
                                      = 484994.0
= 1.84
              = 0.470174E + 00
                                       = 587719.0
= 1.85
              = 0.569866E + 00
                                      = 712334.0
              = 0.690696E + 00
= 1.86
                                       = 863371.0
                                       = 1946449
= 1.87
              = 0.837150E + 00
= 1.88
              = 0.101465E+01
                                       = 1268320
              = 0.122979E+01
= 1.89
                                       = 1537240
= 1.90
                                      = 1863180
              = 0.149055E+01
= 1.91
              = 0.180661E+01
                                       = 2258269
= 1.92
              = 0.218967E+01
                                       = 2737080
= 1.93
              = 0.265395E + 01
                                       = 3317430
= 1.94
              = 0.321667E+01
                                       = 4020830
= 1.95
              = 0.389870E + 01
                                       = 4873380
= 1.96
              = 0.472535E+01
                                       = 5906690
= 1.97
              = 0.572728E+01
                                       = 7159100
= 1.98
              = 0.694164E+01
                                      = 8677050
= 1.99
              = 0.841358E + 01
                                      = 0.1051700E+08
= 2.00
              = 0.101975E+02
                                      = 0.1274692E + 08
```

*



 $\underline{\text{Table 10}}.$ Relation between $\mathbf{V}_{\mathbf{S}}$ and $\mathbf{V}_{\mathbf{A}}.$



```
C-FOCAL, 1969
01.01 FOR V = -0.75, 0.01, -0.01; DO 02.00
01.02 OUIT
02.01 SET A=8.32E-6
02.02 SET B=1.25E6
02.03 SET C=38.46*V
02 \cdot 94 SET D=FEXP(-C)+C-1
02.05 SET G=FEXP(C)-C-1
02.06 \text{ SET } 0 = A*FSOT(D+5.9E-22*G)
02.07 SET Y=U-B*0
                                                    11, % 7.96, 7,!
42.08 TYPE 2 3.02, U,"
                                  11, %, 0, 11
*G0
                                                V_{A}
 (volt)
                                              (volt)
= -0.75
                                          =-0.1908291萬+08
                = \emptyset \cdot 152663E + 02
=-0.74
                = \emptyset \cdot 125956E + \emptyset 2
                                          = -0 \cdot 1574460E + 08
= -0.73
                = 0.103921E+02
                                          =-0.1299020E+08
=-0.72
                = 0.857416E+01
                                          =-0.1071770E+08
= -0.71
                = 0.707418E+01
                                          =-8842720
= -0.70
                = \emptyset.583661E+01
                                          =-7295770
=-0.69
                = 0.481555E + 01
                                          =-6019440
=-0.68
                = 0.397312E+01
                                          =-4955400
                                          =-4097570
=-0.67
                = 0.327806E+01
                = 0.270460E + 01
                                          =-3389750
=-0.66
```

= 0.223145E+01=-0.65 =-2789310 = 0.184108E+01=-0.64 =-2301350 = 0.151900E+01=-0.63 =-1898750 =-0.62 = 9.125326E+01 =-1566580 = 0.103402E+01=-1292520 = -0.61= 0.853127E+00 =-0.60 =-1066410 = -0.59= 0.703880E+00=-879850.0 =-725930 • 0 =-0.58 = 0.580743E+00= 0.479147E+00=-598935 • 0 =-0.57 =-0.56 = 0.395326E + 00=-494158 • 0 =-0.55 $= \emptyset.326167\Xi + \emptyset\emptyset$ =-407709.0 =-0.54 = 0.269107E+00=-336385 • 0 =-0.53 = 0.222029E+00 =-277537 · M = 0.183188E+00 =-228985.0 =-0.52 $= 0.151140E \pm 00$ =-188926•0 = -0.51=-0.50 = 0.124700E+00 =-155876.0 =-0.49 = 0.102885E+00 =-128607.0 =-106108.0 =-0.48 = 0.848861E-01=-87545.50 = 0.700360E-01= -0.47=-72230.50 = 0.577840E-01=-0.46 = 0.476752E-01=-59594.40 =-0.45 = 0.393349E-01=-49169 • 00 =-0.44 =-40567.50 =-0.43 = 0.324536E-01= 0.267761E-01=-33470.60 =-0.42 $=-27615 \cdot 39$ = 0.229919E-01= -0.41=-22784 • 30 =-0.40 = 0.182271E-01



Vs			$v_\mathtt{A}$
(volt)			(volt)
=-0.39	=	0.150384E-01	=-18798.50
=-0.38	=	0.124076E-01	=-15509 • 90
=-0.37	=	0 • 102370E - 01	=-12796 • 60
=-0.36	=	0.844612E-02	=-10558 • 00
=-0.35	=	0.696852E-02	=-8711•000
=-0.34	=	0.574942E-02	=-7187 • 120
=-0.33	=	0.474358E-02	=-5929 •810
=-0.32	ones Street	0.391370E-02	=-4892.450
=-0.31	=	0.388899E-08	=-4036.550
=-0.30	=	0.266406E-02	=-3330•380
=-0.29	=	0.219795E-02	=-2747 • 730
=-0.28	=	0.181338E-02	=-2267.000
=-0.27	=	0.149607E-02	=-1870-350
=-0.26	=	0 • 123425E - 02	=-1543 • 080
=-0.25	=	0 • 101823E - 02	=-1273 • 030
=-0.24	=	0.839972E-03	=-1050.210
=-0.23	=	0.692883E-03	=-866 • 3350
=-0.22	=	0.571503E-03	=-714.5980
=-0.21	Ξ	0.471330E-03	=-589 • 3730
=-0.20	=	0.388652E-03	=-486.0150
=-0.19	===	0.320403E-03	=-490.6940
=-0.18	=	0.264054E-03	=-330.2480
=-0 • 17	=	Ø • 217519E - 03	=-272.0690
=-0.16	=	Ø • 179076E - Ø3	=-224.0050
=-0.15	=	0.147303E-03	=-184.2780
= -0 • 14	=	0.121027E-03	=-151.4230
=-0.13	=	Ø.992792E-Ø4	=-124·2290 =-101·6970
= -0 · 12 = -0 · 11	=	0.812618E-04 0.663148E-04	=-83.00369
= -0.10 $= -0.10$	=	0.538944E-04	=-67.46800
=-0.09	=	0.435517E-04	= -54 • 529 70
=-0.08	=	0.349168E-04	=-43.72600
=-0.07	=	0.276848E-04	= -34 • 67600
=-0.06	=	0.216046E-04	= -27 • 06580
= -0.05	=	0.164698E-04	=-20.63730
= -0 .04	=	0.121107E-04	=-15.17849
=-0.03	=	0.838824E-05	=-10.51539
= -0.08	=	0.518829E-05	=-6.505360
= -0 • 0 1	=	0.241765E-05	=-3.032060
*			



CHALTER IV

THE APPARATUS AND EXPERIMENTAL PROCEDURE

4.1 The Apparatus and the Sample

Figure 19 gives a schematic diagram of the apparatus used for the experiment. The sample and sample holder were mounted inside the vacuum chamber. The specimen is a rectangular bar of single crystal cuprous oxide with the size of 1.2 x 2.5 x 8.0 mm, with the resistance along the longest side of about 2.0 x 10⁶ ohm, and with contacts of platinum to the ends (see Figure 20). The dielectric spacer between the sample and the platinum electrode is a mylar plate of 0.004 cm thickness. The sample resistance was measured by means of the d. c. wheatstone bridge (see Figure 19). The electric field applied to the sample is produced by batteries.



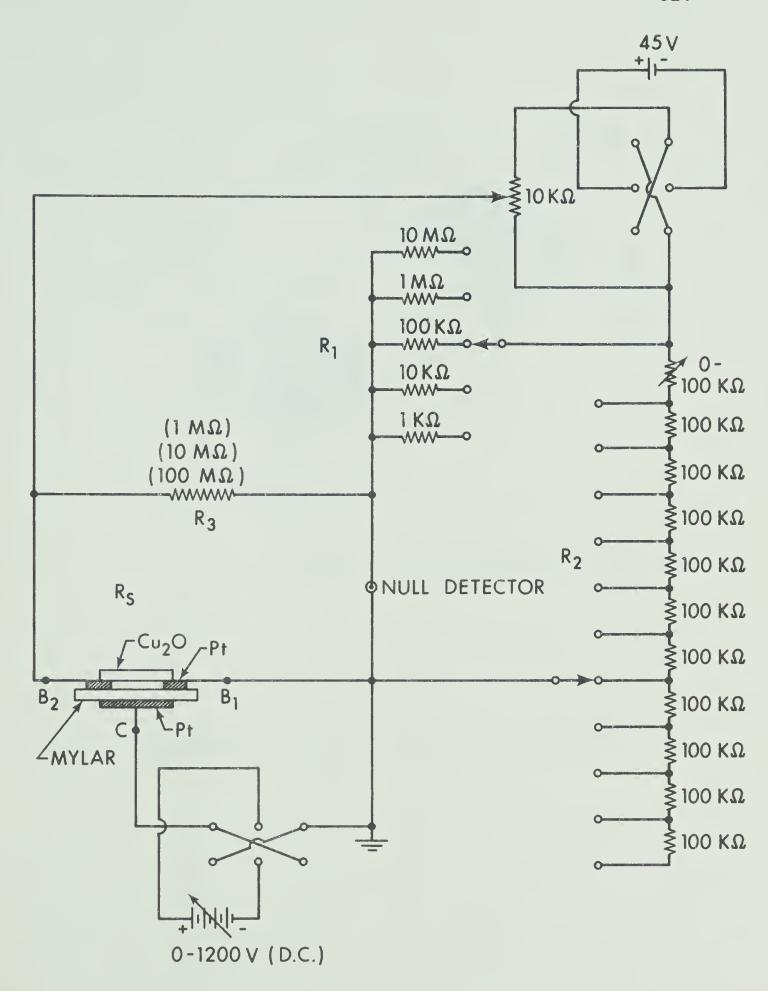
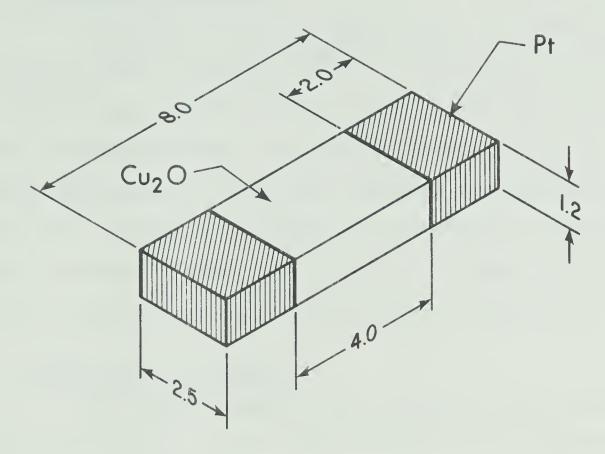


Figure 19. Schematic diagram of apparatus for measuring field effect.





NOTE : ALL DIMENSIONS IN millimeters

Figure 20. Shape and size of the sample.



4.2 The Sample Preparation

Crystals of cuprous oxide (Cu₂0) were grown by the grain growth technique^{25,26,29}. The samples used were cut from larger single crystals and provided with sputtered platinum contacts. The entire theory of Cu₂0 as a defect semiconductor³⁰ has been based on the experimental fact that, regardless of method of preparation, the material is always p-type. This in turn is blamed on an excess of oxygen beyond the stoichiometric proportions.

4.3 Experimental Procedure

The sample chamber was evacuated to the pressure of 2×10^{-6} mm Hg. In the measurements of the field-effect the standard method was used: a constant voltage (up to 1200 V) was applied to a capacitor, one electrode of which was the sample and the other the metal deposited on the mylar spacer. The measured capacitance of the whole system was 20 - 25 pF, at a frequency of 1 kc as measured by the impedance bridge (GR-type 1650 A).

For each new applied voltage the system is allowed to reach equilibrium. The change in the sample resistance was measured by means of an unbalanced d. c. bridge.

Readings were taken 2 min after applying the voltage.

During the experiment, the measuring voltage across the sample is kept small (about 5.0 V or less) compared to



that of which applied at the capacitor so as to maintain the entire surface at effectively the same potential.



CHAPTER V

EXPERIMENTAL RESULTS AND DISCUSSION

5.1 Experimental Results

In the experiment, we can apply more than 1000 V of positive potential to the platinum plate-electrode of the capacitor and up to 700 V of negative potential. The experimental data of the measuring resistances of the sample at various applied voltages are presented in Tables 11 and 12. From these tables, the surface conductance, $\Delta\sigma$, is plotted against the applied voltage, V_A , as shown in Figure 21. It is seen that in our experiment, the field effect existed in our chosen cuprous oxide sample. The minimum value of surface conductance, $(\Delta\sigma)_{\min}$, is -4.2 x 10⁻⁹ mho/o at a value of the applied potential of 560 V. The presence of a minimum in the experimental field effect curve allowed us to compare the experimental data with the calculated curves and to find the dependence of the surface band curvature on the applied voltage.

Figure 22 shows both theoretical and experimental curves of surface conductance, $\Delta\sigma$, versus charge densities $(Q_{_{\rm S}},\,Q_{_{\rm T}})$. The abscissa is now $Q_{_{\rm T}}$. The experimental curve has been adjusted vertically so that its minimum occurs at the minimum of the theoretical curve. This adjustment is significant since the minimum conductance,



 $(\Delta\sigma)_{\min}$, has a unique value independent of charge in surface states, Q_{ss}, which is assumed to be immobile. Having made this adjustment, the experimental surface conductance has an absolute significance, in terms of Q_{s} and V_{s} . The difference between the experimental and theoretical curves at a given value of $\Delta\sigma$ is just Q_{SS} . Thus by comparing the two curves one can obtain Q as a function of V . Figure 23 is a plot of this result. As indicated, the surface states are neutral when $V_s \simeq 1.38 \text{ V}$. The shape of the curve is related to, but does not uniquely determine, the energy distribution of the surface states. The distribution may be continuous, in which case the slope of the curve is the surface state density involving the minimum number of states; or the distribution may be discrete, perhaps as described by Bardeen and Brattain 31 in their model of the surface. This later possibility would predict a curve similar in shape to Figure 23.



Table 11. Experimental data.

$$(V_A = 0 \rightarrow +1000 V)$$

$V_{\mathbb{A}}$	R _s (x10 ⁶ Ω)	$\sigma \times (10^{-7} \text{ mho})$	$\Delta\sigma \times (10^{-9} \text{ mho/o})$
0	1.9610	5.0994	0
+50	1.9620	5.0968	-0.26
+100	1.9627	5.0950	-0.44
+150	1.9649	5.0893	-1.01
+200	1.9660	5.0849	-1.45
+250	1.9684	5.0803	-1.91
+300	1.9725	5.0697	-2.97
+350	1.9733	5.0676	-3.18
+400	1.9741	5.0656	-3.38
+450	1.9752	5.0627	-3.67
+500	1.9762	5.0602	-3.92
+520	1.9767	5.0589	-4.05
+540	1.9771	5.0578	-4.16
+560	1.9773	5.0573	-4.21
+580	1.9767	5.0589	-4.05
+600	1.9769	5.0584	-4.10
+620	1.9733	5.0676	-3.18
+640	1.9718	5.0715	-2.79
+660	1.9706	5.0746	-2.48
+680	1.9697	5.0769	-2.25
+700	1.9685	5.0800	-1.94
+720	1.9670	5.0839	-1.55
+740	1.9669	5.0842	-1.52
+760	1.9668	5.0844	-1.39
+780	1.9664	5.0855	-1.21
+800	1.9657	5.0873	-1.19
+820	1.9656	5.0875	-1.08
+840	1.9652	5.0886	-0.25
+860	1.9584	5.1062	0.68
+880	1.9588	5.1052	0.58
+900	1.9582	5.1068	0.74
+920	1.9575	5.1086	0.92
+940	1.9572	5.1094	1.00
+960	1.9573	5.1091	0.97
+980	1.9574	5.1089	0.95
+1000	1.9559	5.1128	1.34



Table 12. Experimental data.

$$(V_A = 0 \rightarrow -700V)$$

V _A	$R_s \times (10^6 \Omega)$	$\sigma \times (10^{-7} \text{ mho})$	$\Delta \sigma \times (10^{-9} \text{ mho/o})$
0 -50 -100 -150 -200 -250 -300 -350 -400 -450 -500 -520 -540 -560 -600 -620 -640 -660	1.9399 1.9394 1.9397 1.9388 1.9385 1.9365 1.9365 1.9364 1.9364 1.9363 1.9369 1.9369 1.9386 1.9399 1.9408 1.9406 1.9407 1.9402	5.1549 5.1562 5.1554 5.1578 5.1586 5.1586 5.1640 5.1658 5.1650 5.1643 5.1659 5.1645 5.1629 5.1584 5.1550 5.1526 5.1531 5.1529 5.1542	0 0.13 0.05 0.29 0.37 0.37 0.91 1.09 1.01 0.94 1.10 0.96 0.80 0.35 0.01 -0.23 -0.18 -0.20 -0.07
-680 -700	1.9387 1.9368	5.1582 5.1638	0.33



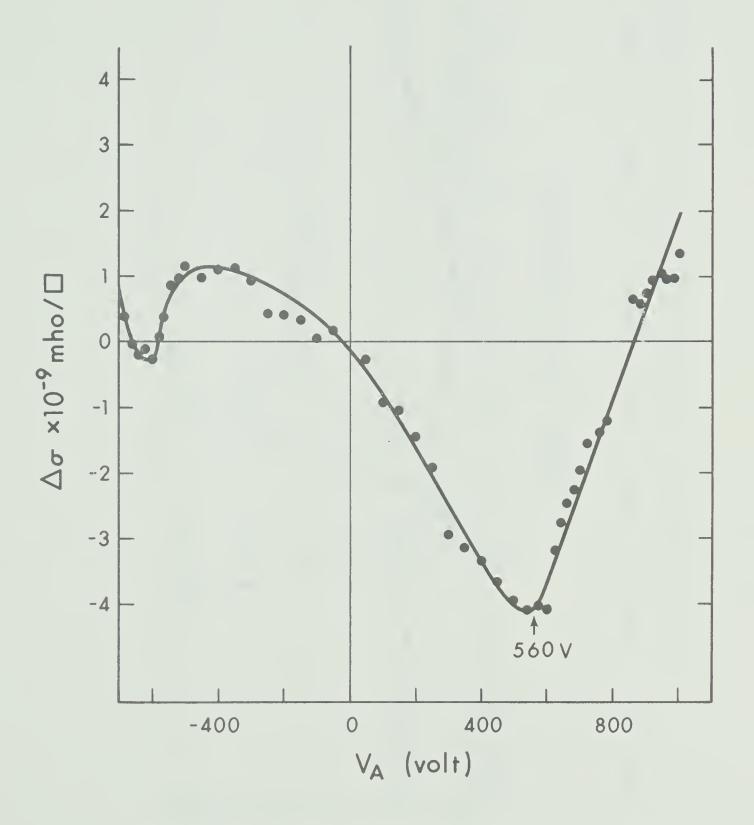
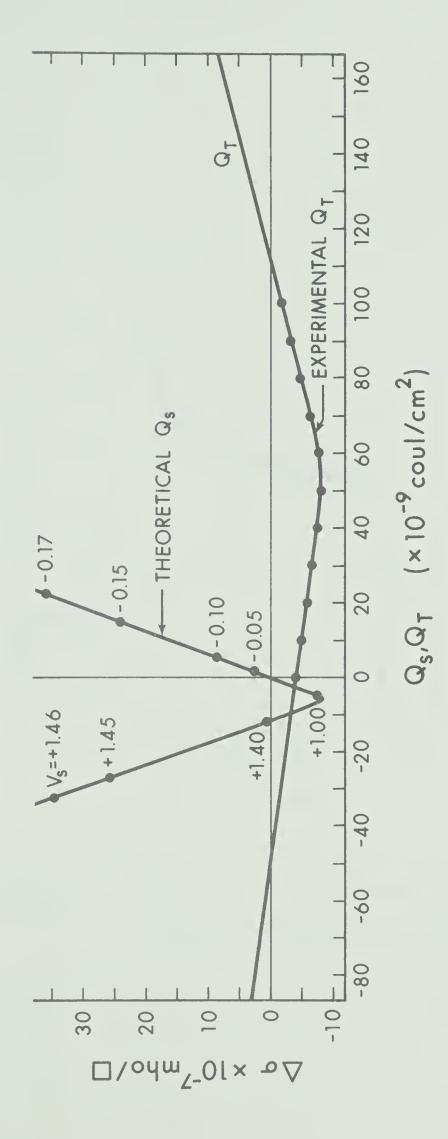


Figure 21. Experimental curve of $\Delta\sigma$ vs V_A .





Theoretical dependence of surface conductance on space charge and experimentally determined dependence on total charge. Figure 22.



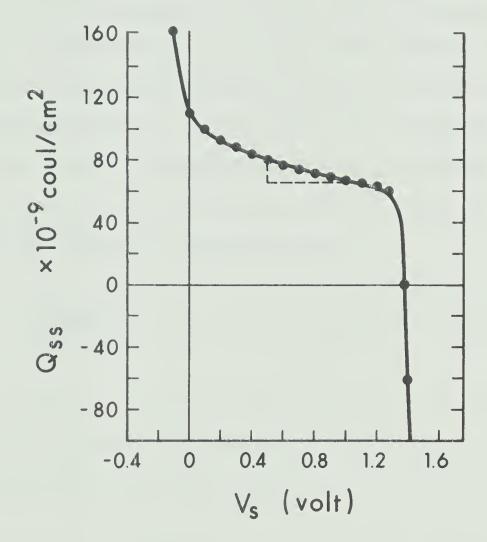


Figure 23. Charge in surface states as a function of surface potential.



5.2 Discussion

The Figure 23 shows the experimental dependence of the surface charge Q_{SS} on the surface band curvature V_S . The nature of the surface energy levels in cuprous oxide is clearly apparent: as the band curvature varies from $V_S = 0$ volt to $V_S = 1.27$ volt, the surface-level charge decreases. The dependence of Q_{SS} on V_S is rather smooth at room temperature. In this case, the energy distribution of the surface states seems to be continuous. The surface state density per unit potential (N_{SS}) is then obtained by graphical differentiation:

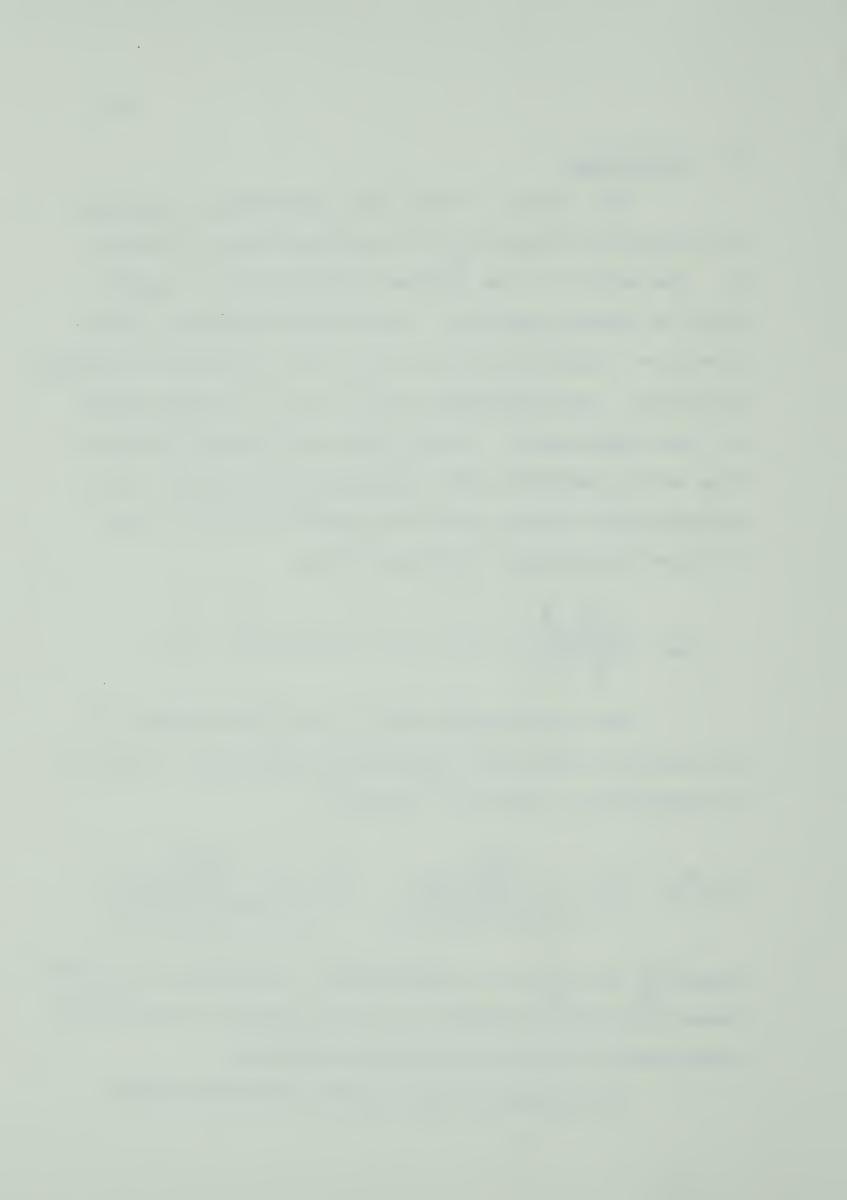
$$N_{ss} = \frac{1}{q} \left(\frac{\partial Q_{ss}}{\partial V_{s}} \right)_{v} \approx 1.75 \times 10^{11} \text{ states/cm}^2 - \text{volt.}$$

For the discrete model of the distribution of the surface states, the experimental curve $Q_{SS} = f(V_S)$ can be described by (see Sze¹⁴, Peka³²)

$$Q_{SS}(V_S) = \sum_{i=1}^{k} \frac{qN_{SD}^i}{g \exp\left(\frac{E_F - E_t}{kT}\right) + 1} - \sum_{i=1}^{k} \frac{qN_{SA}^i}{\left(1/g\right)\exp\left(\frac{E_t - E_F}{kT}\right) + 1}$$

where $N_{\rm sD}^{\rm i}$ and $N_{\rm sA}^{\rm i}$ are, respectively, the density of surface donor and acceptor states; $E_{\rm t}$ is the energy of the surface states and g is the ground state degeneracy.

In principle, with suitably selected surface



state parameters, we can calculate the total theoretical dependence of \mathbf{Q}_{SS} on \mathbf{V}_{S} from values of the parameters \mathbf{N}^{i} and \mathbf{E}_{t} by using the above equation. Then, inversely, the density and energy position of each state could be determined 32 from the parts of the curve separated by practically horizontal plateaus. The type of level (donor or acceptor) is found from the sign of the charge localized at the surface states (\mathbf{Q}_{SS} < 0 represents surface acceptor states, and \mathbf{Q}_{SS} > 0 represents surface donor states).

5.3 Conclusion

The main purposes of this project were first to build and test equipment for field effect measurements, secondly to review the basic theory of the subject matter and to study the characteristics of the field effect of single crystals of cuprous oxide prepared in our laboratory. We repeated, at room temperature, measurements done elsewhere 27,32 . We succeeded in finding the minimum in the experimental dependence of the surface conductance on the applied voltage which allowed us to study both the potential of the surface and the distribution of charge in surface states as shown in Figure 23, we then obtained the surface state density, $N_{\rm SS} \simeq 1.75 \times 10^{11} \, {\rm states/cm}^2 - {\rm volt}$, which is in the same order as the surface acceptor state density as given by Peka 32 (1 x 10^{11} , 3 x 10^{11} , 8 x 10^{11}



states/cm² - volt). But from the sign of the charge distribution localized at the surface states (Figure 23), we conclude the existence of the donor rather than the acceptor type states. Since the spectrum of slow surface state charges is a smooth function of the surface potential, the distribution of the surface energy levels in our cuprous oxide sample should be continuous rather than discrete ones as proposed by Peka^{27,32}. Most likely this is the individual property of our samples.

Other experiments were performed by connecting a recorder to the output of the null-detector. Voltage changes reflecting variations in surface conductance were recorded on a fast d. c. recorder (MFE Model M-20 CAHA). The field-effect time constant of the slow-states is seen on the recording paper. The field-effect time constant is arbitrarily defined as the time required for the initial observed conductance change to decay to 60 percent of its original value. The time constants of the samples at the slow states range from 5 min. to 15 min. The investigation of field effect time constants will allow us to study about the charge transfer mechanism from the bulk of the sample to the various types of states at the surface.

The data on the field-effect time constant were collected but the detailed analysis has not been done due to time limitations imposed by pressures to return to



Thailand.

5.4 Suggestions for Further Work

A most interesting extension of the present experiments would be the transient method (with pulse d. c. and a. c. fields). This method can be studied in the following:

- 1. D. C. or low-frequency fields: for studying the charge transfer mechanism between the slow states and the underlying space-charge region.
- 2. Higher frequency fields: which eliminate the effect of slow states which at the same time, permitting the fast states to maintain equilibrium with the spacecharge region.
- 3. Short pulses and very high frequency fields: where the interaction of the fast states with the space-charge region can be investigated or in some cases even eliminated.

Another experiment such as the measurements of luminescence together with the field effect will allow us to study the spectral distribution of energy.



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